

# Semiconducting Metal Oxide Thin-Film Transistors

Online at: <https://doi.org/10.1088/978-0-7503-2556-1>



# Semiconducting Metal Oxide Thin-Film Transistors

**Edited by  
Ye Zhou**

*Institute for Advanced Study, Shenzhen University, Nanshan, Shenzhen, Guangdong,  
People's Republic of China*

**IOP** Publishing, Bristol, UK

© IOP Publishing Ltd 2021

All rights reserved. No part of this publication may be reproduced, stored in a retrieval system or transmitted in any form or by any means, electronic, mechanical, photocopying, recording or otherwise, without the prior permission of the publisher, or as expressly permitted by law or under terms agreed with the appropriate rights organization. Multiple copying is permitted in accordance with the terms of licences issued by the Copyright Licensing Agency, the Copyright Clearance Centre and other reproduction rights organizations.

Permission to make use of IOP Publishing content other than as set out above may be sought at [permissions@iopublishing.org](mailto:permissions@iopublishing.org).

Ye Zhou has asserted his right to be identified as the author of this work in accordance with sections 77 and 78 of the Copyright, Designs and Patents Act 1988.

ISBN 978-0-7503-2556-1 (ebook)  
ISBN 978-0-7503-2554-7 (print)  
ISBN 978-0-7503-2557-8 (myPrint)  
ISBN 978-0-7503-2555-4 (mobi)

DOI 10.1088/978-0-7503-2556-1

Version: 20210101

IOP ebooks

British Library Cataloguing-in-Publication Data: A catalogue record for this book is available from the British Library.

Published by IOP Publishing, wholly owned by The Institute of Physics, London

IOP Publishing, Temple Circus, Temple Way, Bristol, BS1 6HG, UK

US Office: IOP Publishing, Inc., 190 North Independence Mall West, Suite 601, Philadelphia, PA 19106, USA

# Contents

<b>Preface</b>	<b>xi</b>
<b>Editor biography</b>	<b>xii</b>
<b>List of contributors</b>	<b>xiii</b>
<b>1 Introduction to semiconducting metal oxides</b>	<b>1-1</b>
<i>Shi-Rui Zhang and Ye Zhou</i>	
1.1 Background	1-1
1.2 Fundamentals of semiconducting metal oxide	1-2
1.3 Application of semiconducting metal oxide	1-5
References	1-6
<b>2 Fundamentals of metal-oxide thin-film transistors</b>	<b>2-1</b>
<i>Meng Zhang, Sunbin Deng, Yan Yan, Man Wong and Hoi-Sing Kwok</i>	
2.1 Overview of thin-film transistor technology	2-1
2.1.1 History and mainstream technologies	2-1
2.1.2 Operation mechanism	2-3
2.1.3 Device structure	2-4
2.1.4 Key static parameters	2-6
2.2 Metal oxide semiconductors for thin-film transistors	2-8
2.2.1 Binary metal oxide semiconductors	2-9
2.2.2 Multicomponent metal oxide semiconductors	2-11
2.3 Reliability of metal oxide thin-film transistors	2-13
2.3.1 Ambient stress	2-14
2.3.2 Gate bias stress	2-15
2.3.3 Illumination stress	2-16
2.3.4 Thermal stress	2-18
2.4 Approaches towards high performance	2-18
2.4.1 Active channels	2-19
2.4.2 Gate insulators	2-22
2.4.3 Gate electrodes	2-23
2.4.4 Source/drain regions	2-24
2.5 Summary	2-26
References	2-27

<b>3</b>	<b>Preparation of metal oxide thin film by pulsed laser deposition</b>	<b>3-1</b>
	<i>Te-Wei Chiu and Subramanian Sakthinathan</i>	
3.1	Introduction	3-1
	3.1.1 Preparation of metal oxides by pulsed laser deposition	3-1
	3.1.2 Apparatus	3-2
3.2	Orientation control	3-5
	3.2.1 Epitaxy	3-5
	3.2.2 Buffer layer	3-7
3.3	Ambient gas	3-13
	3.3.1 Effect of laser energy density under O <sub>2</sub> gas ambient	3-14
	3.3.2 Effect of N <sub>2</sub> O gas	3-15
3.4	Laser annealing	3-16
	3.4.1 ZnO thin films	3-18
	3.4.2 CuCrO <sub>2</sub> :Mg thin films	3-20
3.5	Aurora PLD	3-21
3.6	Conclusion	3-22
	References	3-22
<b>4</b>	<b>ZnO-based ultraviolet light-emitting materials and devices</b>	<b>4-1</b>
	<i>Weizhen Liu, Cen Zhang, Haiyang Xu and Yichun Liu</i>	
4.1	Introduction	4-1
4.2	Preparation and properties of ZnO materials	4-5
4.3	P–N and P–I–N heterojunction LEDs	4-8
	4.3.1 Surface/interfacial engineering and modification	4-9
	4.3.2 Incorporation of localized surface plasmons	4-16
	4.3.3 Cooperative effect of nanocrystallization and surface plasmons	4-19
	4.3.4 Emerging composite heterojunctions	4-27
4.4	MIS heterojunction LDs	4-30
4.5	Prospects and challenges	4-35
	References	4-37
<b>5</b>	<b>Heterojunction oxide thin-film transistors</b>	<b>5-1</b>
	<i>Hendrik Faber, Emre Yarali, Emre Yengel and Thomas D Anthopoulos</i>	
5.1	Introduction	5-1
5.2	Mechanisms and materials for HJ TFTs	5-3
	5.2.1 2DEG formation	5-3
	5.2.2 Dual active layers and other mechanisms	5-7

5.3	TFTs based on bilayer HJs and multilayer stacks	5-9
5.3.1	Overview	5-9
5.3.2	Distinct heterojunction layers versus mixed phase oxides	5-13
5.3.3	Influence of layer thicknesses	5-14
5.3.4	Influence of stacking sequence	5-16
5.3.5	Modulation doping	5-16
5.4	Improvements in bias stress stability for HJ TFTs	5-17
5.5	Conclusions	5-22
	Acknowledgements	5-22
	References	5-22
<b>6</b>	<b>Application of one-dimensional metal oxide semiconductor in field effect transistor</b>	<b>6-1</b>
	<i>Fengyun Wang and Hongliang Zu</i>	
6.1	Introduction	6-1
6.2	Preparation of one-dimensional metal oxide materials	6-2
6.2.1	Chemical vapor deposition	6-2
6.2.2	Sol-gel technique	6-3
6.2.3	Electrospinning technology	6-4
6.3	Basic principle of one-dimensional metal oxide semiconductor FET	6-5
6.4	Individual one-dimensional metal oxide NW transistors	6-7
6.4.1	Binary metal oxide NW transistor	6-7
6.4.2	Ternary metal oxide NW transistor	6-9
6.4.3	Quaternary metal oxide NW transistor	6-10
6.4.4	Other metal oxide NF transistors	6-12
6.5	Application of one-dimensional metal oxide semiconductor FET	6-13
6.5.1	Transparent and flexible electronic devices	6-13
6.5.2	Gas sensor devices	6-14
6.5.3	Photodetector	6-17
6.5.4	Synapse-like devices	6-19
6.6	Summary and outlook	6-20
	References	6-21
<b>7</b>	<b>Semiconductor metal-oxide thin-film transistors for display</b>	<b>7-1</b>
	<i>Zhihe Xia</i>	
7.1	Introduction	7-1
7.1.1	Current status of displays	7-1
7.1.2	Active-matrix driving for FPDs	7-3

7.1.3	TFT technologies in display	7-6
7.1.4	Development trend of MO TFTs in display	7-8
7.2	Issues of MO TFTs in display	7-10
7.2.1	TFT structures	7-10
7.2.2	MO materials	7-14
7.3	Circuit design for MO TFTs in display	7-16
7.3.1	Pixel circuits	7-16
7.3.2	Driver circuits	7-19
7.4	Summary and perspective	7-20
	References	7-21
<b>8</b>	<b>Metal oxide transistor for tactile imaging</b>	<b>8-1</b>
	<i>Shuhai Liu and Yong Qin</i>	
8.1	Introduction	8-1
8.2	Transistor-based tactile sensor with compressible gate electrode	8-3
8.3	Piezotronic/piezo-phototronic tactile sensor	8-5
8.3.1	Piezotronic effect	8-6
8.3.2	Piezotronic transistor as pressure sensor	8-7
8.3.3	Piezotronic transistor for tactile imaging	8-9
8.4	Tribotronic tactile sensor	8-13
8.4.1	Contact electrification	8-13
8.4.2	Tribotronic transistor and work mechanism	8-15
8.4.3	Tribotronic transistor for tactile imaging	8-16
8.5	New trends in tactile imaging: self-powered system	8-19
8.6	Summary	8-21
	References	8-21
<b>9</b>	<b>Phototransistors based on metal oxide semiconductors</b>	<b>9-1</b>
	<i>Lin-Bao Luo and Can Fu</i>	
9.1	Introduction	9-1
9.2	Performance parameters	9-6
9.3	Binary metal oxide semiconductors	9-6
9.3.1	ZnO	9-6
9.3.2	Other binary metal oxide semiconductors	9-11
9.4	Ternary metal oxide semiconductors	9-14
9.4.1	Fabrication of ternary metal oxide semiconductors hybrid heterojunction	9-14
9.4.2	Phototransistors	9-15



9.5	Quaternary oxide semiconductors	9-17
9.5.1	Fabrication of quaternary oxide hybrid heterojunction	9-17
9.5.2	Phototransistors	9-18
9.6	Conclusion and challenges	9-23
	References	9-26
<b>10</b>	<b>Semiconductor metal oxide thin film transistor for non-volatile memory</b>	<b>10-1</b>
	<i>Zhi Ye and Ning Zhang</i>	
10.1	Overview	10-1
10.1.1	Introduction	10-1
10.1.2	Classification of floating gate memory	10-3
10.1.3	The main technical indicators of floating gate memory	10-4
10.2	Silicon-based TFT floating gate memory	10-5
10.2.1	SONOS structure	10-5
10.2.2	SOHOS structure	10-8
10.3	Metal oxide TFT based charge-trap memory	10-9
10.3.1	Mechanism of the electrical hysteresis	10-9
10.3.2	Metal oxide TFT based floating gate memory	10-13
10.3.3	Nanocrystal (quantum dot) charge-trap memory	10-21
10.4	Other novel memories	10-27
10.4.1	FeRAM	10-27
10.4.2	RRAM	10-30
10.5	Conclusion and future development	10-33
	References	10-34
<b>11</b>	<b>Semiconductor metal oxide thin-film transistor for artificial synapse</b>	<b>11-1</b>
	<i>Jie Jiang, Yanran Li and Xiaoliang Liu</i>	
11.1	Introduction	11-1
11.2	Machanism and parameters of MOTFT	11-2
11.2.1	Structure of MOTFT	11-2
11.2.2	The principle of MOTFT	11-3
11.2.3	Main device parameters of MOTFT	11-4
11.3	Synapse profile	11-6
11.3.1	Synaptic structure	11-7
11.3.2	Basical characteristics of synapses	11-7

11.4	Neural bionic applications of MOTFT	11-8
11.4.1	EDL MOTFT	11-8
11.4.2	Ferroelectric MOTFT	11-14
11.4.3	Photoelectric MOTFT	11-16
11.5	Summary and outlook	11-22
	References	11-22
<b>12</b>	<b>Semiconducting metal oxide thin film transistors</b>	<b>12-1</b>
	<i>Wenfeng Zhang and Xiaokun Wen</i>	
12.1	Introduction	12-1
12.2	Semiconducting InGaZnO (IGZO) thin film transistors	12-2
12.2.1	Fundamentals	12-2
12.2.2	Device optimization	12-7
12.2.3	Display applications	12-12
12.3	Semiconducting Ga <sub>2</sub> O <sub>3</sub> thin film transistors	12-14
12.3.1	Fundamentals	12-14
12.3.2	Channel fabrication	12-16
12.3.3	Device performance and applications	12-19
12.4	Semiconducting ITO thin film transistors	12-22
12.5	Summary	12-25
	References	12-26

# Preface

Semiconducting metal oxide thin-film transistors are promising candidates for functional electronic devices. They have attracted considerable attention owing to their superior electrical performance, high transparency, excellent stability and uniformity. Semiconducting metal oxides usually exhibit higher carrier mobilities than those of amorphous Si and most organic transistors, and better device uniformity than that of polycrystalline Si transistors.

In this book, we will first introduce the concept and basic working mechanism of semiconducting metal oxide thin-film transistors. We then focus on a series of metal oxide thin films with desirable electrical and optical properties for various device applications. The typical devices such as logic circuits, LED drivers, photo-detectors, tactile imaging, transistor memories, artificial synaptic devices and transparent transistors will be discussed.

I would like to express my gratitude to all the fellow authors who have contributed in this book. I also want to acknowledge Robert Trevelyan and Caroline Mitchell at IOP Publishing, for all the help during the book editorial process, and for the excellent experience of working with them. I want to thank all the readers for their interest in our book. I hope that our book can be useful as a reference guide for researchers and students who work in the field of metal oxides and metal oxide-based transistors.

Ye Zhou

# Editor biography

## Ye Zhou

---



Professor Ye Zhou is an IAS Fellow and group leader in the Institute for Advanced Study, Shenzhen University. He received his B.S. (2008) in Electronic Science and Engineering from Nanjing University, M.S. (2009) in Electronic Engineering from Hong Kong University of Science and Technology and PhD (2013) in Physics and Materials Science from City University of Hong Kong. His research interests include flexible electronics, nano-composite materials and nano-scale devices for technological applications such as logic circuits, memories, photonics and sensors. He has 16 granted USA/China patents and published more than 120 papers in journals such as *Science*, *Chemical Reviews*, *Nature Electronics*, *Nature Communications*, *Advanced Materials*, etc. More than 40 of his works have been highlighted as cover pages or frontispieces. He is the Associate Editor of *IEEE Access*, *Applied Nanoscience* and *Science and Technology of Advanced Materials*, Editorial/Community Board Member of *Materials Horizons*, *Multifunctional Materials*, *Chemistry*, *PLOS ONE* and *Chemistry Proceedings*, and served as the Guest Editor of *Nanoscale Horizons*, *Frontiers in Chemistry*, *Frontiers in Physics* and *Polymer International*.

# List of contributors

**Thomas D Anthopoulos**

King Abdullah University of Science and Technology (KAUST), Thuwal 23955-6900, Kingdom of Saudi Arabia

**Te-Wei Chiu**

Department of Materials and Mineral Resources Engineering, National Taipei University of Technology, Taipei 106, Taiwan

**Sunbin Deng**

State Key Laboratory of Advanced Displays and Optoelectronics Technologies, The Hong Kong University of Science and Technology, Hong Kong, People's Republic of China

**Hendrik Faber**

King Abdullah University of Science and Technology (KAUST), Thuwal 23955-6900, Kingdom of Saudi Arabia

**Can Fu**

School of Electronic Science and Applied Physics and Anhui Provincial Key Laboratory of Advanced Materials and Devices, Hefei University of Technology, Hefei, Anhui 230009, People's Republic of China

**Jie Jiang**

School of Physics and Electronics, Central South University, Changsha, Hunan 410083, People's Republic of China

**Hoi-Sing Kwok**

State Key Laboratory of Advanced Displays and Optoelectronics Technologies, The Hong Kong University of Science and Technology, Hong Kong, People's Republic of China

**Yichun Liu**

Key Laboratory for UV Light-Emitting Materials and Technology, Ministry of Education, Northeast Normal University, People's Republic of China

**Shuhai Liu**

Lanzhou University, Lanzhou, Gansu 730000, People's Republic of China

**Weizhen Liu**

Key Laboratory for UV Light-Emitting Materials and Technology, Ministry of Education, Northeast Normal University, People's Republic of China

**Lin-Bao Luo**

School of Electronic Science and Applied Physics and Anhui Provincial Key Laboratory of Advanced Materials and Devices, Hefei University of Technology, Hefei, Anhui 230009, People's Republic of China

**Yanran Li**

School of Physics and Electronics, Central South University, Changsha, Hunan 410083, People's Republic of China

**Xiaoliang Liu**

School of Physics and Electronics, Central South University, Changsha, Hunan 410083, People's Republic of China

**Yong Qin**

Lanzhou University, Lanzhou, Gansu 730000, People's Republic of China

**Subramanian Sakthinathan**

Department of Materials and Mineral Resources Engineering, National Taipei University of Technology, Taipei 106, Taiwan

**Fengyun Wang**

College of Physics and Cultivation Base for State Key Laboratory, Qingdao University, Qingdao 266071, People's Republic of China

**Xiaokun Wen**

Huazhong University of Science and Technology, Wuhan, People's Republic of China

**Man Wong**

State Key Laboratory of Advanced Displays and Optoelectronics Technologies, The Hong Kong University of Science and Technology, Hong Kong, People's Republic of China

**Zhihe Xia**

State Key Laboratory of Advanced Displays and Optoelectronics Technologies, Hong Kong University of Science and Technology, Hong Kong, People's Republic of China

**Haiyang Xu**

Key Laboratory for UV Light-Emitting Materials and Technology, Ministry of Education, Northeast Normal University, People's Republic of China

**Yan Yan**

College of Electronics and Information Engineering, Shenzhen University, Nanshan, Shenzhen, Guangdong, People's Republic of China

**Emre Yarali**

King Abdullah University of Science and Technology (KAUST), Thuwal 23955-6900, Kingdom of Saudi Arabia

**Emre Yengel**

King Abdullah University of Science and Technology (KAUST), Thuwal 23955-6900, Kingdom of Saudi Arabia

**Zhi Ye**

College of Information Science and Electronic Engineering, Zhejiang University, Hangzhou 310027, People's Republic of China

**Shi-Rui Zhang**

Institute for Advanced Study, Shenzhen University, Nanshan, Shenzhen, Guangdong, People's Republic of China

**Meng Zhang**

Institute of Microscale Optoelectronics (IMO), Shenzhen University, Nanshan, Shenzhen, Guangdong, People's Republic of China

**Cen Zhang**

Key Laboratory for UV Light-Emitting Materials and Technology, Ministry of Education, Northeast Normal University, People's Republic of China

**Ye Zhou**

Institute for Advanced Study, Shenzhen University, Nanshan, Shenzhen, Guangdong, People's Republic of China

**Hongliang Zu**

College of Physics and Cultivation Base for State Key Laboratory, Qingdao University, Qingdao 266071, People's Republic of China

**Ning Zhang**

College of Information Science and Electronic Engineering, Zhejiang University, Hangzhou 310027, People's Republic of China

**Wenfeng Zhang**

Huazhong University of Science and Technology, Wuhan, People's Republic of China

# Chapter 1

## Introduction to semiconducting metal oxides

**Shi-Rui Zhang and Ye Zhou**

Semiconducting metal oxide (SMO) materials are promising candidates for various electronic devices. They have attracted considerable attention owing to their superior electrical performance, high transparency, excellent stability and uniformity. In this chapter, we mainly introduce some basic ideas of SMOs.

### 1.1 Background

Oxide, containing at least one oxygen and one other element, is one of the most abundant compounds on Earth, existing in gas, liquid and solid all over the place. A very common example of liquid oxides in room temperature is hydrogen oxide ( $\text{H}_2\text{O}$ ) which we call water, used as a universal solvent and necessary for life on our blue planet. Carbon dioxide ( $\text{CO}_2$ ) is a kind of gas oxide familiar to people, known as an ingredient of photosynthesis and one of the products of respiration. Apart from water and gas oxide, solid oxides also play an important role in our daily life. For instance, silicon oxide ( $\text{SiO}_2$ ), also called silica, has widespread applications in daily necessities, architectures and technologies. The most traditional type of colorless glass is quartz, in which silicon oxide is the single constituent in amorphous state. With excellent optical properties and chemical stability, quartz is not only utilized to manufacture optical fibers used in cable television and communication systems but also applied to the processing of diverse semiconductor devices [1]. Since the advent of the first MOSFET in the late 1950s, solid oxides have been proved to be indispensable in the modern semiconductor industry [2, 3]. The aforementioned silicon oxide acts as an insulating layer in the metal-oxide-semiconductor (MOS) structure, the core of MOSFET. MOSFET is a kind of device with three terminals: source, drain and gate. The MOS structure inside the device can be regarded as a planar capacitor where the semiconductor is basically p-type or n-type silicon and the metal layer could be conductive polycrystalline silicon besides metals. At the beginning, MOS structure can be fabricated by growing a layer of silicon oxide through thermal deposition on the silicon wafer and then depositing the metal layer.



When talking about the function of oxide layer in MOS structure and even in the whole device, we could simply say that it performs a dielectric property, preventing electrons or holes from tunneling from semiconductor to metal gate, contributing to the formation of channel near the interface between oxide and semiconductor.

Although oxides were usually thought to be insulators, some metal oxides such as simple binary oxide including ZnO, In<sub>2</sub>O<sub>3</sub>, SnO<sub>2</sub>, etc [4], and complicated oxide Zn–Sn–O, In–Sn–O [5, 6] actually have properties of semiconductors. Before going deep into talking about SMOs, a widely used device should be introduced. As the derivative of MOSFET, thin-film transistors (TFTs) have wide application in electronics. TFT works based on the same field effect mechanism as MOSFET. In general, TFT is fabricated by deposited semiconductor materials, dielectric materials and conducting materials in the form of thin film on a certain substrate [7–9]. The primary application of TFT is in display products such as liquid crystal display (LCD) and organic light-emitting diode (OLED) which are based on active matrix (AM) [10, 11]. TFT is widely used in the manufacture of active matrix liquid crystal display (AMLCD), occupying the largest segment of output of the panel display industry. In the meantime, active matrix organic light-emitting diode (AMOLED) is in rapid development. Generally speaking, TFT used in AMLCD and AMOLED can be made by using a very wide variety of semiconducting materials, but commonly used material is silicon including single crystalline silicon, microcrystalline silicon, low temperature polysilicon (LTPS) and amorphous silicon. Facing the advent of next generation display technologies, there are still some disadvantages existing in current silicon based TFT for display. To begin with, amorphous silicon based TFTs have relatively inadequate mobility, lower than  $1 \text{ cm}^2 \text{ V}^{-1} \cdot \text{s}^{-1}$ , limiting the operating speed of TFT devices as higher mobility could lead to high current which makes capacitive loads quickly charged or discharged [12, 13]. Besides, though LTPS based TFTs possess mobility about  $100 \text{ cm}^2 \text{ V}^{-1} \cdot \text{s}^{-1}$ , the existence of lots of grain boundaries leads to the difference of electrical characteristics between TFT units [14, 15]. What's more, silicon based TFTs are opaque to visible light and temperature of deposition is generally high, not applicable to the trend of transparent display and flexible panels. By using transparent electrodes such as indium tin oxide (ITO) and transparent semiconductors we can make TFTs totally transparent. In this condition, semiconducting metal oxide becomes an ideal candidate due to its sufficient mobility and characteristics of transparency under visible light, attracting great attention from researchers. In 2003, several groups adopted ZnO as n-channel to fabricate highly transparent TFTs [16–18]. It's worth noting that these ZnO-based TFTs could reach mobility larger than  $1 \text{ cm}^2 \text{ V}^{-1} \cdot \text{s}^{-1}$ , symbolizing the beginning of application of SMOs as the semiconducting channel layer in TFTs.

## 1.2 Fundamentals of semiconducting metal oxide

As mentioned above, oxide contains at least one oxygen and one other element, existing in solid, liquid and gas phase. Unlike molecular oxides, SMO generally has the form of solid and belongs to the family of non-stoichiometric compounds, which means proportions of elemental composition cannot be exactly represented by a

ratio of small natural numbers. As a kind of ionic solid, SMO has strong ionic bonds connecting positive metallic ions and negative oxygen ions. As for SMO, inside the materials, the 's' electronic shell is filled inherently while the 'd' shell is incompletely filled, owing to which, SMO possesses superior thermal/chemical stability and unique properties such as tunable energy bands, high dielectric constants and so on [19]. And these unique properties endow SMO capabilities in different applications. SMO is a very large group of materials, so they differ from each other in crystalline structure, inherent defects, energy band level and other physical aspects. For example, in terms of crystalline structure, ZnO could exist in hexagonal wurtzite or cubic zincblende. However, under ambient conditions, hexagonal wurtzite is more stable and common with the space group of  $P6_3mc$  [20]. The lattice constants of ZnO in wurtzite form are  $a = 3.25 \text{ \AA}$  and  $c = 5.2 \text{ \AA}$ , where the ratio of  $c/a$  is 1.633, closed to ideal value. In contrast,  $\text{In}_2\text{O}_3$  crystallizes in the form of cubic with lattice constant of  $10.08 \text{ \AA}$  while  $\text{SnO}_2$  belongs to rutile tetragonal and lattice constants are  $a = 4.737 \text{ \AA}$ ,  $c = 3.185 \text{ \AA}$  [4]. These various crystal structures lead to different unique properties of SMO.

For oxides, several kinds of defects exist widely inside materials, including point defects, line defects, plane defects and volume defects. In fact, defects exist in all crystalline solids which are not perfect though they exhibit periodic crystal structures [21, 22]. Point defects are also called zero-dimensional defects and can be mainly divided into three kinds, including vacancy defects, interstitial defects and Frenkel pairs when there is no heteroatom [23, 24]. Vacancy defects refer to vacant sites that should be occupied by certain atoms in a totally perfect crystal. And because of the stability of crystal structure around the vacancy, the neighboring atoms of the vacancies will not collapse easily, guaranteeing the existence of these vacancies. What's more, once a certain atom moves into the vacant site, the vacancy would move in the opposite direction and occupy the site where the atom used to be located. In contrast, when atoms appear in a region where there are commonly no atoms existing, interstitial defects show up with generally high energy configuration. The last kind of defect seems to be a combination of vacancy defects and interstitial defects, which means an atom occupies an interstitial site and leaves a vacancy, called Frenkel defects. As mentioned above, SMO belongs to ionic solids, owing to which, ionic bonds are more easily broken than covalent bonds so SMO usually has more intrinsic defects compared to elemental semiconductor materials [25]. For SMO, there are six classic point defects such a site of metallic atom (M) replaced with oxygen atom (O), a site of O replaced with M, no atom on a site of M, no atom on a site of O, M or O existing in an interstitial region [19]. On account of the existence of intrinsic defects like oxygen vacancies and metallic interstitial, undoped SMO generally exhibits n-type semiconducting properties. But for certain SMOs, the origin of n-type semiconducting is still controversial. For instance, there is another explanation for n-type conductivity of ZnO instead of inherent defects in the absence of intentional doping [26]. By using first-principle calculation and experiment, hydrogen is identified and characterized in ZnO bulk, being thought to be responsible plausibly as its presence is inevitable in most growth and annealing processes [27–30].

For solid-state physics, band theory is a significant concept, describing the range of energy levels that electrons could stay at (bands) and could not stay at (band gap). Pauli exclusion principle finally leads to the formation of valence band and conduction band [31, 32]. Many physical properties of solids including resistance, absorption and so on can be well explained by band theory. In short, band gap means a range of energy where no electronic states exist and band gap energy of a semiconductor is the minimum energy that the electrons required to transfer from valence band into conduction band. According to band theory, electrons cannot move freely inside the solid if the valence band is totally full and the conduction band is completely empty. Once electrons transfer from valence band to conduction band, they will be able to move freely, which means the formation of current. External heat or a photon with energy higher than band gap energy could excite electrons so that they can leave the valence band and transit into the conduction band, leaving orbital holes in the valence band. For most SMOs, the band gap is generally wide ( $>3$  eV). For example, the band gap of ZnO,  $\text{In}_2\text{O}_3$ ,  $\text{SnO}_2$  is about 3.4 eV, 3.5 eV, 3.6 eV [4]. Owing to the wide-band gap, SMO materials are able to endure large electric field and have high breakdown voltages, which means that SMO-based electronic devices could be operated under high temperature and power. What's more, the wide band gap also endows SMOs with high optical transparency in the visible region of the electromagnetic spectrum, which is a desired characteristic in transparent electronics.

In addition to band theory, impurity level is another vital parameter of semiconductors. Impurity level has significant impact on carrier concentration, microstructure and related aspects of a semiconductor. Generally, through doping, the intentional introduction of extra compositions into an intrinsic semiconductor alters the impurity level, resulting in the variation of electrical and optical properties. From the perspective of band theory, doping introduces extra energy levels within the band gap and the introduced energy levels will be closed to valence band or conduction band when species of dopant are different. Specifically, electron donor or n-type doping brings in energy levels near the conduction band while electron acceptor or p-type doping brings in ones near the valence band. As for ZnO, n-type doping can be achieved by replacing with Al, Ga, In and other group-III elements or by substituting group-VII elements for O while p-type doping is commonly thought to be difficult [4, 33, 34]. From point of view of carrier concentration, regardless of n-type or p-type doping, doped semiconductors would have higher carrier concentration compared to their intrinsic state because both electrons in n-type semiconductors and holes in p-type semiconductors contribute to conductivity significantly. Some highly doped semiconductors even possess conductivity comparable to metals. The reason impurity level of semiconductor is important is that it has a direct impact on the carrier mobility, which is another crucial parameter of semiconductors when they are applied to electronic devices. Carrier mobility is related to two kinds of scattering inside material: lattice scattering (phonon scattering) and ionized impurity scattering [35]. In terms of lattice scattering, when temperature is higher than absolute zero, atoms inside semiconductor will vibrate and create acoustic waves (phonons), which break the ideal periodic

potential. As a consequence, vibrating atoms interact with moving carriers by scattering them, causing the reduction of mobility. In other words, higher temperature results in smaller mobility and vice versa. Regarding ionized impurity scattering, electron donors or acceptors are commonly ionized when being doped into semiconductor. Coulombic interaction will be produced when moving electrons or holes approach these doped impurities, leading to scattering of carriers. Under constant temperature, increasing impurity level normally lowers the carrier mobility.

### 1.3 Application of semiconducting metal oxide

SMOs are widely used in many fields, especially in electronics. The electrode may be the simplest application of SMO. For example, indium tin oxide (ITO) is a highly doped n-type semiconductor with low resistivity and high carrier concentration. Besides, ITO also possesses typical wide band gap and high transmittance in the range of visible light. These unique electrical and optical properties make ITO an ideal candidate for a transparent conducting electrode [36]. For example, ITO can not only be drain, source and gate electrode in TFT, but can also be used as anode in OLED [6, 37, 38]. Furthermore, due to the transparent conductive property as well as ease of being deposited as thin film, ITO is used to make transparent conductive coating for display technologies and photovoltaics [39–41].

As mentioned above, TFT is one of the important applications of SMO. The introduction of SMO could break the limitation of traditional silicon based TFT. In 2003, Hoffman *et al* [17] investigated transparent thin-film transistor (TTFT) devices by using ZnO as n-channel. In this research, highly transparent n-type ITO served as drain, source and gate electrode at the same time with aluminum–titanium oxide (ATO) deposited as gate insulator. These TTFTs showed optical transmission of 75% in the visible light region of the electromagnetic spectrum and drain current ON/OFF of about  $10^7$ . Most importantly, this research also demonstrated that these ZnO based devices' channel mobilities could be more than  $1 \text{ cm}^2 \text{ V}^{-1} \cdot \text{s}^{-1}$  and reached up to  $2.5 \text{ cm}^2 \text{ V}^{-1} \cdot \text{s}^{-1}$ . Nomura *et al* [18] fabricated TFTs in single-crystalline highly doped oxide semiconductor,  $\text{InGaO}_3(\text{ZnO})_5$ . The devices exhibited field-effect mobility of about  $80 \text{ cm}^2 \text{ V}^{-1} \cdot \text{s}^{-1}$  due to less grain boundary and scattering in a single crystal as well as high doping density. In fact, in the modern display industry, amorphous In–Ga–Zn–O (a-IGZO)-based TFTs perform excellently due to high mobility and high uniformity, so a-IGZO is a kind of material being widely used in actual mass production [42–47].

The use of SMO-based TFT was naturally extended to the area of flash memory devices as they adopted TFT as fundamental structure. In 2017, Hota *et al* [48] constructed a transparent flash memory by combining amorphous oxide with high- $\kappa$  oxide materials by the sol–gel method. As a kind of n-type semiconductor, ZnO is applied to form the channel.  $\text{Ta}_2\text{O}_5$  functions as the charge trapping layer and tunneling dielectric. For low voltage operation,  $\text{Al}_2\text{O}_3$  plays the role of blocking dielectric layer. ITO is the electrode. With program and erase, the maximum memory window of  $\sim 10.7 \text{ V}$  is demonstrated. Flash memory performed well in durability and reliability tests, holding data for more than  $10^4 \text{ s}$  and having

approximately 100 program/erase cycles. With the development of non-volatile memory devices, resistive random access memory (ReRAM) is thought to be one of the potential candidates for next-generation devices. So many materials exhibit resistive switching phenomenon which is required in ReRAM. In fact, resistive switching phenomenon was first found on  $\text{Al}_2\text{O}_3$  by Hickmott in 1962 [49]. Hickmott studied five metal–oxide–metal sandwiches such as  $\text{Al–SiO}_2\text{–Au}$ ,  $\text{Al–Al}_2\text{O}_3\text{–Au}$ ,  $\text{Al–Ta}_2\text{O}_3\text{–Au}$ ,  $\text{Al–ZrO}_2\text{–Au}$  and  $\text{Al–TiO}_2\text{–Au}$  under direct-current-voltage, in which  $\text{Al}_2\text{O}_3$  was investigated extensively. The switching times of these oxides are below 1  $\mu\text{s}$ , indicating the excellent performance of oxide in resistive switching. Up to now, numerous kinds of SMO have been investigated. For example, the highest ON/OFF ratio ( $>10^9$ ) was realized in the research of  $\text{TaO}_x$  and  $\text{GeO}_x$  devices [50, 51].  $\text{HfO}_x$  and  $\text{TaO}_x$  based devices both reached nanosecond level in program speed [52–54]. ReRAMs based on other metal oxides such as  $\text{CuO}_x$  [55–57],  $\text{CoO}_x$  [58, 59],  $\text{NiO}_x$  [60], etc, have also been studied systematically. The underlying mechanism of resistive switching behavior of metal oxides is mainly put down to the formation and rupture of conductive filaments (CFs) or the changes of valence states caused by the migration of oxygen vacancy [61, 62]. For SMO-based ReRAM, owing to the production and the migration of oxygen vacancies inside metal oxide film, conductive filaments can evolve and resistive switching or memory function can be realized without active metal electrode and metal conductive filaments. Commonly speaking, ‘electroforming’ process is required when the first resistive switching happens in SMO-based ReRAM. In this process, some oxygen atoms inside oxides will lose electrons and oxygen vacancies will be produced under high applied voltage accompanied with generating  $\text{O}_2$ . And then the redistribution of these oxygen vacancies causes the changes of resistance states of the metal oxide film under different applied voltages, resulting in the memory function of ReRAM.

In conclusion, we have listed some major applications of SMO and discussed them in limited space, but we don’t enumerate all the applications as they are extremely wide. In this book, more detailed discussion in SMOs and their application in different fields will be presented.

## References

- [1] Fanderlik I 2013 *Silica Glass and Its Application* (Amsterdam: Elsevier)
- [2] Nicollian E H and Brews J R 1982 *MOS/Metal Oxide Semiconductor/Physics and Technology* (New York: Wiley) p 920
- [3] Lee M L, Fitzgerald E A, Bulsara M T, Currie M T and Lochtefeld A 2005 Strained Si, SiGe, and Ge channels for high-mobility metal-oxide-semiconductor field-effect transistors *J. Appl. Phys.* **97** 011101
- [4] Batzill M and Diebold U 2005 The surface and materials science of tin oxide *Prog. Surf. Sci.* **79** 47–154
- [5] Rajachidambaram J S, Sanghavi S, Nachimuthu P, Shutthanandan V, Varga T, Flynn B, Thevuthasan S and Herman G S 2012 Characterization of amorphous zinc tin oxide semiconductors *J. Mater. Res.* **27** 2309–17

- [6] Kim H, Gilmore C M, Piqué A, Horwitz J S, Mattoussi H, Murata H, Kafafi Z H and Chrisey D B 1999 Electrical, optical, and structural properties of indium–tin–oxide thin films for organic light-emitting devices *J. Appl. Phys.* **86** 6451–61
- [7] Brody T P 1984 The thin film transistor—a late flowering bloom *IEEE Trans. Electron Devices* **31** 1614–28
- [8] Weimer P 1962 The TFT a new thin-film transistor *Proc. IRE* **50** 1462–9
- [9] Brody T P and Kunig H E 1966 A high-gain InAs thin-film transistor *Appl. Phys. Lett.* **9** 259–60
- [10] Kuo Y 2013 Thin film transistor technology—past, present, and future *Interface Mag.* **22** 55–61
- [11] Fortunato E, Barquinha P and Martins R 2012 Oxide semiconductor thin-film transistors: a review of recent advances *Adv. Mater.* **24** 2945–86
- [12] Sirringhaus H 2014 25th anniversary article: organic field-effect transistors: the path beyond amorphous silicon *Adv. Mater.* **26** 1319–35
- [13] Wager J F 2003 Applied physics. Transparent electronics *Science* **300** 1245–6
- [14] Wager J F 2014 Flat-panel-display backplanes: LTPS or IGZO for AMLCDs or AMOLED displays? *Inf. Disp.* **30** 26–9
- [15] Nathan A, Chaji G R and Ashtiani S J 2005 Driving schemes for a-Si and LTPS AMOLED displays *J. Disp. Technol.* **1** 267–77
- [16] Carcia P F, McLean R S, Reilly M H and Nunes G 2003 Transparent ZnO thin-film transistor fabricated by rf magnetron sputtering *Appl. Phys. Lett.* **82** 1117–9
- [17] Hoffman R L, Norris B J and Wager J F 2003 ZnO-based transparent thin-film transistors *Appl. Phys. Lett.* **82** 733–5
- [18] Nomura K, Ohta H, Ueda K, Kamiya T, Hirano M and Hosono H 2003 Thin-film transistor fabricated in single-crystalline transparent oxide semiconductor *Science* **300** 1269–72
- [19] Deng Y 2019 Understanding semiconducting metal oxide gas sensors *Semiconducting Metal Oxides for Gas Sensing* ed Y Deng (Singapore: Springer) pp 1–22
- [20] Özgür Ü, Alivov Y I, Liu C, Teke A, Reshchikov M A, Doğan S, Avrutin V, Cho S J and Morkoç H 2005 A comprehensive review of ZnO materials and devices *J. Appl. Phys.* **98** 041301
- [21] Watkins G 1997 Native defects and their interactions with impurities in silicon *MRS Online Proc. Libr. Arch.* **469** 139
- [22] Smyth D M 2000 *Defect Chemistry of Metal Oxides* (Oxford: Oxford University Press) p 304
- [23] Crawford J H and Slifkin L M 2013 *Point Defects in Solids: General and Ionic Crystals* (Berlin: Springer)
- [24] Spaeth J-M, Niklas J R and Bartram R H 2012 *Structural Analysis of Point Defects in Solids: An Introduction to Multiple Magnetic Resonance Spectroscopy* (Berlin: Springer)
- [25] Fisher E R, Elkind J L, Clemmer D E, Georgiadis R, Loh S K, Aristov N, Sunderlin L S and Armentrout P B 1990 Reactions of fourth-period metal ions ( $\text{Ca}^+ - \text{Zn}^+$ ) with  $\text{O}_2$ : metal-oxide ion bond energies *J. Chem. Phys.* **93** 2676–91
- [26] Look D C, Hemsley J W and Szelove J R 1999 Residual native shallow donor in ZnO *Phys. Rev. Lett.* **82** 2552–5
- [27] Van De Walle C G 2000 Hydrogen as a cause of doping in zinc oxide *Phys. Rev. Lett.* **85** 1012–5
- [28] Janotti A and Van de Walle C G 2007 Hydrogen multicentre bonds *Nat. Mater.* **6** 44–7

- [29] Janotti A and Van de Walle C G 2009 Fundamentals of zinc oxide as a semiconductor *Rep. Prog. Phys.* **72** 126501
- [30] Cox S F *et al* 2001 Experimental confirmation of the predicted shallow donor hydrogen state in zinc oxide *Phys. Rev. Lett.* **86** 2601–4
- [31] Kittel C and McEuen P 1976 *Introduction to Solid State Physics* (New York: Wiley)
- [32] Holgate S A 2009 *Understanding Solid State Physics* (Boca Raton, FL: CRC Press)
- [33] Kato H, Sano M, Miyamoto K and Yao T 2002 Growth and characterization of Ga-doped ZnO layers on a-plane sapphire substrates grown by molecular beam epitaxy *J. Cryst. Growth* **237-239** 538–43
- [34] Norton D P, Heo Y W, Ivill M P, Ip K, Pearton S J, Chisholm M F and Steiner T 2004 ZnO: growth, doping and processing *Mater. Today* **7** 34–40
- [35] Neamen D A 2012 *Semiconductor Physics and Devices: Basic Principles* (New York: McGraw-Hill)
- [36] Farhan M S, Zalnezhad E, Bushroa A R and Sarhan A A D 2013 Electrical and optical properties of indium-tin oxide (ITO) films by ion-assisted deposition (IAD) at room temperature *Int. J. Precis. Eng. Manuf.* **14** 1465–9
- [37] Kim H, Piqué A, Horwitz J S, Mattoussi H, Murata H, Kafafi Z H and Chrisey D B 1999 Indium tin oxide thin films for organic light-emitting devices *Appl. Phys. Lett.* **74** 3444–6
- [38] Kawachi G, Kimura E, Wakui Y, Konishi N, Yamamoto H, Matsukawa Y and Sasano A 1994 A novel technology for a-Si TFT-LCD's with buried ITO electrode structure *IEEE Trans. Electron Devices* **41** 1120–4
- [39] Du J, Chen X-L, Liu C-C, Ni J, Hou G-F, Zhao Y and Zhang X-D 2014 Highly transparent and conductive indium tin oxide thin films for solar cells grown by reactive thermal evaporation at low temperature *Appl. Phys. A* **117** 815–22
- [40] Frach P, Glöß D, Goedicke K, Fahland M and Gnehr W M 2003 High rate deposition of insulating TiO<sub>2</sub> and conducting ITO films for optical and display applications *Thin Solid Films* **445** 251–8
- [41] Kim S I, Cho S H, Choi S R, Oh M C, Jang J H and Song P K 2009 Crystallization and electrical properties of ITO:Ce thin films for flat panel display applications *Thin Solid Films* **517** 4061–4
- [42] Nomura K, Ohta H, Takagi A, Kamiya T, Hirano M and Hosono H 2004 Room-temperature fabrication of transparent flexible thin-film transistors using amorphous oxide semiconductors *Nature* **432** 488–92
- [43] Yabuta H, Sano M, Abe K, Aiba T, Den T, Kumomi H, Nomura K, Kamiya T and Hosono H 2006 High-mobility thin-film transistor with amorphous InGaZnO<sub>4</sub> channel fabricated by room temperature RF-magnetron sputtering *Appl. Phys. Lett.* **89** 112123
- [44] Jeong J K, Jeong J H, Yang H W, Park J-S, Mo Y-G and Kim H D 2007 High performance thin film transistors with cosputtered amorphous indium gallium zinc oxide channel *Appl. Phys. Lett.* **91** 113505
- [45] Jeong J H, Yang H W, Park J-S, Jeong J K, Mo Y-G, Kim H D, Song J and Hwang C S 2008 Origin of subthreshold swing improvement in amorphous indium gallium zinc oxide transistors *Electrochem. Solid-State Lett.* **11** H157
- [46] Kim G H, Kim H S, Shin H S, Ahn B D, Kim K H and Kim H J 2009 Inkjet-printed InGaZnO thin film transistor *Thin Solid Films* **517** 4007–10

- [47] Kikuchi Y, Nomura K, Yanagi H, Kamiya T, Hirano M and Hosono H 2010 Device characteristics improvement of a-In-Ga-Zn-O TFTs by low-temperature annealing *Thin Solid Films* **518** 3017–21
- [48] Hota M K, Alshammari F H, Salama K N and Alshareef H N 2017 Transparent flash memory using single Ta<sub>2</sub>O<sub>5</sub> layer for both charge-trapping and tunneling dielectrics *ACS Appl. Mater. Interfaces* **9** 21856–63
- [49] Hickmott T W 1962 Low-frequency negative resistance in thin anodic oxide films *J. Appl. Phys.* **33** 2669–82
- [50] Tsuruoka T, Terabe K, Hasegawa T and Aono M 2010 Forming and switching mechanisms of a cation-migration-based oxide resistive memory *Nanotechnology* **21** 425205
- [51] Kurnia F, Liu C, Jung C U and Lee B W 2013 The evolution of conducting filaments in forming-free resistive switching Pt/TaO<sub>x</sub>/Pt structures *Appl. Phys. Lett.* **102** 152902
- [52] Torrezan A C, Strachan J P, Medeiros-Ribeiro G and Williams R S 2011 Sub-nanosecond switching of a tantalum oxide memristor *Nanotechnology* **22** 485203
- [53] Miranda E A, Walczyk C, Wenger C and Schroeder T 2010 Model for the resistive switching effect in HfO<sub>2</sub> MIM structures based on the transmission properties of narrow constrictions *IEEE Electron Device Lett.* **31** 609–11
- [54] Chen Y Y, Goux L, Clima S, Govoreanu B, Degraeve R, Kar G S, Fantini A, Groeseneken G, Wouters D J and Jurczak M 2013 Endurance/retention trade-off on HfO<sub>2</sub>/metal cap 1T1R bipolar RRAM *IEEE Trans. Electron Devices* **60** 1114–21
- [55] Chen A, Haddad S, Wu Y C, Fang T N, Kaza S and Lan Z 2008 Erasing characteristics of Cu<sub>2</sub>O metal-insulator-metal resistive switching memory *Appl. Phys. Lett.* **92** 013503
- [56] Hu P, Li X Y, Lu J Q, Yang M, Lv Q B and Li S W 2011 Oxygen deficiency effect on resistive switching characteristics of copper oxide thin films *Phys. Lett. A* **375** 1898–902
- [57] Yin M, Zhou P, Lv H B, Tang T A, Chen B A, Lin Y Y, Bao A and Chi M H 2008 Enhancement of endurance for CuxO based RRAM cell *2008 9th Int. Conf. Solid-State and Integrated-Circuit Technology (Beijing)* pp 917–20
- [58] Kwak J S, Do Y H, Bae Y C, Im H and Hong J P 2010 Reproducible unipolar resistive switching behaviors in the metal-deficient CoO<sub>x</sub> thin film *Thin Solid Films* **518** 6437–40
- [59] Gao X, Guo H, Xia Y, Yin J and Liu Z 2010 Unipolar resistive switching characteristics in Co<sub>3</sub>O<sub>4</sub> films *Thin Solid Films* **519** 450–2
- [60] Yoshida C, Kinoshita K, Yamasaki T and Sugiyama Y 2008 Direct observation of oxygen movement during resistance switching in NiO/Pt film *Appl. Phys. Lett.* **93** 042106
- [61] Sawa A 2008 Resistive switching in transition metal oxides *Mater. Today* **11** 28–36
- [62] Li C *et al* 2017 Direct observations of nanofilament evolution in switching processes in HfO<sub>2</sub>-based resistive random access memory by *in situ* TEM studies *Adv. Mater.* **29** 1602976



## Full list of references

### Chapter 1

- [1] Fanderlik I 2013 *Silica Glass and Its Application* (Amsterdam: Elsevier)
- [2] Nicollian E H and Brews J R 1982 *MOS/Metal Oxide Semiconductor/Physics and Technology* (New York: Wiley), p 920
- [3] Lee M L, Fitzgerald E A, Bulsara M T, Currie M T and Lochtefeld A 2005 Strained Si, SiGe, and Ge channels for high-mobility metal-oxide-semiconductor field-effect transistors *J. Appl. Phys.* **97** 011101
- [4] Batzill M and Diebold U 2005 The surface and materials science of tin oxide *Prog. Surf. Sci.* **79** 47–154
- [5] Rajachidambaram J S, Sanghavi S, Nachimuthu P, Shutthanandan V, Varga T, Flynn B, Thevuthasan S and Herman G S 2012 Characterization of amorphous zinc tin oxide semiconductors *J. Mater. Res.* **27** 2309–17
- [6] Kim H, Gilmore C M, Piqué A, Horwitz J S, Mattoussi H, Murata H, Kafafi Z H and Chrisey D B 1999 Electrical, optical, and structural properties of indium–tin–oxide thin films for organic light-emitting devices *J. Appl. Phys.* **86** 6451–61
- [7] Brody T P 1984 The thin film transistor—a late flowering bloom *IEEE Trans. Electron Devices* **31** 1614–28
- [8] Weimer P 1962 The TFT a new thin-film transistor *Proc. IRE* **50** 1462–9
- [9] Brody T P and Kunig H E 1966 A high-gain InAs thin-film transistor *Appl. Phys. Lett.* **9** 259–60
- [10] Kuo Y 2013 Thin film transistor technology—past, present, and future *Interface Mag.* **22** 55–61
- [11] Fortunato E, Barquinha P and Martins R 2012 Oxide semiconductor thin-film transistors: a review of recent advances *Adv. Mater.* **24** 2945–86
- [12] Sirringhaus H 2014 25th anniversary article: organic field-effect transistors: the path beyond amorphous silicon *Adv. Mater.* **26** 1319–35
- [13] Wager J F 2003 Applied physics. Transparent electronics *Science* **300** 1245–6
- [14] Wager J F 2014 Flat-panel-display backplanes: LTPS or IGZO for AMLCDs or AMOLED displays? *Inf. Disp.* **30** 26–9
- [15] Nathan A, Chaji G R and Ashtiani S J 2005 Driving schemes for a-Si and LTPS AMOLED displays *J. Disp. Technol.* **1** 267–77
- [16] Carcia P F, McLean R S, Reilly M H and Nunes G 2003 Transparent ZnO thin-film transistor fabricated by rf magnetron sputtering *Appl. Phys. Lett.* **82** 1117–9
- [17] Hoffman R L, Norris B J and Wager J F 2003 ZnO-based transparent thin-film transistors *Appl. Phys. Lett.* **82** 733–5
- [18] Nomura K, Ohta H, Ueda K, Kamiya T, Hirano M and Hosono H 2003 Thin-film transistor fabricated in single-crystalline transparent oxide semiconductor *Science* **300** 1269–72
- [19] Deng Y 2019 Understanding semiconducting metal oxide gas sensors *Semiconducting Metal Oxides for Gas Sensing* ed Y Deng (Singapore: Springer) pp 1–22
- [20] Özgür Ü, Alivov Y I, Liu C, Teke A, Reshchikov M A, Doğan S, Avrutin V, Cho S J and Morkoç H 2005 A comprehensive review of ZnO materials and devices *J. Appl. Phys.* **98** 041301

- [21] Watkins G 1997 Native defects and their interactions with impurities in silicon *MRS Online Proc. Libr. Arch.* **469** 139
- [22] Smyth D M 2000 *Defect Chemistry of Metal Oxides* (Oxford: Oxford University Press) p 304
- [23] Crawford J H and Slifkin L M 2013 *Point Defects in Solids: General and Ionic Crystals* (Berlin: Springer)
- [24] Spaeth J-M, Niklas J R and Bartram R H 2012 *Structural Analysis of Point Defects in Solids: An Introduction to Multiple Magnetic Resonance Spectroscopy* (Berlin: Springer)
- [25] Fisher E R, Elkind J L, Clemmer D E, Georgiadis R, Loh S K, Aristov N, Sunderlin L S and Armentrout P B 1990 Reactions of fourth-period metal ions ( $\text{Ca}^+ - \text{Zn}^+$ ) with  $\text{O}_2$ : metal-oxide ion bond energies *J. Chem. Phys.* **93** 2676–91
- [26] Look D C, Hemsley J W and Sizelove J R 1999 Residual native shallow donor in ZnO *Phys. Rev. Lett.* **82** 2552–5
- [27] Van De Walle C G 2000 Hydrogen as a cause of doping in zinc oxide *Phys. Rev. Lett.* **85** 1012–5
- [28] Janotti A and Van de Walle C G 2007 Hydrogen multicentre bonds *Nat. Mater.* **6** 44–7
- [29] Janotti A and Van de Walle C G 2009 Fundamentals of zinc oxide as a semiconductor *Rep. Prog. Phys.* **72** 126501
- [30] Cox S F *et al* 2001 Experimental confirmation of the predicted shallow donor hydrogen state in zinc oxide *Phys. Rev. Lett.* **86** 2601–4
- [31] Kittel C and McEuen P 1976 *Introduction to Solid State Physics* (New York: Wiley)
- [32] Holgate S A 2009 *Understanding Solid State Physics* (Boca Raton, FL: CRC Press)
- [33] Kato H, Sano M, Miyamoto K and Yao T 2002 Growth and characterization of Ga-doped ZnO layers on a-plane sapphire substrates grown by molecular beam epitaxy *J. Cryst. Growth* **237-239** 538–43
- [34] Norton D P, Heo Y W, Ivill M P, Ip K, Pearton S J, Chisholm M F and Steiner T 2004 ZnO: growth, doping and processing *Mater. Today* **7** 34–40
- [35] Neamen D A 2012 *Semiconductor Physics and Devices: Basic Principles* (New York: McGraw-Hill)
- [36] Farhan M S, Zalnezhad E, Bushroa A R and Sarhan A A D 2013 Electrical and optical properties of indium-tin oxide (ITO) films by ion-assisted deposition (IAD) at room temperature *Int. J. Precis. Eng. Manuf.* **14** 1465–9
- [37] Kim H, Piqué A, Horwitz J S, Mattoussi H, Murata H, Kafafi Z H and Chrisey D B 1999 Indium tin oxide thin films for organic light-emitting devices *Appl. Phys. Lett.* **74** 3444–6
- [38] Kawachi G, Kimura E, Wakui Y, Konishi N, Yamamoto H, Matsukawa Y and Sasano A 1994 A novel technology for a-Si TFT-LCD's with buried ITO electrode structure *IEEE Trans. Electron Devices* **41** 1120–4
- [39] Du J, Chen X-L, Liu C-C, Ni J, Hou G-F, Zhao Y and Zhang X-D 2014 Highly transparent and conductive indium tin oxide thin films for solar cells grown by reactive thermal evaporation at low temperature *Appl. Phys. A* **117** 815–22
- [40] Frach P, Glöß D, Goedicke K, Fahland M and Gnehr W M 2003 High rate deposition of insulating  $\text{TiO}_2$  and conducting ITO films for optical and display applications *Thin Solid Films* **445** 251–8
- [41] Kim S I, Cho S H, Choi S R, Oh M C, Jang J H and Song P K 2009 Crystallization and electrical properties of ITO:Ce thin films for flat panel display applications *Thin Solid Films* **517** 4061–4

- [42] Nomura K, Ohta H, Takagi A, Kamiya T, Hirano M and Hosono H 2004 Room-temperature fabrication of transparent flexible thin-film transistors using amorphous oxide semiconductors *Nature* **432** 488–92
- [43] Yabuta H, Sano M, Abe K, Aiba T, Den T, Kumomi H, Nomura K, Kamiya T and Hosono H 2006 High-mobility thin-film transistor with amorphous InGaZnO<sub>4</sub> channel fabricated by room temperature RF-magnetron sputtering *Appl. Phys. Lett.* **89** 112123
- [44] Jeong J K, Jeong J H, Yang H W, Park J-S, Mo Y-G and Kim H D 2007 High performance thin film transistors with cosputtered amorphous indium gallium zinc oxide channel *Appl. Phys. Lett.* **91** 113505
- [45] Jeong J H, Yang H W, Park J-S, Jeong J K, Mo Y-G, Kim H D, Song J and Hwang C S 2008 Origin of subthreshold swing improvement in amorphous indium gallium zinc oxide transistors *Electrochem. Solid-State Lett.* **11** H157
- [46] Kim G H, Kim H S, Shin H S, Ahn B D, Kim K H and Kim H J 2009 Inkjet-printed InGaZnO thin film transistor *Thin Solid Films* **517** 4007–10
- [47] Kikuchi Y, Nomura K, Yanagi H, Kamiya T, Hirano M and Hosono H 2010 Device characteristics improvement of a-In-Ga-Zn-O TFTs by low-temperature annealing *Thin Solid Films* **518** 3017–21
- [48] Hota M K, Alshammari F H, Salama K N and Alshareef H N 2017 Transparent flash memory using single Ta<sub>2</sub>O<sub>5</sub> layer for both charge-trapping and tunneling dielectrics *ACS Appl. Mater. Interfaces* **9** 21856–63
- [49] Hickmott T W 1962 Low-frequency negative resistance in thin anodic oxide films *J. Appl. Phys.* **33** 2669–82
- [50] Tsuruoka T, Terabe K, Hasegawa T and Aono M 2010 Forming and switching mechanisms of a cation-migration-based oxide resistive memory *Nanotechnology* **21** 425205
- [51] Kurnia F, Liu C, Jung C U and Lee B W 2013 The evolution of conducting filaments in forming-free resistive switching Pt/TaO<sub>x</sub>/Pt structures *Appl. Phys. Lett.* **102** 152902
- [52] Torrezan A C, Strachan J P, Medeiros-Ribeiro G and Williams R S 2011 Sub-nanosecond switching of a tantalum oxide memristor *Nanotechnology* **22** 485203
- [53] Miranda E A, Walczyk C, Wenger C and Schroeder T 2010 Model for the resistive switching effect in HfO<sub>2</sub> MIM structures based on the transmission properties of narrow constrictions *IEEE Electron Device Lett.* **31** 609–11
- [54] Chen Y Y, Goux L, Clima S, Govoreanu B, Degraeve R, Kar G S, Fantini A, Groeseneken G, Wouters D J and Jurczak M 2013 Endurance/retention trade-off on HfO<sub>2</sub>/metal cap 1T1R bipolar RRAM *IEEE Trans. Electron Devices* **60** 1114–21
- [55] Chen A, Haddad S, Wu Y C, Fang T N, Kaza S and Lan Z 2008 Erasing characteristics of Cu<sub>2</sub>O metal-insulator-metal resistive switching memory *Appl. Phys. Lett.* **92** 013503
- [56] Hu P, Li X Y, Lu J Q, Yang M, Lv Q B and Li S W 2011 Oxygen deficiency effect on resistive switching characteristics of copper oxide thin films *Phys. Lett. A* **375** 1898–902
- [57] Yin M, Zhou P, Lv H B, Tang T A, Chen B A, Lin Y Y, Bao A and Chi M H 2008 Enhancement of endurance for CuxO based RRAM cell *2008 9th Int. Conf. Solid-State and Integrated-Circuit Technology (Beijing)* pp 917–20
- [58] Kwak J S, Do Y H, Bae Y C, Im H and Hong J P 2010 Reproducible unipolar resistive switching behaviors in the metal-deficient CoO<sub>x</sub> thin film *Thin Solid Films* **518** 6437–40
- [59] Gao X, Guo H, Xia Y, Yin J and Liu Z 2010 Unipolar resistive switching characteristics in Co<sub>3</sub>O<sub>4</sub> films *Thin Solid Films* **519** 450–2

- [60] Yoshida C, Kinoshita K, Yamasaki T and Sugiyama Y 2008 Direct observation of oxygen movement during resistance switching in NiO/Pt film *Appl. Phys. Lett.* **93** 042106
- [61] Sawa A 2008 Resistive switching in transition metal oxides *Mater. Today* **11** 28–36
- [62] Li C *et al* 2017 Direct observations of nanofilament evolution in switching processes in HfO<sub>2</sub>-based resistive random access memory by *in situ* TEM studies *Adv. Mater.* **29** 1602976

## Chapter 2

- [1] Fortunato E, Barquinha P and Martins R 2012 Oxide semiconductor thin-film transistors: a review of recent advances *Adv. Mater.* **24** 2945–86
- [2] Nathan A, Lee S, Jeon S and Robertson J 2014 Amorphous oxide semiconductor TFTs for displays and imaging *J. Display Technol.* **10** 917–27
- [3] Park J S, Maeng W-J, Kim H-S and Park J-S 2012 Review of recent developments in amorphous oxide semiconductor thin-film transistor devices *Thin Solid Films* **520** 1679–93
- [4] Nomura K, Ohta H, Takagi A, Kamiya T, Hirano M and Hosono H 2004 Room-temperature fabrication of transparent flexible thin-film transistors using amorphous oxide semiconductors *Nature* **432** 488
- [5] Kamiya T, Nomura K and Hosono H 2010 Present status of amorphous In–Ga–Zn–O thin-film transistors *Sci. Technol. Adv. Mater.* **11** 044305
- [6] Zhou W *et al* 2012 Bridged-grain solid-phase-crystallized polycrystalline-silicon thin-film transistors *IEEE Electron Device Lett.* **33** 1414–6
- [7] Deng S, Chen R, Zhou W, Ho J Y L, Wong M and Kwok H S 2016 Fabrication of high-performance bridged-grain polycrystalline silicon TFTs by laser interference lithography *IEEE Trans. Electron Devices* **63** 1085–90
- [8] Wager J F 2016 Oxide TFTs: a progress report *Inf. Display* **31** 16–21
- [9] Wang Z, Nayak P K, Caraveo-Frescas J A and Alshareef H N 2016 Recent developments in p-Type oxide semiconductor materials and devices *Adv. Mater.* **28** 3831–92
- [10] Wallmark J T and Johnson H 1966 *Field-Effect Transistors: Physics, Technology and Applications* (Upper Saddle River, NJ: Prentice Hall)
- [11] Kwon J Y and Jeong J K 2015 Recent progress in high performance and reliable n-type transition metal oxide-based thin film transistors *Semicond. Sci. Technol.* **30** 024002
- [12] Yeom H-I *et al* 2016 60-3: distinguished paper: oxide vertical TFTs for the application to the ultra high resolution display *SID Symp. Dig. Tech. Pap.* **47** 820–22
- [13] Xu H *et al* 2011 High performance indium-zinc-oxide thin-film transistors fabricated with a back-channel-etch-technique *Appl. Phys. Lett.* **99** 253501
- [14] Luo D *et al* 2013 Effects of etching residue on positive shift of threshold voltage in amorphous indium–zinc-oxide thin-film transistors based on back-channel-etch structure *IEEE Trans. Electron Devices* **61** 92–7
- [15] Park Y, Um J, Mativenga M and Jang J 2015 Modification of electrode-etchant for sidewall profile control and reduced back-channel corrosion of inverted-staggered metal-oxide TFTs *ECS J. Solid State Sci. Technol.* **4** Q124–9
- [16] Kang D H, Kang I, Ryu S H and Jang J 2011 Self-aligned coplanar a-IGZO TFTs and application to high-speed circuits *IEEE Electron Device Lett.* **32** 1385–7
- [17] Chen R, Zhou W, Zhang M, Wong M and Kwok H S 2012 Self-aligned indium–gallium–zinc oxide thin-film transistor with source/drain regions doped by implanted arsenic *IEEE Electron Device Lett.* **34** 60–2

- [18] Chen R, Zhou W, Zhang M, Wong M and Kwok H S 2012 Self-aligned indium–gallium–zinc oxide thin-film transistor with phosphorus-doped source/drain regions *IEEE Electron Device Lett.* **33** 1150–2
- [19] Wu C-H, Hsieh H-H, Chien C-W and Wu C-C 2009 Self-aligned top-gate coplanar In-Ga-Zn-O thin-film transistors *J. Disp. Technol.* **5** 515–9
- [20] Kim S *et al* 2009 Source/drain formation of self-aligned top-gate amorphous GaInZnO thin-film transistors by NH<sub>3</sub> plasma treatment *IEEE Electron Device Lett.* **30** 374–6
- [21] Allemang C R *et al* 2020 High-performance zinc tin oxide TFTs with active layers deposited by atomic layer deposition *Adv. Electron. Mater.* **6** 2000195
- [22] Zhirnov V V and Cavin R K 2008 Negative capacitance to the rescue? *Nat. Nanotechnol.* **3** 77–8
- [23] Klasens H and Koelmans H J S 1964 A tin oxide field-effect transistor *Solid-State Electron.* **7** 701–2
- [24] Boesen G and Jacobs J E 1968 ZnO field-effect transistor *Proc. IEEE* **56** 2094–5
- [25] Nomura K, Ohta H, Ueda K, Kamiya T, Hirano M and Hosono H 2003 Thin-film transistor fabricated in single-crystalline transparent oxide semiconductor *Science* **300** 1269–72
- [26] Yaglioglu B, Yeom H Y, Beresford R and Paine D C 2006 High-mobility amorphous In<sub>2</sub>O<sub>3</sub>–10wt%ZnO thin film transistors *Appl. Phys. Lett.* **89** 062103
- [27] Chiang H, Wager J, Hoffman R, Jeong J and Keszler D A 2005 High mobility transparent thin-film transistors with amorphous zinc tin oxide channel layer *Appl. Phys. Lett.* **86** 013503
- [28] Ryu M K, Yang S, Park S-H K, Hwang C-S and Jeong J K 2009 High performance thin film transistor with cosputtered amorphous Zn–In–Sn–O channel: combinatorial approach *Appl. Phys. Lett.* **95** 072104
- [29] Kim C-J *et al* 2009 Amorphous hafnium-indium-zinc oxide semiconductor thin film transistors *Appl. Phys. Lett.* **95** 252103
- [30] Cho D H *et al* 2009 Transparent oxide thin-film transistors composed of Al and Sn-doped zinc indium oxide *IEEE Electron Device Lett.* **30** 48–50
- [31] Yamazaki S *et al* 2019 Crystalline IGZO ceramics (crystalline oxide semiconductor)-based devices for artificial intelligence *Int. J. Ceram. Eng. Sci.* **1** 6–20
- [32] Özgür Ü *et al* 2005 A comprehensive review of ZnO materials and devices *J. Appl. Phys.* **98** 11
- [33] Hoffman R, Norris B J and Wager J 2003 ZnO-based transparent thin-film transistors *Appl. Phys. Lett.* **82** 733–5
- [34] Masuda S, Kitamura K, Okumura Y, Miyatake S, Tabata H and Kawai T 2003 Transparent thin film transistors using ZnO as an active channel layer and their electrical properties *J. Appl. Phys.* **93** 1624–30
- [35] Carcia P, McLean R, Reilly M and Nunes G Jr 2003 Transparent ZnO thin-film transistor fabricated by rf magnetron sputtering *Appl. Phys. Lett.* **82** 1117–9
- [36] Fortunato E M *et al* 2005 Fully transparent ZnO thin-film transistor produced at room temperature *Adv. Mater.* **17** 590–4
- [37] Kim Y S and Park C H 2009 Rich variety of defects in ZnO via an attractive interaction between O vacancies and Zn interstitials: origin of n-type doping *Phys. Rev. Lett.* **102** 2009
- [38] 2009 Zinc oxide: perfect pair of defects *NPG Asia Mater.* (<https://doi.org/10.1038/asiamat.2009.216>)

- [39] Ahn C H, Kim S H, Kim Y H and Cho H K 2016 Extremely thin Al<sub>2</sub>O<sub>3</sub> surface-passivated nanocrystalline ZnO thin-film transistors designed for low process temperature *J. Am. Ceram. Soc.* **99** 1305–10
- [40] Barquinha P, Martins R, Pereira L and Fortunato E 2012 *Transparent Oxide Electronics: From Materials to Devices* (New York: Wiley)
- [41] Jun T, Kim J, Sasase M and Hosono H 2018 Material design of p-type transparent amorphous semiconductor, Cu-Sn-I *Adv. Mater.* **30** 1706573
- [42] Buchholz D B *et al* 2014 The structure and properties of amorphous indium oxide *Chem. Mater.* **26** 5401–11
- [43] Medvedeva J E, Buchholz D B and Chang R P H 2017 Recent advances in understanding the structure and properties of amorphous oxide semiconductors *Adv. Electron. Mater.* **3** 1700082
- [44] Hosono H, Kikuchi N, Ueda N and Kawazoe H 1996 Working hypothesis to explore novel wide band gap electrically conducting amorphous oxides and examples *J. Non-Cryst. Solids* **198** 165–9
- [45] Kamiya T, Nomura K and Hosono H 2010 Subgap states, doping and defect formation energies in amorphous oxide semiconductor a-InGaZnO<sub>4</sub> studied by density functional theory *Phys. Status Solidi a* **207** 1698–703
- [46] Itagaki N *et al* 2008 Zn-In-O based thin-film transistors: compositional dependence *Phys. Status Solidi a* **205** 1915–9
- [47] Spiehl D, Haming M, Sauer H M, Bonrad K and Dorsam E 2015 Engineering of flexo- and gravure-printed indium–zinc-oxide semiconductor layers for high-performance thin-film transistors *IEEE Trans. Electron Devices* **62** 2871–7
- [48] Lee S *et al* 2011 Trap-limited and percolation conduction mechanisms in amorphous oxide semiconductor thin film transistors *Appl. Phys. Lett.* **98** 203508
- [49] Lokanc M, Eggert R and Redlinger M 2015 The availability of indium: the present, medium term, and long term *Report National Renewable Energy Lab. (NREL), Golden, CO (United States)*
- [50] Son Y, Frost B, Zhao Y and Peterson R L J N E 2019 Monolithic integration of high-voltage thin-film electronics on low-voltage integrated circuits using a solution process *Nat. Electron.* **2** 540–8
- [51] Wang G *et al* 2019 Implementation of self-aligned top-gate amorphous zinc tin oxide thin-film transistors *IEEE Electron Device Lett.* **40** 901–4
- [52] Kim Y-H, Han J-I and Park S K 2011 Effect of zinc/tin composition ratio on the operational stability of solution-processed zinc–tin–oxide thin-film transistors *IEEE Electron Device Lett.* **33** 50–2
- [53] Ghaffarzadeh K *et al* 2010 Persistent photoconductivity in Hf–In–Zn–O thin film transistors *Appl. Phys. Lett.* **97** 143510
- [54] Jeong W H *et al* 2010 Investigating addition effect of hafnium in InZnO thin film transistors using a solution process *Appl. Phys. Lett.* **96** 093503
- [55] Maeng W *et al* 2011 The effect of active-layer thickness and back-channel conductivity on the subthreshold transfer characteristics of Hf–In–Zn–O TFTs *IEEE Electron Device Lett.* **32** 1077–9
- [56] Park J S, Kim K, Park Y G, Mo Y G, Kim H D and Jeong J K 2009 Novel ZrInZnO thin-film transistor with excellent stability *Adv. Mater.* **21** 329–33

- [57] Ye Z, Yue S, Zhang J, Li X, Chen L and Lu J 2016 Annealing treatment on amorphous InAlZnO films for thin-film transistors *IEEE Trans. Electron Devices* **63** 3547–51
- [58] Cho D-H *et al* 2008 Transparent Al–Zn–Sn–O thin film transistors prepared at low temperature *Appl. Phys. Lett.* **93** 142111
- [59] Cho D-H *et al* 2008 Transparent oxide thin-film transistors composed of Al and Sn-doped zinc indium oxide *IEEE Electron Device Lett.* **30** 48–50
- [60] Park J C, Kim S W, Kim C J and Lee H-N 2012 Low-temperature fabrication and characteristics of lanthanum indium zinc oxide thin-film transistors *IEEE Electron Device Lett.* **33** 685–7
- [61] Kim S H, Ahn C H, Yun M G, Cho S W and Cho H K 2014 Anomalous tin chemical bonding in indium-zinc-tin oxide films and their thin film transistor performance *J. Phys. D: Appl. Phys.* **47** 485101
- [62] Ji Hun S, Kwang Suk K, Yeon Gon M, Rino C and Kyeong Jeong J 2014 Achieving high field-effect mobility exceeding 50 cm<sup>2</sup>/Vs in In-Zn-Sn-O thin-film transistors *IEEE Electron Device Lett.* **35** 853–5
- [63] Kim M-G *et al* 2010 High-performance solution-processed amorphous zinc-indium-tin oxide thin-film transistors *JACS* **132** 10352–64
- [64] Kimizuka N and Yamazaki S 2016 *Physics and Technology of Crystalline Oxide Semiconductor CAAC-IGZO: Fundamentals* (New York: Wiley)
- [65] Yamazaki S and Tsutsui T 2017 *Physics and Technology of Crystalline Oxide Semiconductor CAAC-IGZO: Application to Displays* (New York: Wiley)
- [66] Yamazaki S and Fujita M 2016 *Physics and Technology of Crystalline Oxide Semiconductor CAAC-IGZO: Application to LSI* (New York: Wiley)
- [67] Yamazaki S *et al* 2014 Properties of crystalline In–Ga–Zn-oxide semiconductor and its transistor characteristics *Japan J. Appl. Phys.* **53** 04ED18
- [68] Kim G H, Du Ahn B, Shin H S, Jeong W H, Kim H J and Kim H J 2009 Effect of indium composition ratio on solution-processed nanocrystalline InGaZnO thin film transistors *Appl. Phys. Lett.* **94** 233501
- [69] Yamazaki S, Shima Y, Hosaka Y, Okazaki K and Koezuka J 2016 Achievement of a high-mobility FET with a cloud-aligned composite oxide semiconductor *Japan J. Appl. Phys.* **55** 115504
- [70] Koezuka J *et al* 2017 24-1: invited paper: flexible OLED display using C-axis-aligned-crystal/cloud-aligned composite oxide semiconductor technology and laser separation technology *SID Symp. Dig. Tech. Pap.* **48** 329–32
- [71] Deng S *et al* 2016 High-performance staggered top-gate thin-film transistors with hybrid-phase microstructural ITO-stabilized ZnO channels *Appl. Phys. Lett.* **109** 182105
- [72] Deng S *et al* 2017 Investigation of high-performance ITO-stabilized ZnO TFTs with hybrid-phase microstructural channels *IEEE Trans. Electron Devices* **64** 3174–82
- [73] In H-J and Kwon O-K 2009 External compensation of nonuniform electrical characteristics of thin-film transistors and degradation of OLED devices in AMOLED displays *IEEE Electron Device Lett.* **30** 377–9
- [74] Jeong J K, Won Yang H, Jeong J H, Mo Y-G and Kim H D 2008 Origin of threshold voltage instability in indium-gallium-zinc oxide thin film transistors *Appl. Phys. Lett.* **93** 123508
- [75] Kang D *et al* 2007 Amorphous gallium indium zinc oxide thin film transistors: sensitive to oxygen molecules *Appl. Phys. Lett.* **90** 192101

- [76] Park J-S, Jeong J K, Chung H-J, Mo Y-G and Kim H D J A P L 2008 Electronic transport properties of amorphous indium-gallium-zinc oxide semiconductor upon exposure to water *Appl. Phys. Lett.* **92** 072104
- [77] Chen T-C, Kuo Y, Chang T-C, Chen M-C and Chen H-M 2017 Mechanism of a-IGZO TFT device deterioration—illumination light wavelength and substrate temperature effects *J. Phys. D: Appl. Phys.* **50** 42LT02
- [78] Chuang C S *et al* 2008 P-13: photosensitivity of amorphous IGZO TFTs for active-matrix flat-panel displays *SID Symp. Dig. Tech. Pap.* **39** 1215–8
- [79] Jeon S *et al* 2012 Gated three-terminal device architecture to eliminate persistent photoconductivity in oxide semiconductor photosensor arrays *Nat. Mater.* **11** 301
- [80] Li J, Lu L, Chen R, Kwok H-S and Wong M J 2017 A physical model for metal–oxide thin-film transistor under gate-bias and illumination stress *IEEE Trans. Electron Devices* **65** 142–9
- [81] Stewart K A, Yeh B-S and Wager J F 2016 Amorphous semiconductor mobility limits *J. Non-Cryst. Solids* **432** 196–9
- [82] Yang S *et al* 2010 Improvement in the photon-induced bias stability of Al–Sn–Zn–In–O thin film transistors by adopting  $\text{AlO}_x$  passivation layer *Appl. Phys. Lett.* **96** 213511
- [83] Lee K-H *et al* 2009 The effect of moisture on the photon-enhanced negative bias thermal instability in Ga–In–Zn–O thin film transistors *Appl. Phys. Lett.* **95** 232106
- [84] Ji K H *et al* 2010 Comparative study on light-induced bias stress instability of IGZO transistors with  $\text{SiN}_x$   $\text{SiO}_2$  gate dielectrics *IEEE Electron Device Lett.* **31** 1404–6
- [85] Shin J H *et al* 2009 Light effects on the bias stability of transparent ZnO thin film transistors *ETRI J.* **31** 62–4
- [86] Kwon J-Y *et al* 2010 The impact of gate dielectric materials on the light-induced bias instability in Hf–In–Zn–O thin film transistor *Appl. Phys. Lett.* **97** 183503
- [87] Huang X *et al* 2012 Electrical instability of amorphous indium-gallium-zinc oxide thin film transistors under monochromatic light illumination *Appl. Phys. Lett.* **100** 243505
- [88] Migliorato P, Delwar Hossain Chowdhury M, Gwang Um J, Seok M and Jang J 2012 Light/negative bias stress instabilities in indium gallium zinc oxide thin film transistors explained by creation of a double donor *Appl. Phys. Lett.* **101** 123502
- [89] Lee S, Nathan A, Jeon S and Robertson J 2015 Oxygen defect-induced metastability in oxide semiconductors probed by gate pulse spectroscopy *Sci. Rep.* **5** 1–10
- [90] Hsieh T-Y, Chang T-C, Chen T-C and Tsai M-Y 2014 Review of present reliability challenges in amorphous In-Ga-Zn-O thin film transistors *ECS J. Solid State Sci. Technol.* **3** Q3058–70
- [91] Oh S, Baek J H, Bae J U, Park K-S and Kang I B 2016 Effect of interfacial excess oxygen on positive-bias temperature stress instability of self-aligned coplanar InGaZnO thin-film transistors *Appl. Phys. Lett.* **108** 141604
- [92] Kim D H *et al* 2017 21-4: distinguished paper: experimental decomposition of the positive bias temperature stress-induced instability in self-aligned coplanar InGaZnO thin-film transistors and its modeling based on the multiple stretched-exponential functions *SID Symp. Dig. Tech. Pap.* **48** 298–301
- [93] Ji K H *et al* 2010 The effect of density-of-state on the temperature and gate bias-induced instability of InGaZnO thin film transistors *J. Electrochem. Soc.* **157** H983



- [94] Jin S, Kim T-W, Seol Y-G, Mativenga M and Jang J 2014 Reduction of positive-bias-stress effects in bulk-accumulation amorphous-InGaZnO TFTs *IEEE Electron Device Lett.* **35** 560–2
- [95] Yang J *et al* 2017 Investigation of an anomalous hump phenomenon in via-type amorphous In-Ga-Zn-O thin-film transistors under positive bias temperature stress *Appl. Phys. Lett.* **110** 143508
- [96] Im H, Song H, Jeong J, Hong Y and Hong Y 2015 Effects of defect creation on bidirectional behavior with hump characteristics of InGaZnO TFTs under bias and thermal stress *Japan. J. Appl. Phys.* **54** 03CB03
- [97] Hosono H 2006 Ionic amorphous oxide semiconductors: material design, carrier transport, and device application *J. Non-Cryst. Solids* **352** 851–8
- [98] Kamiya T and Hosono H 2010 Material characteristics and applications of transparent amorphous oxide semiconductors *NPG Asia Mater.* **2** 15
- [99] Kyungsoo J, Raja J, Youn-Jung L, Doyoung K and Junsin Y 2013 Effects of carrier concentration, indium content, and crystallinity on the electrical properties of indium-tin-zinc-oxide thin-film transistors *IEEE Electron Device Letters* **34** 1151–3
- [100] Saji K J, Jayaraj M K, Nomura K, Kamiya T and Hosono H 2008 Optical and carrier transport properties of cosputtered Zn–In–Sn–O films and their applications to TFTs *J. Electrochem. Soc.* **155** H390–5
- [101] Shao Y, Xiao X, Wang L, Liu Y and Zhang S 2014 Anodized ITO thin-film transistors *Adv. Funct. Mater.* **24** 4170–5
- [102] Le Y, Shao Y, Xiao X, Xu X and Zhang S 2016 Indium–tin–oxide thin-film transistors with *in situ* anodized Ta<sub>2</sub>O<sub>5</sub> passivation layer *IEEE Electron Device Lett.* **37** 603–6
- [103] Jang Yeon K and Kyeong J J 2015 Recent progress in high performance and reliable n-type transition metal oxide-based thin film transistors *Semicond. Sci. Technol.* **30** 024002
- [104] Jeon S *et al* 2010 Low-frequency noise performance of a bilayer InZnO–InGaZnO thin-film transistor for analog device applications *IEEE Electron Device Letters* **31** 1128–30
- [105] Chung Y J, Kim U K, Hwang E S and Hwang C S 2014 Indium tin oxide/InGaZnO bilayer stacks for enhanced mobility and optical stability in amorphous oxide thin film transistors *Appl. Phys. Lett.* **105** 013508
- [106] Wang S-L *et al* 2012 High mobility thin film transistors with indium oxide/gallium oxide bilayer structures *Appl. Phys. Lett.* **100** 063506
- [107] Stewart K A and Wager J F 2016 69-2: oxide-TFT mobility limits and CMOS feasibility *SID Symp. Dig. Tech. Pap.* **47** 944–6
- [108] Stewart K A and Wager J F 2016 Thin-film transistor mobility limits considerations *J. Soc. Inf. Disp.* **24** 386–93
- [109] Deng S *et al* 2018 P-20: towards high-performance and cost-effective top-gated oxide TFTs with hybrid-phase microstructural channels *SID Symp. Dig. Tech. Pap.* **49** 1252–5
- [110] Pan T-M, Peng B-J, Her J-L and Lou B-S 2017 Effect of In and Zn content on structural and electrical properties of InZnSnO thin-film transistors using an Yb<sub>2</sub>TiO<sub>5</sub> gate dielectric *IEEE Trans. Electron Devices* **64** 2233–8
- [111] Cheng M-H, Zhao C, Huang C-L, Kim H, Nakata M and Kanicki J 2016 Amorphous InSnZnO thin-film transistor voltage-mode active pixel sensor circuits for indirect x-ray imagers *IEEE Trans. Electron Devices* **63** 4802–10

- [112] Raja J *et al* 2016 Improved data retention of InSnZnO nonvolatile memory by H<sub>2</sub>O<sub>2</sub> treated Al<sub>2</sub>O<sub>3</sub> tunneling layer: a cost-effective method *IEEE Electron Device Lett.* **37** 1272–5
- [113] Deng S *et al* 2017 Investigation of high-performance ITO-stabilized ZnO TFTs with hybrid-phase microstructural channels *IEEE Trans. Electron Devices* **64** 3174–82
- [114] Chiu C, Chang S and Chang S-J 2010 High-performance a-IGZO thin-film transistor using Ta<sub>2</sub>O<sub>5</sub> gate dielectric *IEEE Electron Device Lett.* **31** 1245–7
- [115] Ma P *et al* 2018 Low voltage operation of IGZO thin film transistors enabled by ultrathin Al<sub>2</sub>O<sub>3</sub> gate dielectric *Appl. Phys. Lett.* **112** 023501
- [116] Kim J, Fuentes-Hernandez C, Potscavage W Jr, Zhang X-H and Kippelen B 2009 Low-voltage InGaZnO thin-film transistors with Al<sub>2</sub>O<sub>3</sub> gate insulator grown by atomic layer deposition *Appl. Phys. Lett.* **94** 142107
- [117] Rembert T, Battaglia C, Anders A and Javey A 2015 Room temperature oxide deposition approach to fully transparent, all-oxide thin-film transistors *Adv. Mater.* **27** 6090–5
- [118] Ji K H *et al* 2010 Comparative study on light-induced bias stress instability of IGZO transistors with SiN<sub>x</sub> and SiO<sub>2</sub> gate dielectrics *IEEE Electron Device Lett.* **31** 1404–6
- [119] Lee J-M, Cho I-T, Lee J-H, Cheong W-S, Hwang C-S and Kwon H-I 2009 Comparative study of electrical instabilities in top-gate InGaZnO thin film transistors with Al<sub>2</sub>O<sub>3</sub> and Al<sub>2</sub>O<sub>3</sub>/SiN<sub>x</sub> gate dielectrics *Appl. Phys. Lett.* **94** 222112
- [120] Seshan K and Schepis D 2018 *Handbook of Thin Film Deposition* (Burlington, MA: William Andrew)
- [121] Lu L, Li J and Wong M 2014 A comparative study on the effects of annealing on the characteristics of zinc oxide thin-film transistors with gate-stacks of different gas-permeability *IEEE Electron Device Lett.* **35** 841–3
- [122] Park J-S, Jeong J K, Chung H-J, Mo Y-G and Kim H D 2008 Electronic transport properties of amorphous indium-gallium-zinc oxide semiconductor upon exposure to water *Appl. Phys. Lett.* **92** 072104
- [123] Deng S *et al* 2019 Gate insulator engineering in top-gated indium-tin-oxide-stabilized ZnO thin-film transistors **40** 1104–7
- [124] Kim J, Fuentes-Hernandez C, Potscavage W Jr, Zhang X-H and Kippelen B 2009 Low-voltage InGaZnO thin-film transistors with Al<sub>2</sub>O<sub>3</sub> gate insulator grown by atomic layer deposition *Appl. Phys. Lett.* **94** 142107
- [125] Ma P *et al* 2018 Low voltage operation of IGZO thin film transistors enabled by ultrathin Al<sub>2</sub>O<sub>3</sub> gate dielectric *Appl. Phys. Lett.* **112** 023501
- [126] Chen R, Zhou W, Zhang M, Wong M and Kwok H S 2013 Self-aligned top-gate InGaZnO thin film transistors using SiO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub> stack gate dielectric *Thin Solid Films* **548** 572–5
- [127] Shao Y, Xiao X, He X, Deng W and Zhang S 2015 Low-voltage a-InGaZnO thin-film transistors with anodized thin HfO<sub>2</sub> gate dielectric *IEEE Electron Device Lett.* **36** 573–5
- [128] Ma P *et al* 2018 Half-volt operation of IGZO thin-film transistors enabled by ultrathin HfO<sub>2</sub> gate dielectric *Appl. Phys. Lett.* **113** 063501
- [129] Yuan L, Zou X, Fang G, Wan J, Zhou H and Zhao X 2011 High-performance amorphous indium gallium zinc oxide thin-film transistors with HfO<sub>x</sub>N<sub>y</sub>/HfO<sub>2</sub>/HfO<sub>x</sub>N<sub>y</sub> tristack gate dielectrics *IEEE Electron Device Lett.* **32** 42
- [130] Shan F, Liu A, Liu G, Meng Y, Fortunato E and Martins R 2014 Low-voltage high-stability InZnO thin-film transistor using ultra-thin solution-processed ZrO<sub>x</sub> dielectric *J. Disp. Technol.* **11** 541–6

- [131] Lee J S, Chang S, Koo S-M and Lee S Y 2010 High-performance a-IGZO TFT with  $ZrO_2$  gate dielectric fabricated at room temperature *IEEE Electron Device Lett.* **31** 225–7
- [132] Park J C *et al* 2014 Comparative study of  $ZrO_2$  and  $HfO_2$  as a high-k dielectric for amorphous InGaZnO thin film transistors *J. Nanoelectron. Optoelectron.* **9** 67–70
- [133] Chang T, Chiu C, Weng W, Chang S-J, Tsai T and Huang Z J A P L 2012 High responsivity of amorphous indium gallium zinc oxide phototransistor with  $Ta_2O_5$  gate dielectric *Appl. Phys. Lett.* **101** 261112
- [134] Chiu C, Chang S and Chang S-J J I E D L 2010 High-performance a-IGZO thin-film transistor using  $Ta_2O_5$  gate dielectric *IEEE Electron Device Lett.* **31** 1245–7
- [135] Shao Y, Xiao X, Wang L, Liu Y and Zhang S 2014 Anodized ITO thin-film transistors *Adv. Funct. Mater.* **24** 4170–5
- [136] Ning H *et al* 2018 Facile room temperature routes to improve performance of IGZO thin-film transistors by an ultrathin  $Al_2O_3$  passivation layer *IEEE Trans. Electron Devices* **65** 537–41
- [137] Weng S *et al* 2019 High-performance amorphous zinc–tin–oxide thin-film transistors with low tin concentration *IEEE J. Electron Devices Soc.* **7** 632–7
- [138] Zhong W, Yao R, Liu Y, Lan L and Chen R 2020 Effect of self-assembled monolayers (SAMs) as surface passivation on the flexible a-InSnZnO thin-film transistors *IEEE Trans. Electron Devices* **67** 3157–62
- [139] Deng S *et al* 2018 Threshold voltage adjustment in hybrid-microstructural ITO-stabilized ZnO TFTs via gate electrode engineering *IEEE Electron Device Lett.* **39** 975–8
- [140] Chen C-L *et al* 2016 A physics-based model of threshold voltage for amorphous oxide semiconductor thin-film transistors *AIP Adv.* **6** 035025
- [141] Wang W *et al* 2015 Analysis of the contact resistance in amorphous InGaZnO thin film transistors *Appl. Phys. Lett.* **107** 063504
- [142] Kim W-S, Moon Y-K, Kim K-T, Lee J-H and Park J-W 2010 An investigation of contact resistance between metal electrodes and amorphous gallium–indium–zinc oxide (a-GIZO) thin-film transistors *Thin Solid Films* **518** 6357–60
- [143] Lee S, Park H and Paine D C 2012 The effect of metallization contact resistance on the measurement of the field effect mobility of long-channel unannealed amorphous In–Zn–O thin film transistors *Thin Solid Films* **520** 3769–73
- [144] Morosawa N, Ohshima Y, Morooka M, Arai T and Sasaoka T 2012 Novel self-aligned top-gate oxide TFT for AMOLED displays *J. Soc. Inform. Display* **20** 47–52
- [145] Nag M *et al* 2015 Low-temperature formation of source–drain contacts in self-aligned amorphous oxide thin-film transistors *J. Inform. Display* **16** 111–7
- [146] Peng H *et al* 2020 Top-gate amorphous indium-gallium-zinc-oxide thin-film transistors with magnesium metallized source/drain regions *IEEE Trans. Electron Devices* **67** 1619–24
- [147] Park J *et al* 2008 Self-aligned top-gate amorphous gallium indium zinc oxide thin film transistors *Appl. Phys. Lett.* **93** 053501
- [148] Kim S *et al* 2009 Source/drain formation of self-aligned top-gate amorphous-GaInZnO thin film transistors by  $NH_3$  plasma treatment *IEEE Electron Device Lett.* **30** 374
- [149] Xia Z, Lu L, Li J, Kwok H-S and Wong M 2018 A bottom-gate metal-oxide thin-film transistor with self-aligned source/drain regions **65** 2820–6
- [150] Xia Z, Lu L, Li J, Kwok H-S and Wong M 2019 Self-aligned elevated-metal metal-oxide thin-film transistors for displays and flexible electronics *2019 IEEE Int. Electron Devices Meeting (IEDM)* (Piscataway, NJ: IEEE), pp 8.4.1–4

- [151] Lu L, Li J, Feng Z, Kwok H S and Wong M 2016 Elevated-metal–metal-oxide thin-film transistor: technology and characteristics *IEEE Electron Device Lett.* **37** 728–30
- [152] Nag M *et al* 2015 P-6: impact of buffer layers on the self-aligned top-gate a-IGZO TFT characteristics *SID Symp. Dig. Tech. Pap.* **46** 1139–42
- [153] Minami T, Sato H, Nanto H and Takata S 1986 Highly conductive and transparent silicon doped zinc oxide thin films prepared by RF magnetron sputtering *Japan J. Appl. Phys.* **25** L776
- [154] Das A, Misra P and Kukreja L 2009 Effect of Si doping on electrical and optical properties of ZnO thin films grown by sequential pulsed laser deposition *J. Phys. D: Appl. Phys.* **42** 165405
- [155] Clatot J, Campet G, Zeinert A, Labrugère C, Nistor M and Rougier A 2011 Low temperature Si doped ZnO thin films for transparent conducting oxides *Sol. Energy Mater. Sol. Cells* **95** 2357–62
- [156] Howard D, Marchand P, Carmalt C, Parkin I and Darr J 2017 Si-doped zinc oxide transparent conducting oxides; nanoparticle optimisation, scale-up and thin film deposition *J. Mater. Chem. C* **5** 8796–801
- [157] Deng S *et al* 2017 Hybrid-phase microstructural ITO-stabilized ZnO TFTs with self-aligned coplanar architecture *IEEE Electron Device Lett.* **38** 1676–9

### Chapter 3

- [1] Rossall A K, Berg J A V, Meehan D, Rajendiran S and Wagenaars E 2019 Analysis of plasma enhanced pulsed laser deposition of transition metal oxide thin films using medium energy ion scattering *Nucl. Instrum. Methods Phys. Res. B* **450** 274–8
- [2] Ohnishi T, Koinuma H and Lippmaa M 2006 Pulsed laser deposition of oxide thin films *Appl. Surf. Sci.* **252** 2466–71
- [3] Baig M K, Atiq S, Bashir S, Riaz S, Naseem S, Soleimani H and Yahya N 2016 Pulsed laser deposition of SMCO thin films for MEMS applications *J. Appl. Res. Technol.* **14** 287–92
- [4] Xia H, Tang S B and Lu L 2007 Thin film microbatteries prepared by pulsed laser deposition *J. Korean Phys. Soc.* **51** 1055–62
- [5] Kuwata N, Kumar, Toribami K, Suzuki T, Hattori T and Kawamura J 2006 Thin film lithium ion batteries prepared only by pulsed laser deposition *Solid State Ionics* **177** 2827–32
- [6] Xia H, Lu L and Ceder G 2006 Substrate effect on the microstructure and electrochemical properties of LiCoO<sub>2</sub> thin films grown by PLD *J. Alloys Compd.* **417** 304–10
- [7] Rajendiran S, Rossall A, Gibson A and Wagenaars E 2014 Modelling of laser ablation and reactive oxygen plasmas for pulsed laser deposition of zinc oxide *Surf. Coat. Technol.* **260** 417–23
- [8] Henning R A, Uredat P, Simon C, Bloesser A, Cop P, Elm M T and Marschall R 2019 Characterization of MFe<sub>2</sub>O<sub>4</sub> (M = Mg, Zn) thin films prepared by pulsed laser deposition for photo electrochemical applications *J. Phys. Chem. C* **123** 18240–7
- [9] Lethy K J, Beena D, Pillai V P M and Ganesan V 2008 Bandgap renormalization in titania modified nanostructured tungsten oxide thin films prepared by pulsed laser deposition technique for solar cell applications *J. Appl. Phys.* **104** 033515
- [10] Yan B, Liu J, Song B, Xiao P and Lu L 2013 Li-rich thin film cathode prepared by pulsed laser deposition *Sci. Rep.* **3** 3332

- [11] Kitai S, Maida O, Kanashima T and Okuyama M 2003 Preparation and characterization of high-k praseodymium and lanthanoid oxide thin films prepared by pulsed laser deposition *Jpn. J. Appl. Phys.* **42** 247–53
- [12] Guanjun Z, Rong C J, Rui C, Wen Y S and Yan M Z 2006 Preparation of BiFeO<sub>3</sub> thin films by pulsed laser deposition method *Trans. Nonferrous Met. Soc. China* **16** 123–5
- [13] Ohshima T, Thareja R K, Ikegami T and Ebihara K 2003 Preparation of ZnO thin films on various substrates by pulsed laser deposition *Surf. Coat. Technol.* **169** 517–20
- [14] Popescu C, Dorcioman G and Popescu A C 2016 *Laser Ablation Applied for Synthesis of Thin Films: Insights Into Laser Deposition Methods* (Rijeka: IntechOpen) (<https://doi.org/10.5772/65124>)
- [15] Ma C and Chen C 2016 Pulsed laser deposition for complex oxide thin film and nanostructure *Advanced Nano Deposition Methods* ed Y Lin and X Chen 1st edn (New York: Wiley)
- [16] Phuoc T X 2014 Complete green synthesis of gold nanoparticles using laser ablation in deionized water containing chitosan and starch *J. Mater. Sci. Nanotechnol.* **2** 1–7
- [17] Mkrtcheyev O V, Privalov V E, Fotiadi A E and Shemanin V G 2015 Laser ablation studies of nanocomposites *St. Petersburg Polytech. Univ. J. Phys. Math.* **1** 82–6
- [18] Yang G, Lin Q, Ding Y, Tian D and Duan Y 2015 Laser induced breakdown spectroscopy based on single beam splitting and geometric configuration for effective signal enhancement *Sci. Rep.* **5** 7625
- [19] Harris J J, Joyce B A and Dobson P J 1981 Oscillations in the surface structure of Sn-doped GaAs during growth by MBE *Surf. Sci.* **103** L90–6
- [20] Mahan J E, Geib K M, Robinson G Y and Long R G 1990 A review of the geometrical fundamentals of reflection high energy electron diffraction with application to silicon surfaces *J. Vac. Sci. Technol. A* **8** 3692–700
- [21] Horio Y, Hashimoto Y and Ichimiya A 1996 A new type of RHEED apparatus equipped with an energy filter *Appl. Surf. Sci.* **100** 292–6
- [22] Andrieu S and Avitaya F A 1991 Ga adsorption on Si (111) analyzed by RHEED and *in situ* ellipsometry *J. Cryst. Growth* **112** 146–52
- [23] Ichimiya A and Cohen P I 2004 *Reflection High-Energy Electron Diffraction* (Cambridge: Cambridge University Press)
- [24] Lu Z, Sun X, Xiang Y, Washington M, Wang G C and Lu T M 2017 Revealing the crystalline integrity of wafer-scale graphene on SiO<sub>2</sub>/Si: an azimuthal RHEED approach *ACS Appl. Mater. Interfaces* **9** 23081–91
- [25] Tang F, Parker T, Wang G C and Lu T M 2007 Surface texture evolution of polycrystalline and nanostructured films: RHEED surface pole figure analysis *J. Phys. D: Appl. Phys.* **40** R427–39
- [26] Schroeder J L, Ingason A S, Rosen J and Birch J 2015 Beware of poor-quality MgO substrates: a study of MgO substrate quality and its effect on thin film quality *J. Cryst. Growth* **420** 22–31
- [27] Casero R P, Roman R G S, Perriere J, Laurent A, Seiler W, Gergaud P and Keller D 1997 Epitaxial growth of CeO<sub>2</sub> on MgO by pulsed laser deposition *Appl. Surf. Sci.* **109** 341–4
- [28] Morin F J 1959 Oxides which show a metal-to-insulator transition at the Neel temperature *Phys. Rev. Lett.* **3** 34
- [29] Surnev S, Ramsey M G and Netzer F P 2003 Vanadium oxide surface studies *Prog. Surf. Sci.* **73** 117–65

- [30] Qazilbash M M *et al* 2007 Mott transition in VO<sub>2</sub> revealed by infrared spectroscopy and nano-imaging *Science* **318** 1750–3
- [31] Bian J, Miao L and Zhao S 2014 Structural and optical properties of VO<sub>2</sub> film grown on sapphire substrate by pulsed laser deposition *Adv. Mater. Res.* **912** 325–8
- [32] Mori H and Ishiwara H 1991 Epitaxial growth of SrTiO<sub>3</sub> films on Si(100) substrates using a focused electron beam evaporation method *Japan J. Appl. Phys.* **30** L1415
- [33] Moon B K and Ishiwara H 1994 Roles of buffer layers in epitaxial growth of SrTiO<sub>3</sub> films on silicon substrates *Japan J. Appl. Phys.* **33** 1472
- [34] Sanchez F, Aguiar R, Trtik V, Guerrero C, Ferrater C and Varela M 1998 Epitaxial growth of SrTiO<sub>3</sub> (00h), (0hh) and (hhh) thin films on buffered Si (001) *J. Mater. Res.* **13** 1422–5
- [35] Yamada T, Wakiya N, Shinozaki K and Mizutani N 2002 Growth mechanism of SrTiO<sub>3</sub> thin film on CeO<sub>2</sub>(001) surface *Key Eng. Mater.* **137** 228–9
- [36] Yamada T, Wakiya N, Shinozaki K and Mizutani N 2003 Epitaxial growth of SrTiO<sub>3</sub> films on CeO<sub>2</sub>/yttria-stabilized zirconia/Si (001) with TiO<sub>2</sub> atomic layer by pulsed-laser deposition *Appl. Phys. Lett.* **83** 4815–7
- [37] Yamashita K, Sakamaki Y, Sakamoto N, Shinozaki K, Suzuki H and Wakiya N 2011 Ferroelectricity of SrTiO<sub>3</sub> thin films prepared by dynamic-aurora pulsed laser deposition *Key Eng. Mater.* **485** 11–4
- [38] Chiu T W, Wakiya N, Shinozaki K and Mizutani N 2003 Growth of highly (001)-textured strontium barium niobate thin films on epitaxial LaNiO<sub>3</sub>/CeO<sub>2</sub>/YSZ/Si (100) *Thin Solid Films* **426** 62–7
- [39] Zhang Y L, Xie X S, Mo D, Pun E Y B and Shi L P 1996 Growth and photorefractive properties of Mn-doped (K<sub>1-x</sub>Na<sub>x</sub>)<sub>0.1</sub>(Sr<sub>0.6</sub>Ba<sub>0.4</sub>)<sub>0.9</sub>Nb<sub>2</sub>O<sub>6</sub> crystals *J. Appl. Phys.* **79** 8835–7
- [40] Chen C J, Xu Y, Xu R and Mackenzie J D 1991 Ferroelectric and pyroelectric properties of strontium barium niobate films prepared by the sol-gel method *J. Appl. Phys.* **69** 1763–5
- [41] Copetti C A, Soltner H, Schubert J, Zander W, Hollricher O, Buchal C, Schulz H, Tellmann N and Klein N 1993 High quality epitaxy of YBa<sub>2</sub>Cu<sub>3</sub>O<sub>7-x</sub> on silicon-on-sapphire with the multiple buffer layer YSZ/CeO<sub>2</sub> *Appl. Phys. Lett.* **63** 1429–31
- [42] Haakenaasen R, Fork D K and Colovchenko J A 1994 High quality crystalline YBa<sub>2</sub>Cu<sub>3</sub>O<sub>7-δ</sub> films on thin silicon substrates *Appl. Phys. Lett.* **64** 1573–5
- [43] Li Y, Linzen S, Seidel P, Machalet F, Schmidl F, Schneidewind H, Schmauder T, Cihar R and Schaller S 1995 Epitaxial growth of Yba<sub>2</sub>Cu<sub>3</sub>O<sub>7-delta</sub> thin films on CoSi<sub>2</sub>/Si substrates with combined CeO<sub>2</sub>/YSZ buffer layers *Inst. Phys. Conf. Ser.* **148** 911–4
- [44] Sanchez F, Ferrater C, Alcobe X, Bassas J and Garcia Cuenca M V 2001 Pulsed laser deposition of epitaxial LaNiO<sub>3</sub> thin films on buffered Si (100) *Thin Solid Films* **384** 200–5
- [45] Chiu T W, Wakiya N, Shinozaki K and Mizutani N 2002 Effects of ambient gas and film thickness on orientation and surface morphology of Sr<sub>0.5</sub>Ba<sub>0.5</sub>Nb<sub>2</sub>O<sub>6</sub> thin films prepared by pulsed laser deposition *J. Ceram. Soc. Jpn.* **110** 368–72
- [46] Chiu T W, Tonooka K and Kikuchi N 2010 Influence of oxygen pressure on the structural, electrical and optical properties of VO<sub>2</sub> thin films deposited on ZnO/glass substrates by pulsed laser deposition *Thin Solid Films* **518** 7441–4
- [47] Hood P J and DeNatale J F 1991 Millimeter-wave dielectric properties of epitaxial vanadium dioxide thin films *J. Appl. Phys.* **70** 376–81
- [48] Soltani M, Chaker M, Haddad E and Kruzelesky R V 2006 Thermochromic vanadium dioxide smart coatings grown on kapton substrates by reactive pulsed laser deposition *J. Vac. Sci. Technol. A* **24** 612–7

- [49] Jerominek H, Picard F and Vincent D 1993 Vanadium oxide films for optical switching and detection *Opt. Eng.* **32** 2092–100
- [50] Burkhardt W, Christmann T, Franke S, Kriegseis W, Meister D, Meyer B K, Niessner, Schalch D and Scharmann A 2002 Tungsten and fluorine co-doping of VO<sub>2</sub> films *Thin Solid Films* **402** 226–31
- [51] Kim D H and Kwok H S 1994 Pulsed laser deposition of VO<sub>2</sub> thin films *Appl. Phys. Lett.* **65** 3188–90
- [52] Nagashima K, Yanagida T, Tanaka H and Kawai T 2006 Influence of ambient atmosphere on metal-insulator transition of strained vanadium dioxide ultrathin films *J. Appl. Phys.* **100** 063714
- [53] Vasquez R A, Ewbank M D and Neugaonkar R R 1991 Photorefractive properties of doped strontium-barium niobate *Opt. Commun.* **80** 253–8
- [54] Zhang Y L, Xie X S, Mo D, Pun E Y B and Shi L P 1996 Growth and photorefractive properties of Mn-doped (KNa)<sub>0.1</sub>(Sr<sub>0.6</sub>Ba<sub>0.4</sub>)<sub>0.9</sub>Nb<sub>2</sub>O<sub>6</sub> crystals *J. Appl. Phys.* **79** 8835–7
- [55] Vre R D and Hesselink L 1994 Analysis of photorefractive stratified volume holographic optical elements *J. Opt. Soc. Am.* **11** 1800–8
- [56] Aronson L B and Hesselink L 1990 Photorefractive integrated-optical switch arrays in LiNbO<sub>3</sub> *Opt. Lett* **15** 30–2
- [57] Hesselink L and Bashaw M C 1993 Optical memories implemented with photorefractive media *Opt. Quantum Electron* **25** S611–61
- [58] Sakamoto S and Yazaki T 1973 Anomalous electro-optic properties of ferroelectric strontium barium niobate and their device applications *Appl. Phys. Lett.* **22** 429–31
- [59] Nystrom M J, Wessels B W, Lin W P, Wong G K, Neumayer D A and Marks T 1995 Nonlinear optical properties of textured strontium barium niobate thin films prepared by metalorganic chemical vapor deposition *J. Appl. Phys. Lett.* **66** 1726–8
- [60] Tanaka K, Nakagawa O, Nakano M, Shimuta T, Tabata H and Kawai T 1998 Epitaxial growth of (Sr, Ba) Nb<sub>2</sub>O<sub>6</sub> thin films by pulsed laser deposition *Japan J. Appl. Phys.* **37** 6142
- [61] Chiu T W, Wakiya N, Shinozaki K and Mizutani N 2002 Effects of ambient gas and surface morphology of Sr<sub>0.5</sub>Ba<sub>0.5</sub>Nb<sub>2</sub>O<sub>6</sub> thin films prepared by pulsed laser deposition *J. Ceram. Soc. Jpn.* **110** 368–72
- [62] Nakaiso T, Sugiyama H, Noda M and Okuyama M 2000 Low-temperature preparation of Sr<sub>2</sub>(Ta<sub>1-x</sub>Nb<sub>x</sub>)<sub>2</sub>O<sub>7</sub> thin films by pulsed laser deposition and its electrical properties *Japan J. Appl. Phys.* **39** 5517
- [63] Song Z, Lin C, Wang L, Huang J, Hesse D, Zakharov N D, Xu H and Okuyama M 2000 Microstructure and electrical properties of textured Sr<sub>0.51</sub>Ba<sub>0.48</sub>La<sub>0.01</sub>Nb<sub>2</sub>O<sub>6</sub> thin films *Appl. Phys. A* **70** 355–8
- [64] Li M, Chen X, Wang J, Yang J, Wu G and Zhao L 2000 Platinum silicide formation during pulsed laser annealing prepared by pulsed laser deposition *4th Int. Conf. Thin Film Phys. Appl.* vol 4086 (Shanghai, China) pp 823–6
- [65] Neimash V, Shepelyavyi P, Dovbeshko G, Goushcha A O, Isaiev M, Melnyk V, Didukh O and Kuzmich A 2016 Nanocrystals growth control during laser annealing of Sn:( $\alpha$ -Si) composites *J. Nanomater.* **8** 7920238
- [66] Chiu T W, Tonooka K and Kikuchi N 2008 Fabrication of ZnO and CuCrO<sub>2</sub>:Mg thin films by pulsed laser deposition with *in situ* laser annealing and its application to oxide diodes *Thin Solid Films* **516** 5941–7

- [67] Carey P G, Smith P M, Theiss S D and Wickboldt P 1999 Polysilicon thin film transistors fabricated on low temperature plastic substrates *J. Vac. Sci. Technol.* **17** 1946–9
- [68] Peng Y C, Fu G S, Yu W, Li S Q and Wang Y L 2004 Crystallization of amorphous Si films by pulsed laser annealing and their structural characteristics *Semicond. Sci. Technol.* **19** 759
- [69] Benko F A and Koffyberg F B 1986 Preparation and opto-electronic properties of semiconducting  $\text{CuCrO}_2$  *Mater. Res. Bull.* **21** 753–7
- [70] Nagarajan R, Draeseke A D, Sleight A W and Tate J 2001 p-Type conductivity in  $\text{CuCr}_{1-x}\text{Mg}_x\text{O}_2$  films and powders *J. Appl. Phys.* **89** 8022–5
- [71] Ozen I, Gulgün M A and Ozcan M 2004 Self-induced crystallinity in RF magnetron sputtered zno thin films *Key Eng. Mater.* **264** 1225–8
- [72] Zhang Y, Du G, Zhang B, Cui Y, Zhu H and Chang Y 2005 Properties of ZnO thin films grown on Si substrates by MOCVD and ZnO/Si heterojunctions *Semicond. Sci. Technol.* **20** 1132
- [73] Chiu T, Wakiya N, Shinozaki K and Mizutani N 2004 Effects of heating process on crystalline orientation and electrical properties of  $(\text{Bi,L a})_4\text{Ti}_3\text{O}_{12}$  thin films derived by chemical solution deposition method *Integr. Ferroelectr.* **62** 189–92
- [74] Tonooka K and Kikuchi N 2006 Preparation of transparent  $\text{CuCrO}_2\text{:Mg/ZnO}$  p–n junctions by pulsed laser deposition *Thin Solid Films* **515** 2415–8
- [75] Debnath N, Kawaguchi T, Kumasaka W, Das H, Shinozaki K, Sakamoto N, Suzuki H and Wakiya N 2017 As-grown enhancement of spinodal decomposition in spinel cobalt ferrite thin films by dynamic aurora pulsed laser deposition *J. Magn. Magn. Mater.* **432** 391–5
- [76] Dirnberger L, Dyer P E, Farrar S R and Key P H 1993 Proceeding of the second international conference on laser ablation *AIP Conf. Proc.* vol 288 (New York: AIP), 349
- [77] Wakiya N, Nagamune T, Shinozaki K and Mizutani N 2004 *In-situ* magnetic field induced structure and properties of epitaxial spinel ferrite thin films prepared by pulsed laser deposition (PLD) (dynamic aurora pld method) *Mater. Res. Soc. Symp. Proc.* **853** 14.34
- [78] Dirnberger L, Dyer P E, Farrar S R and Key P H 1994 Observation of magnetic-field-enhanced excitation and ionization in the plume of krf-laser-ablated magnesium *Appl. Phys. A* **59** 311–6
- [79] Lash J S, Gilgenbach R M and Ching C H 1994 Laser-ablation-assisted-plasma discharges of aluminum in a transverse-magnetic field *Appl. Phys. Lett.* **65** 531–3
- [80] Tachiki M and Kobayashi T 1999 Manipulation of laser ablation plume by magnetic field application *Japan J. Appl. Phys.* **38** 3642
- [81] Kobayashi T, Akiyoshi H and Tachiki M 2002 Development of prominent PLD (Aurora method) suitable for high-quality and low-temperature film growth *Appl. Surf. Sci.* **197** 294–303

## Chapter 4

- [1] Bia S, Lia Q, He Z, Guo Q, Yeboah K A-, Liu Y and Jiang C 2019 Highly enhanced performance of integrated piezo photo-transistor with dual inverted OLED gate and nanowire array channel *Nano Energy* **66** 104101
- [2] Chung K, Lee C-H and Yi G-C 2010 Transferable GaN layers grown on ZnO-coated graphene layers for optoelectronic devices *Science* **330** 655–7
- [3] Zhao W, Xiong X, Han Y, Wen L, Zou Z, Luo S, Li H, Su J, Zhai T and Gao Y 2017 Fe-doped p-ZnO nanostructures/n-GaN heterojunction for ‘Blue-Free’ orange light-emitting diodes *Adv. Opt. Mater.* **5** 1700146



- [4] Son D I, Kwon B W, Park D H, Seo W-S, Yi Y, Angadi B, Lee C-L and Choi W K 2012 Emissive ZnO-graphene quantum dots for white-light-emitting diodes *Nat. Nanotechnol.* **7** 465–71
- [5] Lee C-H, Kim Y-J, Hong Y J, Jeon S-R, Bae S, Hong B H and Yi G-C 2011 Flexible inorganic nanostructure light-emitting diodes fabricated on graphene films *Adv. Mater.* **23** 4614–9
- [6] Qian L, Zheng Y, Xue J and Holloway P H 2011 Stable and efficient quantum-dot light-emitting diodes based on solution-processed multilayer structures *Nat. Photon.* **5** 543–8
- [7] Shi Z-F, Zhang Y-T, Cui X-J, Zhuang S-W, Wu B, Chu X-W, Dong X, Zhang B-L and Du G-T 2015 Photoluminescence performance enhancement of ZnO/MgO heterostructured nanowires and their applications in ultraviolet laser diodes *Phys. Chem. Chem. Phys.* **17** 13813–20
- [8] Qin F F, Xu C X, Zhu Q X, Lu J F, Chen F, You D T, Zhua Z and Manohari A G 2018 Optical performance improvement in hydrothermal ZnO/graphene structures for ultraviolet lasing *J. Mater. Chem. C* **6** 3240–4
- [9] Wang C-S, Nieh C-H, Lin T-Y and Chen Y-F 2015 Electrically driven random laser memory *Adv. Funct. Mater.* **25** 4058–63
- [10] Fallert J, Dietz R J B, Sartor J, Schneider D, Klingshirn C and Kalt H 2009 Co-existence of strongly and weakly localized random laser modes *Nat. Photon.* **3** 279–82
- [11] Gargas D J, Moore M C, Ni A, Chang S-W, Zhang Z, Chuang S-L and Yang P 2010 Whispering gallery mode lasing from zinc oxide hexagonal nanodisks *ACS Nano* **4** 3270–6
- [12] Lu Y-J, Shan C-X, Jiang M-M, Hu G-C, Zhang N, Wang S-P, Li B-H and Shen D-Z 2015 Random lasing realized in n-ZnO/p-MgZnO core-shell nanowire heterostructures *CrystEngComm* **17** 3917–22
- [13] Chen R, Ling B, Sun X W and Sun H D 2011 Room temperature excitonic whispering gallery mode lasing from high-quality hexagonal ZnO microdisks *Adv. Mater.* **23** 2199–204
- [14] Huang M H, Mao S, Feick H, Yan H, Wu Y, Kind H, Weber E, Russo R and Yang P 2001 Room-temperature ultraviolet nanowire nanolasers *Science* **292** 1897–9
- [15] Huang J, Chu S, Kong J, Zhang L, Schwarz C M, Wang G, Chernyak L, Chen Z and Liu J 2013 ZnO p-n homojunction random laser diode based on nitrogen-doped p-type nanowires *Adv. Opt. Mater.* **1** 179–85
- [16] Bie Y-Q, Liao Z-M, Zhang H-Z, Li G-R, Ye Y, Zhou Y-B, Xu J, Qin Z-X, Dai L and Yu D-P 2011 Self-powered, ultrafast, visible-blind UV detection and optical logical operation based on ZnO/GaN nanoscale p-n junctions *Adv. Mater.* **23** 649–53
- [17] Huang B-R, Saravanan A and Lu H-C 2020 Structural engineering of dispersed graphene flakes into ZnO nanotubes on discontinues ultra-nanocrystalline diamond substrates for high-performance photodetector with excellent UV light to dark current ratios *Adv. Mater. Interfaces* **7** 1901694
- [18] Zhang Y, Hu M and Wang Z 2020 Enhanced performances of p-si/n-ZnO self-powered photodetector by interface state modification and pyro-phototronic effect *Nano Energy* **71** 104630
- [19] Zhang Z, Wang K, Zheng K, Deng S, Xu N and Chen J 2018 Electron bombardment induced photoconductivity and high gain in a flat panel photodetector based on a ZnS photoconductor and ZnO nanowire field emitters *ACS Photonics* **5** 4147–55
- [20] Lee D, Seol M-L, Motilal G, Kim B, Moon D-I, Han J-W and Meyyappan M 2020 All 3D-printed flexible ZnO UV photodetector on an ultraflat substrate *ACS Sens.* **5** 1028–32

- [21] Hu M, Teng F, Chen H, Jiang M, Gu Y, Lu H, Hu L and Fang X 2017 Novel  $\Omega$ -shaped core-shell photodetector with high ultraviolet selectivity and enhanced responsivity *Adv. Funct. Mater.* **27** 1704477
- [22] Nasiri N, Bo R, Wang F, Fu L and Tricoli A 2015 Ultraporous electron-depleted ZnO nanoparticle networks for highly sensitive portable visible-blind UV photodetectors *Adv. Mater.* **27** 4336–43
- [23] Ahn S, Chen W, M-Gonzalez M A, Lockett M, Wang J and Mena O V 2020 Enhanced charge transfer and responsivity in hybrid quantum dot/graphene photodetectors using ZnO as intermediate electron-collecting layer *Adv. Electron. Mater.* **6** 2000014
- [24] Lee Y T *et al* 2017 Mixed-dimensional 1D ZnO-2D WSe<sub>2</sub> van der Waals heterojunction device for photosensors *Adv. Funct. Mater.* **27** 1703822
- [25] Drobek M, Kim J-H, Bechelany M, Vallicari C, Julbe A and Kim S S 2016 MOF-based membrane encapsulated ZnO nanowires for enhanced gas sensor selectivity *ACS Appl. Mater. Interfaces* **8** 8323–28
- [26] Thongma S, Tantisantisom K, Grisdanurak N and Boonkoom T 2019 UV enhanced white-light response based on p-Si/n-ZnO nanorod heterojunction photosensor *Sens. Actuators A: Phys.* **296** 324–30
- [27] Kim Y, Kim J, Kim H-M and Jang J 2020 Quantum-dots photosensor with wide bandgap P-type and N-type oxide semiconductors for high detectivity and responsivity *Adv. Mater. Technol.* **5** 1900857
- [28] Tian H, Fan H, Li M and Ma L 2016 Zeolitic imidazolate framework coated ZnO nanorods as molecular sieving to improve selectivity of formaldehyde gas sensor *ACS Sens.* **1** 243–50
- [29] Dhamodharan P, Manoharan C, Bououdina M, Venkadachalapathy R and Ramalingam S 2017 Al-doped ZnO thin films grown onto ITO substrates as photoanode in dye sensitized solar cell *Sol. Energy* **141** 127–44
- [30] Qiao S, Liu J, Fu G, Ren K, Li Z, Wang S and Pan C 2018 ZnO nanowire based CIGS solar cell and its efficiency enhancement by the piezo-phototronic effect *Nano Energy* **49** 508–14
- [31] Chuang C-H M, Maurano A, Brandt R E, Hwang G W, Jean J, Buonassisi T, Bulovic V and Bawendi M G 2015 Open-circuit voltage deficit, radiative sub-bandgap states, and prospects in quantum dot solar cells *Nano Lett.* **15** 3286–94
- [32] Kim Y *et al* 2019 A facet-specific quantum dot passivation strategy for colloid management and efficient infrared photovoltaics *Adv. Mater.* **31** 1805580
- [33] Chuang C-H M, Brown P R, Bulović V and Bawendi M G 2014 Improved performance and stability in quantum dot solar cells through band alignment engineering *Nat. Mater.* **13** 796–801
- [34] Xu J *et al* 2018 2D matrix engineering for homogeneous quantum dot coupling in photovoltaic solids *Nat. Nanotechnol.* **13** 456–63
- [35] Eisner F *et al* 2018 Solution-processed In<sub>2</sub>O<sub>3</sub>/ZnO heterojunction electron transport layers for efficient organic bulk heterojunction and inorganic colloidal quantum-dot solar cells *Sol. RRL* **2** 1800076
- [36] Wang L *et al* 2018 Ultrathin piezotronic transistors with 2 nm channel lengths *ACS Nano* **12** 4903–08
- [37] Pan Z, Peng W, Li F and He Y 2018 Carrier concentration-dependent piezotronic and piezo-phototronic effects in ZnO thin-film transistor *Nano Energy* **49** 529–37

- [38] Yang X *et al* 2019 Coupled ion-gel channel-width gating and piezotronic interface gating in ZnO nanowire devices *Adv. Funct. Mater.* **29** 1807837
- [39] Keil P, Trapp M, Novak N, Frömling T, Kleebe H-J and Rödel J 2018 Piezotronic tuning of potential barriers in ZnO bicrystals *Adv. Mater.* **30** 1705573
- [40] Afouxenidis D, Halcovitch N R, Milne W I, Nathan A and Adamopoulos G 2020 Films stoichiometry effects on the electronic transport properties of solution-processed yttrium doped indium-zinc oxide crystalline semiconductors for thin film transistor applications *Adv. Electron. Mater.* **6** 1900976
- [41] Liu S, Wang L, Feng X, Wang Z, Xu Q, Bai S, Qin Y and Wang Z L 2017 Ultrasensitive 2D ZnO piezotronic transistor array for high resolution tactile imaging *Adv. Mater.* **29** 1606346
- [42] Zu P, Tang Z K, Wong G K L, Kawasaki M, Ohtomo A, Koinuma H and Segawa Y 1997 Ultraviolet spontaneous and stimulated emissions from ZnO microcrystallite thin films at room temperature *Solid State Commun.* **103** 459–63
- [43] R F Service 1997 Will UV lasers beat the blues? *Science* **276** 895
- [44] Tsukazaki A *et al* 2005 Repeated temperature modulation epitaxy for p-type doping and light-emitting diode based on ZnO *Nat. Mater.* **4** 42–6
- [45] Jiao S J, Zhang Z Z, Lu Y M, Shen D Z, Yao B, Zhang J Y, Li B H, Zhao D X, Fan X W and Tang Z K 2006 ZnO p-n junction light-emitting diodes fabricated on sapphire substrates *Appl. Phys. Lett.* **88** 031911
- [46] Chu S, Wang G, Zhou W, Lin Y, Chernyak L, Zhao J, Kong J, Li L, Ren J and Liu J 2011 Electrically pumped waveguide lasing from ZnO nanowires *Nat. Nanotechnol.* **6** 506–10
- [47] Xiao Z Y, Liu Y C, Mu R, Zhao D X and Zhang J Y 2008 Stability of p-type conductivity in nitrogen-doped ZnO thin film *Appl. Phys. Lett.* **92** 052106
- [48] Li X H, Xu H Y, Zhang X T, Liu Y C, Sun J W and Lu Y M 2009 Local chemical states and thermal stabilities of nitrogen dopants in ZnO film studied by temperature-dependent x-ray photoelectron spectroscopy *Appl. Phys. Lett.* **95** 191903
- [49] Alivov Y I, Nostrand J E V, Look D C, Chukichev M V and Ataev B M 2003 Observation of 430 nm electroluminescence from ZnO/GaN heterojunction light-emitting diodes *Appl. Phys. Lett.* **83** 2943–45
- [50] Fu H-K, Cheng C-L, Wang C-H, Lin T-Y and Chen Y-F 2009 Selective angle electroluminescence of light-emitting diodes based on nanostructured ZnO/GaN heterojunctions *Adv. Funct. Mater.* **19** 3471–75
- [51] Zhu H *et al* 2009 Ultralow-threshold laser realized in zinc oxide *Adv. Mater.* **21** 1613–17
- [52] Xu S *et al* 2010 Ordered nanowire array blue/near-UV light emitting diodes *Adv. Mater.* **22** 4749–53
- [53] Park W I and Yi G-C 2004 Electroluminescence in n-ZnO nanorod arrays vertically grown on p-GaN *Adv. Mater.* **16** 87–90
- [54] Zhang X-M, Lu M-Y, Zhang Y, Chen L-J and Wang Z L 2009 Fabrication of a high-brightness blue-light-emitting diode using a ZnO-nanowire array grown on p-GaN thin film *Adv. Mater.* **21** 2767–70
- [55] Shi Z *et al* 2013 High-performance ultraviolet-blue light-emitting diodes based on an n-ZnO nanowall networks/p-GaN heterojunction *Appl. Phys. Lett.* **103** 021109
- [56] Wang D, Wang F, Wang Y, Fan Y, Zhao B and Zhao D 2015 Interfacial emission adjustment in ZnO quantum dots/p-GaN heterojunction light-emitting diodes *J. Phys. Chem. C* **119** 2798–803

- [57] Tang X, Li G and Zhou S 2013 Ultraviolet electroluminescence of light-emitting diodes based on single n-ZnO/p-AlGaIn heterojunction nanowires *Nano Lett.* **13** 5046–50
- [58] Yang Z-P, Xie Z-H, Lin C-C and Lee Y-J 2015 Slanted n-ZnO nanorod arrays/p-GaN light-emitting diodes with strong ultraviolet emissions *Opt. Mater. Express* **5** 399–407
- [59] Zhu G Y, Xu C X, Lin Y, Shi Z L, Li J T, Ding T, Tian Z S and Chen G F 2012 Ultraviolet electroluminescence from horizontal ZnO microrods/GaN heterojunction light-emitting diode array *Appl. Phys. Lett.* **101** 041110
- [60] Fang X *et al* 2016 Ultraviolet electroluminescence from ZnS@ZnO core-shell nanowires/p-GaN introduced by exciton localization *ACS Appl. Mater. Interfaces* **8** 1661–6
- [61] Dai J, Xu C X and Sun X W 2011 ZnO-microrod/p-GaN heterostructured whispering-gallery-mode microlaser diodes *Adv. Mater.* **23** 4115–9
- [62] Jeong M-C, Oh B-Y, Ham M-H, Lee S-W and Myoung J-M 2007 ZnO-nanowire-inserted GaN/ZnO heterojunction light-emitting diodes *Small* **3** 568–72
- [63] Thomas B W and Walsh D 1973 Metal-insulator-semiconductor electroluminescent diodes in single crystal zinc oxide *Electron. Lett.* **9** 362–3
- [64] Minami T, Tanigawa M, Yamanishi M and Kawamura T 1974 Observation of ultraviolet luminescence from the ZnO MIS diodes *Japan J. Appl. Phys.* **13** 1475–6
- [65] Shimizu A, Kanbara M, Hada M and Kasuga M 1978 ZnO green light emitting diode *Jpn. J. Appl. Phys.* **17** 1435–6
- [66] Tang Z K, Wong G K L, Yu P, Kawasaki M, Ohtomo A, Koinuma H and Segawa Y 1998 Room-temperature ultraviolet laser emission from self-assembled ZnO microcrystallite thin films *Appl. Phys. Lett.* **72** 3270–2
- [67] Ya I, Alivov D C, Look B M, Ataev M V, Chukichev V V, Mamedov V I, Zinenko Y A and Agafonov A N 2004 Pustovit, fabrication of ZnO-based metal-insulator-semiconductor diodes by ion implantation *Solid-State Electron.* **48** 2343–6
- [68] Chen P, Ma X and Yang D 2006 Fairly pure ultraviolet electroluminescence from ZnO-based light-emitting devices *Appl. Phys. Lett.* **89** 111112
- [69] Ma X, Chen P, Li D, Zhang Y and Yang D 2007 Electrically pumped ZnO film ultraviolet random lasers on silicon substrate *Appl. Phys. Lett.* **91** 251109
- [70] Zhu H *et al* 2010 Low-threshold electrically pumped random lasers *Adv. Mater.* **22** 1877–81
- [71] Tian Y, Ma X, Jin L and Yang D 2010 Electrically pumped ultraviolet random lasing from ZnO films: compensation between optical gain and light scattering *Appl. Phys. Lett.* **97** 251115
- [72] Liu X-Y, Shan C-X, Wang S-P, Zhang Z-Z and Shen D-Z 2012 Electrically pumped random lasers fabricated from ZnO nanowire arrays *Nanoscale* **4** 2843–6
- [73] Li Y, Wang C, Jin L, Ma X and Yang D 2013 Electrically pumped random lasing in ZnO-based metal-insulator-semiconductor structured devices: effect of ZnO film thickness *J. Appl. Phys.* **113** 213103
- [74] Ni P-N, Shan C-X, Li B-H, Wang S-P and Shen D-Z 2014 Bias-polarity dependent ultraviolet/visible switchable light-emitting devices *ACS Appl. Mater. Interfaces* **6** 8257–62
- [75] Singh S 2016 Al doped ZnO based metal-semiconductor-metal and metal-insulator-semiconductor-insulator-metal UV sensors *Optik* **127** 3523–6
- [76] Yang X, Ni P-N, Jing P-T, Zhang L-G, Ma R-M, Shan C-X, Shen D-Z and Genevet P 2019 Room temperature electrically driven ultraviolet plasmonic lasers *Adv. Opt. Mater.* **7** 1801681

- [77] Han S, Zhang H, Lu Y, Xu W, Fang M, Liu W, Cao P and Zhu D 2020 Self-powered Au/MgZnO/nanolayered Ga-doped ZnO/In metal-insulator-semiconductor UV detector with high internal gain at deep UV light under low voltage *ACS Appl. Nano Mater.* **3** 120–30
- [78] Liu C Y, Xu H Y, Wang L, Li X H and Liu Y C 2009 Pulsed laser deposition of high Mg-content MgZnO films: effects of substrate temperature and oxygen pressure, *J. Appl. Phys.* **106** 073518
- [79] Liu W Z, Xu H Y, Wang L, Li X H and Liu Y C 2011 Size-controlled growth of ZnO nanowires by catalyst-free high-pressure pulsed laser deposition and their optical properties *AIP Adv.* **1** 022145
- [80] Liu W, Liang Y, Xu H, Wang L, Zhang X, Liu Y and Hark S 2010 Heteroepitaxial growth and spatially resolved cathodoluminescence of ZnO/MgZnO coaxial nanorod arrays *J. Phys. Chem. C* **114** 16148–52
- [81] Zhang C, Marvinney C E, Xu H Y, Liu W Z, Wang C L, Zhang L X, Wang J N, Ma J G and Liu Y C 2015 Enhanced waveguide-type ultraviolet electroluminescence from ZnO/MgZnO core/shell nanorod array light-emitting diodes via coupling with Ag nanoparticles localized surface plasmons *Nanoscale* **7** 1073–80
- [82] Zhang C, Zhu F, Xu H, Liu W, Yang L, Wang Z, Ma J, Kang Z and Liu Y 2017 Significant improvement of near-UV electroluminescence from ZnO quantum dot LEDs via coupling with carbon nanodot surface plasmons *Nanoscale* **9** 14592–601
- [83] Liu C, Xu H, Ma J and Liu Y 2013 Origin of ultraviolet electroluminescence in n-ZnO/p-GaN and n-MgZnO/p-GaN heterojunction light-emitting diodes *Phys. Status Solidi a* **210** 2751–5
- [84] Xu H Y, Liu Y C, Liu Y X, Xu C S, Shao C L and Mu R 2005 Ultraviolet electroluminescence from p-GaN/i-ZnO/n-ZnO heterojunction light-emitting diodes *Appl. Phys. B* **80** 871–4
- [85] Zhao L, Xu C S, Liu Y X, Shao C L, Li X H and Liu Y C 2008 A new approach to white light emitting diodes of p-GaN/i-ZnO/n-ZnO heterojunctions *Appl. Phys. B* **92** 185–8
- [86] Yang L, Liu W, Xu H, Ma J, Zhang C, Liu C, Wang Z and Liu Y 2017 Enhanced near-UV electroluminescence from p-GaN/i-Al<sub>2</sub>O<sub>3</sub>/n-ZnO heterojunction LEDs by optimizing the insulator thickness and introducing surface plasmons of Ag nanowires *J. Mater. Chem. C* **5** 3288–95
- [87] Yang L, Liu K, Xu H, Liu W, Ma J, Zhang C, Liu C, Wang Z, Yang G and Liu Y 2017 Enhanced electroluminescence from ZnO quantum dot light-emitting diodes via introducing Al<sub>2</sub>O<sub>3</sub> retarding layer and Ag@ZnO hybrid nanodots *Adv. Opt. Mater.* **5** 1700493
- [88] Liu W Z, Xu H Y, Ma J G, Liu C Y, Liu Y X and Liu Y C 2012 Effect of oxygen-related surface adsorption on the efficiency and stability of ZnO nanorod array ultraviolet light-emitting diodes, *Appl. Phys. Lett.* **100** 203101
- [89] Wang L, Xu H Y, Zhang C, Li X H, Liu Y C, Zhang X T, Tao Y, Huang Y and Chen D L 2012 MgZnO/MgO strained multiple-quantum-well nanocolumnar films: stress-induced structural transition and deep ultraviolet emission *J. Alloys Compd.* **513** 399–403
- [90] Wang L, Ma J, Xu H, Zhang C, Li X and Liu Y 2013 Anisotropic strained cubic MgZnO/MgO multiple-quantum-well nanorods: growths and optical properties, *Appl. Phys. Lett.* **102** 031905
- [91] Zhang S G, Zhang X W, Yin Z G, Wang J X, Dong J J, Gao H L, Si F T, Sun S S and Tao Y 2011 Localized surface plasmon-enhanced electroluminescence from ZnO-based heterojunction light-emitting diodes *Appl. Phys. Lett.* **99** 181116

- [92] Zhang S G, Zhang X W, Yin Z G, Wang J X, Si F T, Gao H L, Dong J J and Liu X 2012 Optimization of electroluminescence from n-ZnO/AlN/p-GaN light-emitting diodes by tailoring Ag localized surface plasmon *J. Appl. Phys.* **112** 013112
- [93] Liu W Z, Xu H Y, Zhang L X, Zhang C, Ma J G, Wang J N and Liu Y C 2012 Localized surface plasmon-enhanced ultraviolet electroluminescence from n-ZnO/i-ZnO/p-GaN heterojunction light-emitting diodes via optimizing the thickness of MgO spacer layer, *Appl. Phys. Lett.* **102** 142101
- [94] Yang L, Wang Y, Xu H, Liu W, Zhang C, Wang C, Wang Z, Ma J and Liu Y 2018 Color-tunable ZnO/GaN heterojunction LEDs achieved by coupling with Ag nanowire surface plasmons *ACS Appl. Mater. Interfaces* **10** 15812–9
- [95] Qiao Q, Shan C-X, Zheng J, Li B-H, Zhang Z-Z, Zhang L-G and Shen D-Z 2012 Localized surface plasmon enhanced light-emitting devices *J. Mater. Chem.* **22** 9481–4
- [96] Hwang S W *et al* 2010 Plasmon-enhanced ultraviolet photoluminescence from hybrid structures of graphene/ZnO films *Phys. Rev. Lett.* **105** 127403
- [97] Liu W Z, Xu H Y, Wang C L, Zhang L X, Zhang C, Sun S Y, Ma J G, Zhang X T, Wang J N and Liu Y C 2013 Enhanced ultraviolet emission and improved spatial distribution uniformity of ZnO nanorod array light-emitting diodes via Ag nanoparticles decoration *Nanoscale* **5** 8634–9
- [98] Liu W *et al* 2016 Effect of SiO<sub>2</sub> spacer-layer thickness on localized surface plasmon enhanced ZnO nanorod array LEDs *ACS Appl. Mater. Interfaces* **8** 1653–60
- [99] Zhang C, Qiu Y, Liu W, Xu H, Yang L, Wang C and Liu Y 2019 Improved near-UV electroluminescence of ZnO nanorod array LEDs by coupling with a graphene plasmon layer *Nanophotonics* **8** 2203–13
- [100] Wang Y, Yang L, Chen H, Liu C, Liu W, Xu H, Zhang C, Wang Z and Liu Y 2018 White LED based on CsPbBr<sub>3</sub> nanocrystal phosphors via a facile two-step solution synthesis route *Mater. Res. Bull.* **104** 48–52
- [101] Feng Q, Shi J, Yang W, Zhong W, Li Y, Chen H, Liu W, Xu H, Liu X and Liu Y 2019 Engineering fluorescence intensity and electron concentration of monolayer MoS<sub>2</sub> by forming heterostructures with semiconductor dots *Nanoscale* **11** 6544–51
- [102] Liu C Y, Xu H Y, Ma J G, Li X H, Zhang X T, Liu Y C and Mu R 2011 Electrically pumped near-ultraviolet lasing from ZnO/MgO core/shell nanowires, *Appl. Phys. Lett.* **99** 063115
- [103] Liu C Y, Xu H Y, Sun Y, Zhang C, Ma J G and Liu Y C 2014 Ultraviolet electroluminescence from Au/MgO/Mg<sub>x</sub>Zn<sub>1-x</sub>O heterojunction diodes and the observation of Zn-rich cluster emission *J. Lumin.* **148** 116–20
- [104] Liu C Y, Xu H Y, Sun Y, Ma J G and Liu Y C 2014 ZnO ultraviolet random laser diode on metal copper substrate *Opt. Express* **22** 16731–7
- [105] Zhang C, Zhang J, Liu W, Xu H, Hou S, Wang C, Yang L, Wang Z, Wang X and Liu Y 2016 Enhanced ultraviolet random lasing from Au/MgO/ZnO heterostructure by introducing p-Cu<sub>2</sub>O hole-injection layer *ACS Appl. Mater. Interfaces* **8** 31485–90
- [106] Ren C *et al* 2020 Highly robust flexible ferroelectric field effect transistors operable at high temperature with low-power consumption *Adv. Funct. Mater.* **30** 1906131
- [107] Guo N *et al* 2020 Light-driven WSe<sub>2</sub>-ZnO junction field-effect transistors for high-performance photodetection *Adv. Sci.* **7** 1901637

## Chapter 5

- [1] Thomas S R, Pattanasattayavong P and Anthopoulos T D 2013 Solution-processable metal oxide semiconductors for thin-film transistor applications *Chem. Soc. Rev.* **42** 6910–23
- [2] Petti L, Münzenrieder N, Vogt C, Faber H, Büthe L, Cantarella G, Bottacchi F, Anthopoulos T D and Tröster G 2016 Metal oxide semiconductor thin-film transistors for flexible electronics *Appl. Phys. Rev.* **3** 021303
- [3] Yeon Kwon J and Kyeong Jeong J 2015 Recent progress in high performance and reliable n-type transition metal oxide-based thin film transistors *Semicond. Sci. Technol.* **30** 024002
- [4] Labram J G, Lin Y-H and Anthopoulos T D 2015 Exploring two-dimensional transport phenomena in metal oxide heterointerfaces for next-generation, high-performance, thin-film transistor technologies *Small* **11** 5472–82
- [5] Li Y, Zhao C, Zhu D, Cao P, Han S, Lu Y, Fang M, Liu W and Xu W 2020 Recent advances of solution-processed heterojunction oxide thin-film transistors *Nanomaterials* **10** 965
- [6] Hong S, Park J W, Kim H J, Kim Y-g and Kim H J 2016 A review of multi-stacked active-layer structures for solution-processed oxide semiconductor thin-film transistors *J. Inf. Disp.* **17** 93–101
- [7] Tampo H *et al* 2008 Polarization-induced two-dimensional electron gases in ZnMgO/ZnO heterostructures *Appl. Phys. Lett.* **93** 202104
- [8] Yu X, Zhou N, Smith J, Lin H, Stallings K, Yu J, Marks T J and Facchetti A 2013 Synergistic approach to high-performance oxide thin film transistors using a bilayer channel architecture *ACS Appl. Mater. Interfaces* **5** 7983–8
- [9] Liu G X, Liu A, Shan F K, Meng Y, Shin B C, Fortunato E and Martins R 2014 High-performance fully amorphous bilayer metal-oxide thin film transistors using ultra-thin solution-processed  $ZrO_x$  dielectric *Appl. Phys. Lett.* **105** 113509
- [10] Kim C H, Rim Y S and Kim H J 2013 Chemical stability and electrical performance of dual-active-layered zinc-tin-oxide/indium-gallium-zinc-oxide thin-film transistors using a solution process *ACS Appl. Mater. Interfaces* **5** 6108–12
- [11] Kim C H, Rim Y S and Kim H J 2014 The effect of a zinc–tin-oxide layer used as an etch-stopper layer on the bias stress stability of solution-processed indium–gallium–zinc-oxide thin-film transistors *J. Phys. D: Appl. Phys.* **47** 385104
- [12] Lee S-H and Choi W-S 2015 Inkjet-printed oxide thin-film transistors using double-active layer structure *J. Disp. Technol.* **11** 698–702
- [13] Kim D J, Rim Y S and Kim H J 2013 Enhanced electrical properties of thin-film transistor with self-passivated multistacked active layers *ACS Appl. Mater. Interfaces* **5** 4190–4
- [14] Lin Y-H *et al* 2015 High electron mobility thin-film transistors based on solution-processed semiconducting metal oxide heterojunctions and quasi-superlattices *Adv. Sci.* **2** 1500058
- [15] Ahn C H, Senthil K, Cho H K and Lee S Y 2013 Artificial semiconductor/insulator superlattice channel structure for high-performance oxide thin-film transistors *Sci. Rep.* **3** 2737
- [16] Khim D, Lin Y-H and Anthopoulos T D 2019 Impact of layer configuration and doping on electron transport and bias stability in heterojunction and superlattice metal oxide transistors *Adv. Funct. Mater.* **29** 1902591
- [17] Park J C, Kim S, Kim S, Kim C, Song I, Park Y, Jung U-I, Kim D H and Lee J-S 2010 Highly stable transparent amorphous oxide semiconductor thin-film transistors having double-stacked active layers *Adv. Mater.* **22** 5512–6

- [18] Liu P-T, Chou Y-T, Teng L-F, Li F-H, Fuh C-S and Shieh H-P D 2011 Ambient stability enhancement of thin-film transistor with InGaZnO capped with InGaZnO:N bilayer stack channel layers *IEEE Electron Device Lett.* **32** 1397–9
- [19] Zhan R, Dong C, Liu P-T and Shieh H-P D 2013 Influence of channel layer and passivation layer on the stability of amorphous InGaZnO thin film transistors *Microelectron. Reliab.* **53** 1879–85
- [20] Cong Y *et al* 2016 High-performance Al–Sn–Zn–O thin-film transistor with a quasi-double-channel structure *IEEE Electron Device Lett.* **37** 53–6
- [21] Abliz A *et al* 2016 Boost up the electrical performance of InGaZnO thin film transistors by inserting an ultrathin InGaZnO:H layer *Appl. Phys. Lett.* **108** 213501
- [22] Ohtomo A and Hwang H Y 2004 A high-mobility electron gas at the LaAlO<sub>3</sub>–SrTiO<sub>3</sub> heterointerface *Nature* **427** 423–6
- [23] Tampo H, Matsubara K, Yamada A, Shibata H, Fons P, Yamagata M, Kanie H and Niki S 2007 High electron mobility Zn polar ZnMgO/ZnO heterostructures grown by molecular beam epitaxy *J. Cryst. Growth* **301–2** 358–61
- [24] He J *et al* 2019 Defect self-compensation for high-mobility bilayer InGaZnO/In<sub>2</sub>O<sub>3</sub> thin-film transistor *Adv. Electron. Mater.* **5** 1900125
- [25] Cho S W, Kim D E, Kim K S, Jung S H and Cho H K 2017 Towards environmentally stable solution-processed oxide thin-film transistors: a rare-metal-free oxide-based semiconductor/insulator heterostructure and chemically stable multi-stacking *J. Mater. Chem. C* **5** 10498–508
- [26] Oh H, Ko Park S-H, Hwang C-S, Yang S, Ki and Ryu M 2011 Enhanced bias illumination stability of oxide thin film transistor through insertion of ultrathin positive charge barrier into active material *Appl. Phys. Lett.* **99** 022105
- [27] Nayak P K, Wang Z, Anjum D H, Hedhili M N and Alshareef H N 2015 Highly stable thin film transistors using multilayer channel structure *Appl. Phys. Lett.* **106** 103505
- [28] Lee S Y, Kim J, Park A, Park J and Seo H 2017 Creation of a short-range ordered two-dimensional electron gas channel in Al<sub>2</sub>O<sub>3</sub>/In<sub>2</sub>O<sub>3</sub> interfaces *ACS Nano* **11** 6040–7
- [29] Drummond T J, Masselink W T and Morkoc H 1986 Modulation-doped GaAs/(Al, Ga)As heterojunction field-effect transistors: MODFETs *Proc. IEEE* **74** 773–822
- [30] Ambacher O *et al* 1999 Two-dimensional electron gases induced by spontaneous and piezoelectric polarization charges in N- and Ga-face AlGaIn/GaN heterostructures *J. Appl. Phys.* **85** 3222–33
- [31] Schlom D G and Pfeiffer L N 2010 Oxide electronics: upward mobility rocks! *Nat. Mater.* **9** 881–3
- [32] Eda Hiro T, Fujimura N and Ito T 2003 Formation of two-dimensional electron gas and the magnetotransport behavior of ZnMnO/ZnO heterostructure *J. Appl. Phys.* **93** 7673–5
- [33] Tsukazaki A, Ohtomo A, Kita T, Ohno Y, Ohno H and Kawasaki M 2007 Quantum hall effect in polar oxide heterostructures *Science* **315** 1388–91
- [34] Yano M, Hashimoto K, Fujimoto K, Koike K, Sasa S, Inoue M, Uetsuji Y, Ohnishi T and Inaba K 2007 Polarization-induced two-dimensional electron gas at Zn<sub>1-x</sub>Mg<sub>x</sub>O/ZnO heterointerface *J. Cryst. Growth* **301–2** 353–7
- [35] Koike K, Hama K, Nakashima I, Takada G-Y, Ozaki M, Ogata K-I, Sasa S, Inoue M and Yano M 2004 Piezoelectric carrier confinement by lattice mismatch at ZnO/Zn<sub>0.6</sub>Mg<sub>0.4</sub>O heterointerface *Japan J. Appl. Phys.* **43** L1372–5



- [36] Tampo H, Shibata H, Matsubara K, Yamada A, Fons P, Niki S, Yamagata M and Kanie H 2006 Two-dimensional electron gas in Zn polar ZnMgO/ZnO heterostructures grown by radical source molecular beam epitaxy *Appl. Phys. Lett.* **89** 132113
- [37] Nakano M, Tsukazaki A, Ohtomo A, Ueno K, Akasaka S, Yuji H, Nakahara K, Fukumura T and Kawasaki M 2010 Electric-field control of two-dimensional electrons in polymer-gated-oxide semiconductor heterostructures *Adv. Mater.* **22** 876–9
- [38] Falson J, Maryenko D, Kozuka Y, Tsukazaki A and Kawasaki M 2011 Magnesium doping controlled density and mobility of two-dimensional electron gas in  $\text{Mg}_x\text{Zn}_{1-x}\text{O}/\text{ZnO}$  heterostructures *Appl. Phys. Express* **4** 091101
- [39] Tsukazaki A, Akasaka S, Nakahara K, Ohno Y, Ohno H, Maryenko D, Ohtomo A and Kawasaki M 2010 Observation of the fractional quantum Hall effect in an oxide *Nat. Mater.* **9** 889–93
- [40] Koike K, Nakashima I, Hashimoto K, Sasa S, Inoue M and Yano M 2005 Characteristics of a  $\text{Zn}_{0.7}\text{Mg}_{0.3}\text{O}/\text{ZnO}$  heterostructure field-effect transistor grown on sapphire substrate by molecular-beam epitaxy *Appl. Phys. Lett.* **87** 112106
- [41] Sasa S, Ozaki M, Koike K, Yano M and Inoue M 2006 High-performance ZnO/ZnMgO field-effect transistors using a hetero-metal-insulator-semiconductor structure *Appl. Phys. Lett.* **89** 053502
- [42] Sasa S, Hayafuji T, Kawasaki M, Koike K, Yano M and Inoue M 2007 Improved stability of high-performance ZnO/ZnMgO hetero-MISFETs *IEEE Electron Device Lett.* **28** 543–5
- [43] Lee M, Jo J W, Kim Y J, Choi S, Kwon S M, Jeon S P, Facchetti A, Kim Y H and Park S K 2018 Corrugated heterojunction metal-oxide thin-film transistors with high electron mobility via vertical interface manipulation *Adv. Mater.* **30** e1804120
- [44] Yarali E *et al* 2020 Low-voltage heterojunction metal oxide transistors via rapid photonic processing *Adv. Electron. Mater.* **6** 2000028
- [45] Chin H-A, Cheng I C, Huang C-I, Wu Y-R, Lu W-S, Lee W-L, Chen J Z, Chiu K-C and Lin T-S 2010 Two dimensional electron gases in polycrystalline MgZnO/ZnO heterostructures grown by rf-sputtering process *J. Appl. Phys.* **108** 054503
- [46] Huang C-I, Chin H-A, Wu Y-R, Cheng I C, Chen J Z, Chiu K-C and Lin T-S 2010 Mobility enhancement of polycrystalline MgZnO/ZnO thin film layers with modulation doping and polarization effects *IEEE Trans. Electron Devices* **57** 696–703
- [47] Cheng I-C, Wang B-S, Hou H-H and Chen J-Z 2012 MgZnO/ZnO heterostructure field-effect transistors fabricated by RF-sputtering *ECTS Trans.* **50** 83–93
- [48] Remashan K, Choi Y S, Park S J and Jang J H 2010 High performance MOCVD-grown ZnO thin-film transistor with a thin MgZnO layer at channel/gate insulator interface *J. Electrochem. Soc.* **157** H1121
- [49] Taniguchi S, Yokozeki M, Ikeda M and Suzuki T-k 2011 Transparent oxide thin-film transistors using n- $(\text{In}_2\text{O}_3)_{0.9}(\text{SnO}_2)_{0.1}/\text{InGaZnO}_4$  modulation-doped heterostructures *Japan J. Appl. Phys.* **50** 04df11
- [50] Faber H *et al* 2017 Heterojunction oxide thin-film transistors with unprecedented electron mobility grown from solution *Sci. Adv.* **3** e1602640
- [51] Tetzner K, Isakov I, Regoutz A, Payne D J and Anthopoulos T D 2017 The impact of post-deposition annealing on the performance of solution-processed single layer  $\text{In}_2\text{O}_3$  and isotype  $\text{In}_2\text{O}_3/\text{ZnO}$  heterojunction transistors *J. Mater. Chem. C* **5** 59–64

- [52] Tetzner K, Lin Y-H, Regoutz A, Seitkhan A, Payne D J and Anthopoulos T D 2017 Sub-second photonic processing of solution-deposited single layer and heterojunction metal oxide thin-film transistors using a high-power xenon flash lamp *J. Mater. Chem. C* **5** 11724–32
- [53] Khim D, Lin Y-H, Nam S, Faber H, Tetzner K, Li R, Zhang Q, Zhang X and Anthopoulos T D 2017 Modulation-doped In<sub>2</sub>O<sub>3</sub>/ZnO heterojunction transistors processed from solution *Adv. Mater.* **29** 1605837
- [54] Lin Y-H *et al* 2019 Hybrid organic–metal oxide multilayer channel transistors with high operational stability *Nat. Electron.* **2** 587–95
- [55] Liu L, Chen S, Liang X and Pei Y 2019 Solution processed AlInO/In<sub>2</sub>O<sub>3</sub> heterostructure channel thin film transistor with enhanced performance *Adv. Electron. Mater.* **5** 1900550
- [56] Chen Y *et al* 2019 Polymer doping enables a two-dimensional electron gas for high-performance homojunction oxide thin-film transistors *Adv. Mater.* **31** e1805082
- [57] Rim Y S, Chen H, Kou X, Duan H S, Zhou H, Cai M, Kim H Y and Yang Y 2014 Boost up mobility of solution-processed metal oxide thin-film transistors via confining structure on electron pathways *Adv. Mater.* **26** 4273–8
- [58] Kim J-I *et al* 2011 Improvement in both mobility and bias stability of ZnSnO transistors by inserting ultra-thin InSnO layer at the gate insulator/channel interface *Appl. Phys. Lett.* **99** 122102
- [59] Chong E and Lee S Y 2012 Influence of a highly doped buried layer for HfInZnO thin-film transistors *Semicond. Sci. Technol.* **27** 012001
- [60] Kim H S *et al* 2012 Density of states-based design of metal oxide thin-film transistors for high mobility and superior photostability *ACS Appl. Mater. Interfaces* **4** 5416–21
- [61] Park J C and Lee H-N 2012 Improvement of the performance and stability of oxide semiconductor thin-film transistors using double-stacked active layers *IEEE Electron Device Lett.* **33** 818–20
- [62] Kim K M, Jeong W H, Kim D L, Rim Y S, Choi Y, Ryu M-K, Park K-B and Kim H J 2011 Low-temperature solution processing of AlInZnO/InZnO dual-channel thin-film transistors *IEEE Electron Device Lett.* **32** 1242–4
- [63] Jeong W H, Kim K M, Kim D L, Rim Y S and Kim H J 2012 The effects of dual-active-layer modulation on a low-temperature solution-processed oxide thin-film transistor *IEEE Trans. Electron Devices* **59** 2149–52
- [64] Nam S *et al* 2016 Solution-processed indium-free ZnO/SnO<sub>2</sub> bilayer heterostructures as a low-temperature route to high-performance metal oxide thin-film transistors with excellent stabilities *J. Mater. Chem. C* **4** 11298–304
- [65] Jung H Y, Kang Y, Hwang A Y, Lee C K, Han S, Kim D H, Bae J-U, Shin W-S and Jeong J K 2014 Origin of the improved mobility and photo-bias stability in a double-channel metal oxide transistor *Sci. Rep.* **4** 3765
- [66] Al-Jawhari H A, Caraveo-Frescas J A, Hedhili M N and Alshareef H N 2013 P-type Cu<sub>2</sub>O/SnO bilayer thin film transistors processed at low temperatures *ACS Appl. Mater. Interfaces* **5** 9615–9
- [67] Zeumault A and Subramanian V 2017 Use of high-k encapsulation to improve mobility in trap-limited metal-oxide semiconductors *Phys. Status Solidi b* **254** 1700124
- [68] Liang K *et al* 2019 High-performance metal-oxide thin-film transistors based on inkjet-printed self-confined bilayer heterojunction channels *J. Mater. Chem. C* **7** 6169–77
- [69] Sanctis S, Krausmann J, Guhl C and Schneider J J 2018 Stacked indium oxide/zinc oxide heterostructures as semiconductors in thin film transistor devices: a case study using atomic layer deposition *J. Mater. Chem. C* **6** 464–72

- [70] Lee S-J, Hwang C-S, Pi J-E, Yang J-H, Byun C-W, Chu H Y, Cho K-I and Cho S-H 2015 High performance amorphous multilayered ZnO-SnO<sub>2</sub> heterostructure thin-film transistors: fabrication and characteristics *ETRI J.* **37** 1135–42
- [71] Krausmann J, Sanctis S, Engstler J, Luysberg M, Bruns M and Schneider J J 2018 Charge transport in low-temperature processed thin-film transistors based on indium oxide/zinc oxide heterostructures *ACS Appl. Mater. Interfaces* **10** 20661–71
- [72] Kim S I, Kim C J, Song I, Kim S W, Yin H and Lee E *et al* 2008 High performance oxide thin film transistors with double active layers *2008 IEEE Int. Electron Dev. Meeting.* pp 1–4
- [73] Chong E, Jeon Y W, Chun Y S, Kim D H and Lee S Y 2011 Localization effect of a current-path in amorphous In–Ga–Zn–O thin film transistors with a highly doped buried-layer *Thin Solid Films* **519** 4347–50
- [74] Hsu H-H, Chang C-Y, Cheng C-H, Chiou S-H and Huang C-H 2014 High mobility bilayer metal–oxide thin film transistors using titanium-doped InGaZnO *IEEE Electron Device Lett.* **35** 87–9
- [75] Lee W, Kim J and Kim Y-H 2017 High-performance InO<sub>x</sub>/GaO<sub>x</sub> bilayer channel thin-film transistors made using persistent high-surface-energy induced by photochemical activation *J. Alloys Compd.* **723** 627–32.
- [76] Lee H, Zhang X, Kim J W, Kim E J and Park J 2018 Investigation of the electrical characteristics of bilayer ZnO/In<sub>2</sub>O<sub>3</sub> thin-film transistors fabricated by solution processing *Materials* **11** 2103
- [77] Lee J-M, Lee H-J, Pi J-E, Yang J-H, Lee J H, Ahn S-D, Kang S-Y and Moon J 2019 All-oxide thin-film transistors with channels of mixed InO<sub>x</sub>-ZnO<sub>y</sub> formed by plasma-enhanced atomic layer deposition process *J. Vac. Sci. Technol. A* **37** 060910
- [78] Sheng J, Hong T, Lee H M, Kim K, Sasase M, Kim J, Hosono H and Park J-S 2019 Amorphous IGZO TFT with high mobility of ~ 70 cm<sup>2</sup>/(V s) via vertical dimension control using pEALD *ACS Appl. Mater. Interfaces* **11** 40300–9
- [79] Chin H A, Cheng I C, Li C K, Wu Y R, Chen J Z, Lu W S and Lee W-L 2011 Electrical properties of modulation-doped rf-sputtered polycrystalline MgZnO/ZnO heterostructures *J. Phys. D: Appl. Phys.* **44** 455101
- [80] Kim K T, Kim J, Kim Y-H and Park S K 2014 In-situ metallic oxide capping for high mobility solution-processed metal-oxide TFTs *IEEE Electron Device Lett.* **35** 850–2
- [81] Cohen D J and Barnett S A 2005 Predicted electrical properties of modulation-doped ZnO-based transparent conducting oxides *J. Appl. Phys.* **98** 053705
- [82] Kim M G, Kanatzidis M G, Facchetti A and Marks T J 2011 Low-temperature fabrication of high-performance metal oxide thin-film electronics via combustion processing *Nat. Mater.* **10** 382–8
- [83] Lin Y-H, Faber H, Zhao K, Wang Q, Amassian A, McLachlan M and Anthopoulos T D 2013 High-performance ZnO transistors processed via an aqueous carbon-free metal oxide precursor route at temperatures between 80-180 °C *Adv. Mater.* **25** 4340–6

## Chapter 6

- [1] Fiori G, Bonaccorso F, Iannaccone G, Palacios T, Neumaier D, Seabaugh A, Banerjee S and Colombo L 2014 Electronics based on two-dimensional materials *Nat. Nanotechnol.* **9** 768–79
- [2] Li Y, Yang X-Y, Feng Y, Yuan Z-Y and Su B-L 2012 One-dimensional metal oxide nanotubes, nanowires, nanoribbons, and nanorods: synthesis, characterizations, properties and applications *Crit. Rev. Solid State Mater. Sci.* **37** 1–74

- [3] Devan R, Patil R, Lin J H and Ma Y-R 2012 One-dimensional metal-oxide nanostructures: recent developments in synthesis, characterization, and applications *Adv. Funct. Mater.* **22** 3326–70
- [4] Comini E, Baratto C, Faglia G, Ferroni M, Vomiero A and Sberveglieri G 2009 Quasi-one dimensional metal oxide semiconductors: preparation, characterization and application as chemical sensors *Prog. Mater. Sci.* **54** 1–67
- [5] Zhang H, Song L, Luo L, Liu L, Wang H and Wang F 2017 TiO<sub>2</sub>/Sb<sub>2</sub>S<sub>3</sub>/P3HT based inorganic–organic hybrid heterojunction solar cells with enhanced photoelectric conversion performance *J. Electron. Mater.* **46** 4670–5
- [6] Wang F, Zhang H, Liu L, Shin B and Shan F 2016 Synthesis, surface properties and optical characteristics of CuV<sub>2</sub>O<sub>6</sub> nanofibers *J. Alloys Compd.* **672** 229–37
- [7] Wang F, Zhang H, Liu L, Shin B and Shan F 2016 AgV<sub>7</sub>O<sub>18</sub>: a new silver vanadate semiconductor with photodegradation ability on dyes under visible-light irradiation *Mater. Lett.* **169** 82–5
- [8] Wang F, Song L, Zhang H, Luo L, Wang D and Tang J 2017 One-dimensional metal-oxide nanostructures for solar photocatalytic water-splitting *J. Electron. Mater.* **46** 4716–24
- [9] Yin H, Zhao Y L, Hua Q, Zhang J, Zhang Y, Xu X, Long Y, Tang J and Wang F 2019 Controlled synthesis of hollow  $\alpha$ -Fe<sub>2</sub>O<sub>3</sub> microspheres assembled with ionic liquid for enhanced visible-light photocatalytic activity *Front. Chem.* **7** 58
- [10] Luo L, Zhang H, Song L, Liu L, Yi X, Tan M, Song J, Wang G and Wang F 2018 Phase transition induced synthesis of one dimensional In<sub>1-x</sub>Zn<sub>x</sub>O<sub>y</sub> heterogeneous nanofibers for superior lithium ion storage *Appl. Surf. Sci.* **470** 340–7
- [11] Tong W, Wang Y, Bian Y, Wang A, Han N and Chen Y 2020 Sensitive cross-linked SnO<sub>2</sub>:NiO networks for MEMS compatible ethanol gas sensors *Nanoscale Res. Lett.* **15** 35
- [12] Wang Y, Liu C, Wang Z, Song Z, Zhou X, Han N and Chen Y 2019 Sputtered SnO<sub>2</sub>:NiO thin films on self-assembled Au nanoparticle arrays for MEMS compatible NO<sub>2</sub> gas sensors *Sensors Actuators B* **278** 28–38
- [13] Zhu X, Li Y, Zhang H, Song L, Zu H, Qin Y, Liu L, Li Y and Wang F 2020 High-performance field effect transistors based on large ratio metal (Al, Ga, Cr) doped In<sub>2</sub>O<sub>3</sub> nanofibers *J. Alloys Compd.* **830** 154578
- [14] Han N, Yang Z, Shen L, Lin H, Wang Y, Pun E Y B, Chen Y and Ho J C 2016 Design and fabrication of 1-D semiconductor nanomaterials for high-performance photovoltaics *Sci. Bull.* **61** 357–67
- [15] Huang H, Liang B, Liu Z, Wang X, Chen D and Shen G 2012 Metal oxide nanowire transistors *J. Mater. Chem.* **22** 13428–45
- [16] Li R, Chen S, Lou Z, Li L, Huang T, Song Y, Chen D and Shen G 2017 Fabrication of porous SnO<sub>2</sub> nanowires gas sensors with enhanced sensitivity *Sensors Actuators B* **252** 79–85
- [17] Chen S, Lou Z, Chen D, Chen Z, Jiang K and Shen G 2016 Highly flexible strain sensor based on ZnO nanowires and P(VDF-TrFE) fibers for wearable electronic device *Sci. China Mater.* **59** 173–81
- [18] Liu D, Li H, Song L, Zhu X, Qin Y, Zu H, He J, Yang Z and Wang F 2020 Modulating electrical and photoelectrical properties of one-step electrospun one-dimensional SnO<sub>2</sub> arrays *Nanotechnology* **31** 335202
- [19] McAlpine M C, Ahmad H, Wang D and Heath J R 2007 Highly ordered nanowire arrays on plastic substrates for ultrasensitive flexible chemical sensors *Nat. Mater.* **6** 379–84

- [20] Li Y, Qian F, Xiang J and Lieber C 2006 Nanowire electronic and optoelectronic devices *Mater. Today* **1** 18–27
- [21] Seoane N, Loureiro A G and Kalna K 2020 Special issue: nanowire field-effect transistor (FET) *Materials* **13** 1845
- [22] Jia C, Lin Z, Huang Y and Duan X 2019 Nanowire electronics: from nanoscale to macroscale *Chem. Rev.* **119** 9074–135
- [23] Dasgupta N, Sun J, Liu C, Brittman S, Andrews S C, Lim J, Gao H, Yan R and Yang P 2014 Semiconductor nanowires-synthesis, characterization, and applications *Adv. Mater.* **26** 2137–84
- [24] Jia X, Zhu X, Tian W, Ding Y, Tian X, Cheng B, Cheng L, Bai S and Qin Y 2020 Nanowire templated CVD synthesis and morphological control of MoS<sub>2</sub> nanotubes *J. Mater. Chem. C* **8** 4133–8
- [25] Lee Y-H *et al* 2012 Synthesis of large-area MoS<sub>2</sub> atomic layers with chemical vapor deposition *Adv. Mater.* **24** 2320–5
- [26] Wu J J and Liu S C 2002 Low-temperature growth of well-aligned ZnO nanorods by chemical vapor deposition *Adv. Mater.* **14** 215–8
- [27] Li Y L, Kinloch I A and Windle A H 2004 Direct spinning of carbon nanotube fibers from chemical vapor deposition synthesis *Science* **304** 276–8
- [28] Chhowalla M, Teo K B K, Ducati C, Rupesinghe N L, Amaratunga G A J, Ferrari A C, Roy D, Robertson J and Milne W I 2001 Growth process conditions of vertically aligned carbon nanotubes using plasma enhanced chemical vapor deposition *J. Appl. Phys.* **90** 5308–17
- [29] Zhang H, Meng Y, Song L, Luo L, Qin Y, Han N, Yang Z, Liu L, Ho J C and Wang F 2018 High-performance enhancement-mode thin-film transistors based on Mg-doped In<sub>2</sub>O<sub>3</sub> nanofiber networks *Nano Res.* **11** 1227–37
- [30] Song L, Luo L, Li X, Liu D, Han N, Liu L, Qin Y, Ho J C and Wang F 2019 Modulating electrical performances of In<sub>2</sub>O<sub>3</sub> nanofiber channel thin film transistors via Sr doping *Adv. Electron. Mater.* **5** 1800707
- [31] Wang F *et al* 2018 ZnO nanofiber thin-film transistors with low-operating voltages *Adv. Electron. Mater.* **4** 1700336
- [32] Yang X, Zu H, Luo L, Zhang H, Li J, Yi X, Liu H, Wang F and Song J 2020 Synergistic tungsten oxide/N, S co-doped carbon nanofibers interlayer as anchor of polysulfides for high-performance lithium-sulfur batteries *J. Alloys Compd.* **833** 154969
- [33] Subbiah T, Bhat G S, Tock R W, Parameswaran S and Ramkumar S S 2005 Electrospinning of nanofibers *J. Appl. Polym. Sci.* **96** 557–69
- [34] Frenot A and Chronakis I S 2003 Polymer nanofibers assembled by electrospinning *Curr. Opin. Colloid Interface Sci.* **8** 64–75
- [35] Demir M M, Yilgor I, Yilgor E and Erman B 2002 Electrospinning of polyurethane fibers *Polymer* **43** 3303–9
- [36] Bhardwaj N and Kundu S C 2010 Electrospinning: a fascinating fiber fabrication technique *Biotechnol. Adv.* **28** 325–47
- [37] Matthews J A, Gary E W, Simpson D G and Bowlin G L 2002 Electrospinning of collagen nanofibers *Biomacromolecules* **3** 232–8
- [38] Reneker D H and Yarin A L 2008 Electrospinning jets and polymer nanofibers *Polymer* **49** 2387–425
- [39] Li D and Xia Y 2003 Fabrication of titania nanofibers by electrospinning *Nano Lett.* **3** 555–60

- [40] Agarwal S, Joachim H W and Greiner A 2008 Use of electrospinning technique for biomedical applications *Polymer* **49** 5603–21
- [41] Fridrikh S V, Jian H Y, Brenner M P and Rutledge G C 2003 Controlling the fiber diameter during electrospinning *Phys. Rev. Lett.* **90** 144502
- [42] Fortunato E, Barquinha P and Martins R 2012 Oxide semiconductor thin-film transistors: a review of recent advances *Adv. Mater.* **24** 2945–86
- [43] Hoffman R L, Norris B J and Wager J F 2003 ZnO-based transparent thin-film transistors *Appl. Phys. Lett.* **82** 733–5
- [44] Carcia P F, McLean R S, Reilly M H and Nunes G 2003 Transparent ZnO thin-film transistor fabricated by rf magnetron sputtering *Appl. Phys. Lett.* **82** 1117–9
- [45] Ionescu A M and Riel H 2011 Tunnel field-effect transistors as energy-efficient electronic switches *Nature* **479** 329–37
- [46] Arnold M S, Avouris P, Pan Z W and Wang Z L 2003 Field-effect transistors based on single semiconducting oxide nanobelts *J. Phys. Chem. B* **107** 659–63
- [47] Heo Y W, Norton D P, Tien L C, Kwon Y, Kang B S, Ren F, Pearton S J and LaRoche J R 2004 ZnO nanowire growth and devices *Mater. Sci. Eng. R* **47** 1–47
- [48] Morisot F, Nguyen V H, Montemont C, Maindron T, Muñoz-Rojas D, Mouis M, Langlet M and Ternon C 2019 Al<sub>2</sub>O<sub>3</sub>, Al doped ZnO and SnO<sub>2</sub> encapsulation of randomly oriented ZnO nanowire networks for high performance and stable electrical devices *Nanotechnology* **30** 385202
- [49] Ditshego N M J and Sultan S M 2019 3D simulation investigating ZnO NWFET characteristics *J. Nano Res.* **58** 40–8
- [50] Ditshego N M J and Sultan S M 2019 Top-down fabrication process of ZnO NWFETs *J. Nano Res.* **57** 77–92
- [51] Chang H, Lee D H, Kim H S, Park J and Lee B Y 2018 Facile fabrication of self-assembled ZnO nanowire network channels and its gate-controlled UV detection *Nanoscale Res. Lett.* **13** 413
- [52] Chakraborty A, Pizzoferrato R, Agresti A, Matteis F D, Orsini A and Medaglia P G 2018 Wet-chemical synthesis of ZnO nanowires on low-temperature photo-activated ZnO-rGO composite thin film with enhanced photoconduction *J. Electron. Mater.* **47** 5863–9
- [53] Zheng X, Sun Y, Yan X, Chen X, Bai Z, Lin P, Shen Y, Zhao Y and Zhang Y 2014 Tunable channel width of a UV-gate field effect transistor based on ZnO micro-nano wire *RSC Adv.* **4** 18378–81
- [54] Willander M *et al* 2009 Zinc oxide nanorod based photonic devices: recent progress in growth, light emitting diodes and lasers *Nanotechnology* **20** 332001
- [55] Zhang Z, Wang K, Zheng K, Deng S, Xu N and Chen J 2018 Electron bombardment induced photoconductivity and high gain in a flat panel photodetector based on a ZnS photoconductor and ZnO nanowire field emitters *ACS Photonics* **5** 4147–55
- [56] Zhang D, Liu Z, Li C, Tang T, Liu X, Han S, Lei B and Zhou C 2004 Detection of NO<sub>2</sub> down to ppb levels using individual and multiple In<sub>2</sub>O<sub>3</sub> nanowire devices *Nano Lett.* **4** 1919–24
- [57] Xu Q, Liu X, Wan B, Yang Z, Li F, Lu J, Hu G, Pan C and Wang Z L 2018 In<sub>2</sub>O<sub>3</sub> nanowire field-effect transistors with Sub-60 mV/dec subthreshold swing stemming from negative capacitance and their logic applications *ACS Nano* **12** 9608–16
- [58] Park H, Yoon K R, Kim S K, Kim I-D, Jin J, Kim Y H and Bae B-S 2016 Highly conducting In<sub>2</sub>O<sub>3</sub> nanowire network with passivating ZrO<sub>2</sub> thin film for solution-processed field effect transistors *Adv. Electron. Mater.* **2** 1600218

- [59] Yan J, Chen Y, Wang X, Fu Y, Wang J, Sun J, Dai G, Tao S and Gao Y 2019 High-performance solar-blind SnO<sub>2</sub> nanowire photodetectors assembled using optical tweezers *Nanoscale* **11** 2162–9
- [60] Liu H and Wan Q 2012 Low-voltage SnO<sub>2</sub> nanowire transistors gated by solution-processed chitosan-based proton conductors *Nanoscale* **4** 4481–4
- [61] Wang X, Aroonyadet N, Zhang Y, Mecklenburg M, Fang X, Chen H, Goo E and Zhou C 2014 Aligned epitaxial SnO<sub>2</sub> nanowires on sapphire: growth and device applications *Nano Lett.* **14** 3014–22
- [62] Sporea R A, Kham M N, Flewitt A J, Ravi S and Silva P 2019 Novel tunnel-contact-controlled IGZO thin-film transistors with high tolerance to geometrical variability *Adv. Mater.* **31** 1902551
- [63] Li F, Yip S P, Dong R, Zhou Z, Lan C, Liang X, Li D, Meng Y, Kang X and Ho J C 2019 Crystalline InGaZnO quaternary nanowires with superlattice structure for high-performance thin-film transistors *Nano Res.* **12** 1796–803
- [64] Hou L, Zhang C, Li L, Du C, Li X, Kang X-F and Chen W 2018 CO gas sensors based on p-type CuO nanotubes and CuO nanocubes: morphology and surface structure effects on the sensing performance *Talanta* **188** 41–9
- [65] Zhu H, Liu A, Liu G and Shan F 2017 Electrospun p-type CuO nanofibers for low-voltage field-effect transistors *Appl. Phys. Lett.* **111** 143501
- [66] Talapin D and Murray C 2005 PbSe nanocrystal solids for n- and p-channel thin film field-effect transistors *Science* **310** 86–9
- [67] Matsubara K, Huang S, Iwamoto M and Pan W 2014 Enhanced conductivity and gating effect of p-type Li-doped NiO nanowires *Nanoscale* **6** 688–92
- [68] Georgiou T *et al* 2013 Vertical field-effect transistor based on graphene–WS<sub>2</sub> heterostructures for flexible and transparent electronics *Nat. Nanotechnol.* **8** 100–3
- [69] Sanghyun J, Facchetti A, Xuan Y, Liu J, Ishikawa F, Ye P, Zhou C, Marks T J and Janes D B 2007 Fabrication of fully transparent nanowire transistors for transparent and flexible electronics *Nat. Nanotechnol.* **2** 378–84
- [70] Kolmakov A and Moskovits M 2004 Chemical sensing and catalysis by one-dimensional metal-oxide nanostructures *Annu. Rev. Mater. Res.* **34** 151–80
- [71] Singh N, Yan C and Lee P S 2010 Room temperature CO gas sensing using Zn-doped In<sub>2</sub>O<sub>3</sub> single nanowire field effect transistors *Sensors Actuators B* **150** 19–24
- [72] Huang T, Lou Z, Chen S, Li R, Jiang K, Chen D and Shen G 2017 Fabrication of rigid and flexible SrGe<sub>4</sub>O<sub>9</sub> nanotube-based sensors for room-temperature ammonia detection *Nano Res.* **11** 431–9
- [73] Yu X, Marks T and Facchetti A 2016 Metal oxides for optoelectronic applications *Nat. Mater.* **15** 383–96
- [74] Li F *et al* 2019 High-performance transparent ultraviolet photodetectors based on InGaZnO superlattice nanowire arrays *ACS Nano* **13** 12042–51
- [75] Chen Y, Qiu W, Wang X, Liu W, Wang J, Dai G, Yuan Y, Gao Y and Sun J 2019 Solar-blind SnO<sub>2</sub> nanowire photo-synapses for associative learning and coincidence detection *Nano Energy* **62** 393–400
- [76] Chen H *et al* 2019 Time-tailoring van der Waals heterostructures for human memory system programming *Adv. Sci.* **6** 1901072
- [77] Vu C-A and Chen W-Y 2019 Field-effect transistor biosensors for biomedical applications: recent advances and future prospects *Sensors* **19** 4214

- [78] Gou G, Sun J, Qian C, He Y, Kong L-A, Fu Y, Dai G, Yang J and Gao Y 2016 Artificial synapses based on biopolymer electrolyte-coupled SnO<sub>2</sub> nanowire transistors *J. Mater. Chem. C* **4** 11110–7

## Chapter 7

- [1] Tsujimura T 2012 *OLED Display Fundamentals and Applications* (New York: Wiley), p 106
- [2] Park J-S 2015 *AOS TFTs for AMOLED TV Handbook of Visual Display Technology* (Berlin: Springer) pp 1–19
- [3] Xia Z, Liu X, Shi R, Li J, Lu L, Kwok H-S and Wong M 2020 A timing model for the optimal design of a prototype active-matrix display *IEEE Trans. Electron Devices* **67** 3167–74
- [4] Kamiya T, Nomura K and Hosono H 2010 Present status of amorphous In–Ga–Zn–O thin-film transistors *Sci. Technol. Adv. Mater.* **11117** 44305–23
- [5] Shanks H, Fang C J, Ley L, Cardona M, Demond F J and Kalbitzer S 1980 Infrared spectrum and structure of hydrogenated amorphous silicon *Phys. Status Solidi* **100** 43–56
- [6] Stutzmann M, Biegelsen D K and Street R A 1987 Detailed investigation of doping in hydrogenated amorphous silicon and germanium *Phys. Rev. B* **35** 5666–701
- [7] Souk J, Morozumi S, Chen F and Bitá I 2018 *Flat Panel Display Manufacturing* (New York: Wiley)
- [8] Chen J, Cranton W and Fihn M 2012 *Handbook of Visual Display Technology* (Cham: Springer)
- [9] Klazes R H, Van Den Broek M H, Bezemer J and Radelaarj S 1982 Determination of the optical bandgap of amorphous silicon *Philos. Mag. B* **45** 377–83
- [10] Street R A 2005 *Hydrogenated Amorphous Silicon* (Cambridge: Cambridge University Press)
- [11] Joubert P 1987 The effect of low pressure on the structure of LPCVD polycrystalline silicon films *J. Electrochem. Soc.* **134** 2541
- [12] Bo X-Z, Yao N, Shieh S R, Duffy T S and Sturm J C 2002 Large-grain polycrystalline silicon films with low intragranular defect density by low-temperature solid-phase crystallization without underlying oxide *J. Appl. Phys.* **91** 2910–5
- [13] Qi G J, Zhang S, Tang T T, Li J F, Sun X W and Zeng X T 2005 Experimental study of aluminum-induced crystallization of amorphous silicon thin films *Surf. Coat. Technol.* **198** 300–3
- [14] Wu G M, Chen C N, Feng W S and Lu H C 2009 Improved AMOLED with aligned poly-Si thin-film transistors by laser annealing and chemical solution treatments *Physica B* **404** 4649–52
- [15] Kim C W, Jung J G, Choi J B, Kim D H, Yi C, Kim H D, Choi Y H and Im J 2011 59.1: invited paper: LTPS backplane technologies for AMLCDs and AMOLEDs *SID Symp. Dig. Tech. Pap.* **42** 862–5
- [16] Rath J 2003 Low temperature polycrystalline silicon: a review on deposition, physical properties and solar cell applications *Sol. Energy Mater. Sol. Cells* **76** 431–87
- [17] Moon K C, Lee J H and Han M K 2005 The study of hot-carrier stress on poly-Si TFT employing C-V measurement *IEEE Trans. Electron Devices* **52** 512–7
- [18] Matsuo T, Mori S, Ban A and Imaya A 2014 8.3: invited paper: advantages of IGZO oxide semiconductor *SID Symp. Dig. Tech. Pap.* **45** 83–6



- [19] Tanaka T, Horie H, Ando S and Hijiya S 1991 Analysis of p/sup +/- poly Si double-gate thin-film SOI MOSFETs *Int. Electron Devices Meeting 1991* (IEEE), pp 683–6 (<http://ieeexplore.ieee.org/document/235330/>)
- [20] Lu L and Wong M 2014 The resistivity of zinc oxide under different annealing configurations and its impact on the leakage characteristics of zinc oxide thin-film transistors *IEEE Trans. Electron Devices* **61** 1077–84
- [21] Wang L, Yoon M-H, Lu G, Yang Y, Facchetti A and Marks T J 2006 High-performance transparent inorganic–organic hybrid thin-film n-type transistors *Nat. Mater.* **5** 893–900
- [22] Presley R E, Munsee C L, Park C-H, Hong D, Wager J F and Keszler D A 2004 Tin oxide transparent thin-film transistors *J. Phys. D: Appl. Phys.* **37** 2810–3
- [23] Chiang H Q, Wager J F, Hoffman R L, Jeong J and Keszler D A 2005 High mobility transparent thin-film transistors with amorphous zinc tin oxide channel layer *Appl. Phys. Lett.* **86** 013503
- [24] Barquinha P, Pimentel A, Marques A, Pereira L, Martins R and Fortunato E 2006 Effect of UV and visible light radiation on the electrical performances of transparent TFTs based on amorphous indium zinc oxide *J. Noncryst. Solids* **352** 1756–60
- [25] Presley R E, Hong D, Chiang H Q, Hung C M, Hoffman R L and Wager J F 2006 Transparent ring oscillator based on indium gallium oxide thin-film transistors *Solid State Electron.* **50** 500–3
- [26] Nomura K, Ohta H, Takagi A, Kamiya T, Hirano M and Hosono H 2004 Room-temperature fabrication of transparent flexible thin-film transistors using amorphous oxide semiconductors *Nature* **432** 488–92
- [27] Hanyu Y, Domen K, Nomura K, Hiramatsu H, Kumomi H, Hosono H and Kamiya T 2013 Hydrogen passivation of electron trap in amorphous In-Ga-Zn-O thin-film transistors *Appl. Phys. Lett.* **103** 202114
- [28] Nomura K, Kamiya T, Hirano M and Hosono H 2009 Origins of threshold voltage shifts in room-temperature deposited and annealed a-In-Ga-Zn-O thin-film transistors *Appl. Phys. Lett.* **95** 2014–7
- [29] Ide K, Kikuchi Y, Nomura K, Kimura M, Kamiya T and Hosono H 2011 Effects of excess oxygen on operation characteristics of amorphous In-Ga-Zn-O thin-film transistors *Appl. Phys. Lett.* **99** 093507
- [30] Hosono H, Yasukawa M and Kawazoe H 1996 Novel oxide amorphous semiconductors: transparent conducting amorphous oxides *J. Noncryst. Solids* **203** 334–44
- [31] Boesen G F and Jacobs J E 1968 ZnO field-effect transistor *Proc. IEEE* **56** 2094–5
- [32] Liu J, Sonshine D A, Shervani S and Hurt R H 2010 Controlled release of biologically active silver from nanosilver surfaces *ACS Nano* **4** 6903–13
- [33] Medvedeva J E, Buchholz D B and Chang R P H 2017 Recent advances in understanding the structure and properties of amorphous oxide semiconductors *Adv. Electron Mater.* **3** 1700082
- [34] Ryu B, Noh H K, Choi E A and Chang K J 2010 O-vacancy as the origin of negative bias illumination stress instability in amorphous In-Ga-Zn-O thin film transistors *Appl. Phys. Lett.* **97** 2012–5
- [35] Oh H, Yoon S M, Ryu M K, Hwang C S, Yang S and Park S H K 2010 Photon-accelerated negative bias instability involving subgap states creation in amorphous In-Ga-Zn-O thin film transistor *Appl. Phys. Lett.* **97** 1–4
- [36] Park J S, Maeng W J, Kim H S and Park J S 2012 Review of recent developments in amorphous oxide semiconductor thin-film transistor devices *Thin Solid Films* **520** 1679–93

- [37] Fortunato E, Barquinha P and Martins R 2012 Oxide semiconductor thin-film transistors: a review of recent advances *Adv. Mater.* **24** 2945–86
- [38] Xia Z, Lu L, Li J, Feng Z, Deng S, Wang S, Kwok H S and Wong M 2017 Characteristics of elevated-metal metal-oxide thin-film transistors based on indium-tin-zinc oxide *IEEE Electron Device Lett.* **38** 894–7
- [39] Song J H, Kim K S, Mo Y G, Choi R and Jeong J K 2014 Achieving high field-effect mobility exceeding 50 cm<sup>2</sup>/Vs in In-Zn-Sn-O thin-film transistors *IEEE Electron Device Lett.* **35** 853–5
- [40] Arai T and Sasaoka T 2011 49.1: invited paper: emergent oxide TFT technologies for next-generation AM-OLED displays *SID Symp. Dig. Tech. Pap.* **42** 710–3
- [41] Ando M, Wakagi M and Minemura T 1998 Effects of back-channel etching on the performance of a-Si:H thin-film transistors *Japan J. Appl. Phys.* **37** 3904–9
- [42] Lu L, Li J, Feng Z, Kwok H S and Wong M 2016 Elevated-metal-metal-oxide thin-film transistor: technology and characteristics *IEEE Electron Device Lett.* **37** 728–30
- [43] Shin H-J *et al* 2015 7.1: invited paper: novel OLED display technologies for large-size UHD OLED TVs *SID Symp. Dig. Tech. Pap.* **46** 53–6
- [44] Lu L, Li J and Wong M 2014 A comparative study on the effects of annealing on the characteristics of zinc oxide thin-film transistors with gate-stacks of different gas-permeability *IEEE Electron Device Lett.* **35** 841–3
- [45] Jang J and Lee S 2018 24.1: invited paper: flexible oxide TFTs for bendable and flexible displays *SID Symp. Dig. Tech. Pap.* **49** 248–51
- [46] Lee S, Chen Y, Kim H, Kim J and Jang J P 2019 14: distinguished poster: highly robust oxide TFT with bulk accumulation and source/drain/active layer splitting *SID Symp. Dig. Tech. Pap.* **50** 1263–6
- [47] Hwang C-S *et al* 2018 46-2: invited paper: ultimate resolution active matrix display with oxide TFT backplanes for electronic holographic display *SID Symp. Dig. Tech. Pap.* **49** 610–2
- [48] Kunitake H *et al* 2019 A C-axis-aligned crystalline In-Ga-Zn oxide FET with a gate length of 21 nm suitable for memory applications *IEEE J. Electron Devices Soc.* **7** 495–502
- [49] Li J, Lu L, Xia Z, Kwok H S and Wong M 2018 Three-mask elevated-metal metal-oxide thin-film transistor with self-aligned definition of the active island *IEEE Electron Device Lett.* **39** 35–8
- [50] Kamiya T and Hosono H 2015 Oxide TFTs *Handbook of Visual Display Technology* (Berlin: Springer), pp 1–28 ([https://doi.org/10.1007/978-3-642-35947-7\\_52-2](https://doi.org/10.1007/978-3-642-35947-7_52-2))
- [51] Nomura K, Kamiya T, Ohta H, Hirano M and Hosono H 2008 Defect passivation and homogenization of amorphous oxide thin-film transistor by wet O<sub>2</sub> annealing *Appl. Phys. Lett.* **93** 10–3
- [52] Hara Y, Kikuchi T, Kitagawa H, Morinaga J, Ohgami H, Imai H, Daitoh T and Matsuo T 2018 53-3: distinguished paper: IGZO-TFT technology for large-screen 8K display *SID Symp. Dig. Tech. Pap.* **49** 706–9
- [53] Yamazaki S, Suzawa H, Inoue K, Kato K, Hirohashi T, Okazaki K and Kimizuka N 2014 Properties of crystalline In-Ga-Zn-oxide semiconductor and its transistor characteristics *Japan J. Appl. Phys.* **53** 04ED18
- [54] Yoo W B *et al* 2018 54-2: flexible a-IGZO TFT for large sized OLED TV *SID Symp. Dig. Tech. Pap.* **49** 714–6

- [55] Yoshitomi S, Niikura Y, Oe Y, Kubota D, Kusunoki K, Hirakata Y, Yamazaki S, Katayama M and Matsuo N 2016 37-2: 1058-ppi 4K LC display using a top-gate self-aligned CAAC-OS FET *SID Symp. Dig. Tech. Pap.* **47** 473–6
- [56] Park C I *et al* 2018 54-1: distinguished paper: world 1st large size 77-inch transparent flexible OLED display *SID Symp. Dig. Tech. Pap.* **49** 710–3
- [57] Zhao Y-C *et al* 2018 28-3: world's first 85-in. 120 Hz-driven 8K × 4K BCE IGZO GOA VA-LCD *SID Symp. Dig. Tech. Pap.* **49** 362–4
- [58] Chang C *et al* 2019 62-3: a 120Hz 1G1D 8k4k LCD with oxide TFT *SID Symp. Dig. Tech. Pap.* **50** 882–4
- [59] Lu X *et al* 2017 21-2: highly reliable amorphous indium-gallium-zinc-tin-oxide TFTs with back-channel-etch structure *SID Symp. Dig. Tech. Pap.* **48** 291–3
- [60] Wu W-J, Zhou L, Yao R-H and Peng J-B 2011 A new voltage-programmed pixel circuit for enhancing the uniformity of AMOLED displays *IEEE Electron Device Lett.* **32** 931–3
- [61] Mo Y G, Kim M, Kang C K, Jeong J H, Park Y S, Choi C G, Kim H D and Kim S S 2011 Amorphous-oxide TFT backplane for large-sized AMOLED TVs *J. Soc. Inf. Disp.* **19** 16
- [62] Kim Y, Kanicki J and Lee H 2014 An a-InGaZnO TFT pixel circuit compensating threshold voltage and mobility variations in AMOLEDs *J. Disp. Technol.* **10** 402–6
- [63] Kimizuka N and Yamazaki S 2016 *Physics and Technology of Crystalline Oxide Semiconductor CAAC-IGZO: Application to Displays* ed S Yamazaki and T Tsutsui (Chichester: Wiley)
- [64] Lin C-L, Chen P-S, Lai P-C, Chu T-C, Wang M-X and Lee C-L 2016 Novel pixel circuit with compensation for normally-off/on a-IGZO TFTs and OLED luminance degradation *J. Disp. Technol.* **12** 1
- [65] Kim D, Kim Y, Lee S, Kang M S, Kim D H and Lee H 2017 High resolution a-IGZO TFT pixel circuit for compensating threshold voltage shifts and OLED degradations *IEEE J. Electron Devices Soc.* **5** 372–7
- [66] Lin C L, Lai P C, Lai P C, Chen P S and Wu W L 2016 Pixel circuit with parallel driving scheme for compensating luminance variation based on a-IGZO TFT for AMOLED displays *J. Disp. Technol.* **12** 1681–7
- [67] Lin C-L, Du Y-W, Cheng M-H, Chen Y-C and Tu C-D 2014 P-26: a low-power gate driver using depletion-mode a-IGZO TFTs *SID Symp. Dig. Tech. Pap.* **45** 1039–42
- [68] Kim B, Choi S C, Lee S Y, Kuk S H, Jang Y H and Kim C D *et al* 2011 A depletion-mode a-IGZO TFT shift register with a single low-voltage-level power signal *IEEE Electron Device Lett.* **32** 1092–4
- [69] Park Y-S, Chung B, Kang C, Park S, Im K, Jeong J H, Kim B-H and Kim S S 2011 49.3: oxide TFT scan driver with dynamic threshold voltage control *SID Symp. Dig. Tech. Pap.* **42** 718–21
- [70] Kang C-K, Park Y-S, Park S-I, Mo Y-G, Kim B-H and Kim S S 2011 4.2: integrated scan driver with oxide TFTs using floating gate method *SID Symp. Dig. Tech. Pap.* **42** 25–7
- [71] Song E, Kang B, Han I, Oh K, Kim B and Nam H 2015 Depletion mode oxide TFT shift register for variable frame rate AMOLED displays *IEEE Electron Device Lett.* **36** 247–9
- [72] Ma Q, Wang H, Zhou L, Fan J, Liao C, Guo X and Zhang S 2019 Robust gate driver on array based on amorphous IGZO thin-film transistor for large size high-resolution liquid crystal displays *IEEE J. Electron Devices Soc.* **7** 717–21
- [73] Shin H-J *et al* 2018 28-2: a novel OLED display panel with high-reliability integrated gate driver circuit using IGZO TFTs for large-sized UHD TVs *SID Symp. Dig. Tech. Pap.* **49** 358–61

## Chapter 8

- [1] Dahiya R S and Valle M 2012 *Robotic Tactile Sensing: Technologies and System* (Berlin: Springer)
- [2] Kim D-H *et al* 2011 Epidermal electronics *Science* **333** 838–43
- [3] Wu W, Wen X and Wang Z L 2013 Taxel-addressable matrix of vertical-nanowire piezotronic transistors for active and adaptive tactile imaging *Science* **340** 952–7
- [4] Wang S *et al* 2018 Skin electronics from scalable fabrication of an intrinsically stretchable transistor array *Nature* **555** 83–8
- [5] Yu X *et al* 2019 Skin-integrated wireless haptic interfaces for virtual and augmented reality *Nature* **575** 473–9
- [6] Zhang C, Tang W, Zhang L, Han C and Wang Z L 2014 Contact electrification field-effect transistor *ACS Nano* **8** 8702–9
- [7] Ramanathan S 2010 *Thin Film Metal-Oxides* (New York: Springer)
- [8] Wu W and Wang Z L 2016 Piezotronics and piezo-phototronics for adaptive electronics and optoelectronics *Nat. Rev. Mater.* **1** 1–17
- [9] Pan C, Zhai J and Wang Z L 2019 Piezotronics and piezo-phototronics of third generation semiconductor nanowires *Chem. Rev.* **119** 9303–59
- [10] Schwartz G, Tee B C-K, Mei J, Appleton A L, Kim D H, Wang H and Bao Z 2013 Flexible polymer transistors with high pressure sensitivity for application in electronic skin and health monitoring *Nat. Commun.* **4** 1–8
- [11] Zang Y, Zhang F, Huang D, Gao X, Di C-a and Zhu D 2015 Flexible suspended gate organic thin-film transistors for ultra-sensitive pressure detection *Nat. Commun.* **6** 1–9
- [12] Sekitani T *et al* 2009 Organic nonvolatile memory transistors for flexible sensor arrays *Science* **326** 1516–9
- [13] Takei K, Takahashi T, Ho J C, Ko H, Gillies A G, Leu P W, Fearing R S and Javey A 2010 Nanowire active-matrix circuitry for low-voltage macroscale artificial skin *Nat. Mater.* **9** 821–6
- [14] Shin S-H *et al* 2017 Integrated arrays of air-dielectric graphene transistors as transparent active-matrix pressure sensors for wide pressure ranges *Nat. Commun.* **8** 14950
- [15] Huang Y-C *et al* 2020 Sensitive pressure sensors based on conductive microstructured air-gap gates and two-dimensional semiconductor transistors *Nat. Electron.* **3** 59–69
- [16] Mannsfeld S C B, Tee B C K, Stoltenberg R M, Chen C V H H, Barman S, Muir B V O, Sokolov A N, Reese C and Bao Z 2010 Highly sensitive flexible pressure sensors with microstructured rubber dielectric layers *Nat. Mater.* **9** 859–64
- [17] Gao Y and Wang Z L 2007 Electrostatic potential in a bent piezoelectric nanowire. The fundamental theory of nanogenerator and nanopiezotronics *Nano Lett.* **7** 2499–505
- [18] Wang Z L 2007 Nanopiezotronics *Adv. Mater.* **19** 889–92
- [19] Wang Z L 2012 *Piezotronics and Piezo-Phototronics* (Berlin: Springer)
- [20] Wang Z L 2010 Piezopotential gated nanowire devices: piezotronics and piezo-phototronics *Nano Today* **5** 540–52
- [21] Zhang Y, Liu Y and Wang Z L 2011 Fundamental theory of piezotronics *Adv. Mater.* **23** 3004–13
- [22] Liu Y, Niu S, Yang Q, Klein B D B, Zhou Y S and Wang Z L 2014 Theoretical study of piezo-phototronic nano-LEDs *Adv. Mater.* **26** 7209–16
- [23] Raidl N, Supancic P, Danzer R and Hofstaetter M 2015 Piezotronically modified double schottky barriers in ZnO varistors *Adv. Mater.* **27** 2031–5

- [24] Keil P, Trapp M, Novak N, Frömling T, Kleebe H-J and Rödel J 2018 Piezotronic tuning of potential barriers in ZnO bicrystals *Adv. Mater.* **30** 1705573
- [25] Liu S, Wang L, Feng X, Liu J, Qin Y and Wang Z L 2019 Piezotronic tunneling junction gated by mechanical stimuli *Adv. Mater.* **31** 1905436
- [26] Liu S, Wang L, Feng X, Wang Z, Xu Q, Bai S, Qin Y and Wang Z L 2017 Ultrasensitive 2D ZnO piezotronic transistor array for high resolution tactile imaging *Adv. Mater.* **29** 1606346
- [27] Han W, Zhou Y, Zhang Y, Chen C-Y, Lin L, Wang X, Wang S and Wang Z L 2012 Strain-gated piezotronic transistors based on vertical zinc oxide nanowires *ACS Nano* **6** 3760–6
- [28] Zhou Y S *et al* 2012 Vertically aligned CdSe nanowire arrays for energy harvesting and piezotronic devices *ACS Nano* **6** 6478–82
- [29] Han X, Du W, Yu R, Pan C and Wang Z L 2015 Piezo-phototronic enhanced UV sensing based on a nanowire photodetector array *Adv. Mater.* **27** 7963–9
- [30] Zhao Z, Pu X, Han C, Du C, Li L, Jiang C, Hu W and Wang Z L 2015 Piezotronic effect in polarity-controlled GaN nanowires *ACS Nano* **9** 8578–83
- [31] Liu S, Wang L, Wang Z, Cai Y, Feng X, Qin Y and Wang Z L 2018 Double-channel piezotronic transistors for highly sensitive pressure sensing *ACS Nano* **12** 1732–8
- [32] Wang C H, Lai K Y, Li Y C, Chen Y C and Liu C P 2015 Ultrasensitive thin-film-based  $\text{Al}_x\text{Ga}_{1-x}\text{N}$  piezotronic strain sensors via alloying-enhanced piezoelectric potential *Adv. Mater.* **27** 6289–95
- [33] Su Y-L, Gupta K, Hsiao Y-L, Wang R-C and Liu C-P 2019 Gigantic enhancement of electricity generation in piezoelectric semiconductors by creating pores as a universal approach *Energy Environ. Sci.* **12** 410–7
- [34] Wang L *et al* 2019 2D piezotronics in atomically thin zinc oxide sheets: interfacing gating and channel width gating *Nano Energy* **60** 724–33
- [35] Dahiya R S, Lorenzelli L, Metta G and Valle M 2010 POSFET devices based tactile sensing arrays *Proc. 2010 IEEE Int. Symp. Circuits and Systems* (Piscataway, NJ: IEEE)
- [36] Pan C, Dong L, Zhu G, Niu S, Yu R, Yang Q, Liu Y and Wang Z L 2013 High-resolution electroluminescent imaging of pressure distribution using a piezoelectric nanowire LED array *Nat. Photonics* **7** 752–8
- [37] Zhang C, Li J, Han C B, Zhang L M, Chen X Y, Wang L D, Dong G F and Wang Z L 2015 Organic tribotronic transistor for contact-electrification-gated light-emitting diode *Adv. Funct. Mater.* **25** 5625–32
- [38] Zou H *et al* 2020 Quantifying and understanding the triboelectric series of inorganic non-metallic materials *Nat. Commun.* **11** 1–7
- [39] Fan F-R, Lin L, Zhu G, Wu W, Zhang R and Wang Z L 2012 Transparent triboelectric nanogenerators and self-powered pressure sensors based on micropatterned plastic films *Nano Lett.* **12** 3109–14
- [40] Wang Z L 2017 On Maxwell's displacement current for energy and sensors: the origin of nanogenerators *Mater. Today* **20** 74–82
- [41] Zhao J *et al* 2017 Flexible organic tribotronic transistor for pressure and magnetic sensing *ACS Nano* **11** 11566–73
- [42] Yang Z W, Pang Y, Zhang L, Lu C, Chen J, Zhou T, Zhang C and Wang Z L 2016 Tribotronic transistor array as an active tactile sensing system *ACS Nano* **10** 10912–20
- [43] Meng Y, Zhao J, Yang X, Zhao C, Qin S, Cho J H, Zhang C, Sun Q and Wang Z L 2018 Mechanosensation-active matrix based on direct-contact tribotronic planar graphene transistor array *ACS Nano* **12** 9381–9

- [44] Bu T, Xu L, Yang Z, Yang X, Liu G, Cao Y, Zhang C and Wang Z L 2020 Nanoscale triboelectrification gated transistor *Nat. Commun.* **11** 1–8
- [45] Wang Z L 2018 Nanogenerators, self-powered systems, blue energy, piezotronics and piezophotonics – a recall on the original thoughts for coining these fields *Nano Energy* **54** 477–83
- [46] Wang X, Zhang H, Dong L, Han X, Du W, Zhai J, Pan C and Wang Z L 2016 Self-powered high-resolution and pressure-sensitive triboelectric sensor matrix for real-time tactile mapping *Adv. Mater.* **28** 2896–903
- [47] Luo J *et al* 2019 Flexible and durable wood-based triboelectric nanogenerators for self-powered sensing in athletic big data analytics *Nat. Commun.* **10** 1–9

## Chapter 9

- [1] Sze S M and Ng K K 2007 *Physics of Semiconductor Devices* (New York: Wiley)
- [2] Knobelspies S, Daus A, Cantarella G, Petti L, Münzenrieder N, Tröster G and Salvatore G A 2016 Flexible a-IGZO phototransistor for instantaneous and cumulative UV-exposure monitoring for skin health *Adv. Electron. Mater.* **2** 1600273
- [3] Im H, Hong S, Lee Y, Lee H and Kim S 2019 A colorimetric multifunctional sensing method for structural-durability-health monitoring systems *Adv. Mater.* **31** 1807552
- [4] Chiu C J, Shih S S, Weng W Y, Chang S J, Hung Z D and Tsai T Y 2012 Deep UV Ta<sub>2</sub>O<sub>5</sub>/zinc-indium-tin-oxide thin film photo-transistor *IEEE Photonics Technol. Lett.* **24** 1018–20
- [5] Chang T H, Chiu C J, Weng W Y, Chang S J, Tsai T Y and Huang Z D 2012 High responsivity of amorphous indium gallium zinc oxide phototransistor with Ta<sub>2</sub>O<sub>5</sub> gate dielectric *Appl. Phys. Lett.* **101** 261112
- [6] Chang T H, Chiu C J, Chang S J, Tsai T Y, Yang T H, Huang Z D and Weng W Y 2013 Amorphous InGaZnO ultraviolet phototransistors with double-stack Ga<sub>2</sub>O<sub>3</sub>/SiO<sub>2</sub> dielectric *Appl. Phys. Lett.* **102** 221104
- [7] Chang S J, Chang T H, Weng W Y, Chiu C J and Chang S P 2014 Amorphous InGaZnO ultraviolet phototransistors with a thin Ga<sub>2</sub>O<sub>3</sub> layer *IEEE J. Sel. Top. Quantum Electron.* **20** 125–9
- [8] Kim D, Kim Y G, Kang B H, Lee J H, Chung J and Kim H J 2020 Fabrication of indium gallium zinc oxide phototransistors via oxide-mesh insertion for visible light detection *J. Mater. Chem. C* **8** 165–72
- [9] Wang C J, You H C, Ou J H, Chu Y Y and Ko F H 2020 Ultraviolet photodetecting and plasmon-to-electric conversion of controlled inkjet-printing thin-film transistors *Nanomaterials* **10** 458
- [10] Williams K J, Nelson C A, Yan X, Li L S and Zhu X 2013 Hot electron injection from graphene quantum dots to TiO<sub>2</sub> *ACS Nano* **7** 1388–94
- [11] Yan L, Du X, Liu C, Zhang S and Zhou H 2019 Narrow bandgap Pb–Sn perovskites/InGaZnO hybrid phototransistors for near-infrared detection *Phys. Status Solidi a* **216** 1900417
- [12] Mottram A D, Lin Y H, Pattanasattayavong P, Zhao K, Amassian A and Anthopoulos T D 2016 Quasi two-dimensional dye-sensitized In<sub>2</sub>O<sub>3</sub> phototransistors for ultrahigh responsivity and photosensitivity photodetector applications *ACS Appl. Mater. Interfaces* **8** 4894–902
- [13] Kang B H, Kim W G, Chung J, Lee J H and Kim H J 2018 Simple hydrogen plasma doping process of amorphous indium gallium zinc oxide-based phototransistors for visible light detection *ACS Appl. Mater. Interfaces* **10** 7223–30

- [14] Ahn C H, Kang W J, Kim Y K, Yun M G and Cho H K 2016 Highly repeatable and recoverable phototransistors based on multifunctional channels of photoactive CdS, fast charge transporting ZnO, and chemically durable Al<sub>2</sub>O<sub>3</sub> layers *ACS Appl. Mater. Interfaces* **8** 15518–23
- [15] Chung J, Tak Y J, Kim W G, Kang B H and Kim H J 2019 Artificially fabricated subgap states for visible-light absorption in indium–gallium–zinc oxide phototransistor with solution-processed oxide absorption layer *ACS Appl. Mater. Interfaces* **11** 38964–72
- [16] Cheng C C, Zhan J Y, Liao Y M, Lin T Y, Hsieh Y P and Chen Y F 2016 Self-powered and broadband photodetectors based on graphene/ZnO/silicon triple junctions *Appl. Phys. Lett.* **109** 053501
- [17] Yang H Y, Son D I, Kim T W, Lee J M and Park W I 2010 Enhancement of the photocurrent in ultraviolet photodetectors fabricated utilizing hybrid polymer-ZnO quantum dot nanocomposites due to an embedded graphene layer *Org. Electron.* **11** 1313–7
- [18] Lee H, An N, Jeong S, Kang S, Kwon S, Lee J and Lee S 2017 Strong dependence of photocurrent on illumination-light colors for ZnO/graphene Schottky diode *Curr. Appl. Phys.* **17** 552–6
- [19] Shao D, Sun X, Xie M, Sun H, Lu F, George S M and Sawyer S 2013 ZnO quantum dots-graphene composite for efficient ultraviolet sensing *Mater. Lett.* **112** 165–8
- [20] Zheng Z, Gan L, Zhang J, Zhuge F and Zhai T 2017 An enhanced UV–Vis–NIR and flexible photodetector based on electrospun ZnO nanowire array/PbS quantum dots film heterostructure *Adv. Sci.* **4** 1600316
- [21] Shao D, Gao J, Chow P, Sun H, Xin G, Sharma P and Sawyer S 2015 Organic–inorganic heterointerfaces for ultrasensitive detection of ultraviolet light *Nano Lett.* **15** 3787–92
- [22] Shin S W, Lee K H, Park J S and Kang S J 2015 Highly transparent, visible-light photodetector based on oxide semiconductors and quantum dots *ACS Appl. Mater. Interfaces* **7** 19666–71
- [23] Wang S S, Rong R, Jin L Z, Yang S S, Li Y X, Zhang H and Huang W 2018 Variable segment roles: modulation of the packing modes, nanocrystal morphologies and optical emissions *Nanoscale* **10** 13310–4
- [24] Zhu H, Liu A, Shan F, Yang W, Zhang W, Li D and Liu J 2016 One-step synthesis of graphene quantum dots from defective CVD graphene and their application in IGZO UV thin film phototransistor *Carbon* **100** 201–7
- [25] Bonaccorso F, Sun Z, Hasan T and Ferrari A C 2010 Graphene photonics and optoelectronics *Nat. Photon.* **4** 611
- [26] Liu X, Yang X, Liu M, Tao Z, Dai Q, Wei L and Nathan A 2014 Photo-modulated thin film transistor based on dynamic charge transfer within quantum-dots-InGaZnO interface *Appl. Phys. Lett.* **104** 113501
- [27] Kim J, Kwon S M, Kang Y K, Kim Y H, Lee M J, Han K and Park S K 2019 A skin-like two-dimensionally pixelized full-color quantum dot photodetector *Sci. Adv.* **5** eaax8801
- [28] Tak Y J, Kim D J, Kim W G, Lee J H, Kim S J, Kim J H and Kim H J 2018 Boosting visible light absorption of metal-oxide-based phototransistors via heterogeneous In–Ga–Zn–O and CH<sub>3</sub>NH<sub>3</sub>PbI<sub>3</sub> films *ACS Appl. Mater. Interfaces* **10** 12854–61
- [29] Baskoutas S and Bester G 2011 Transition in the optical emission polarization of ZnO nanorods *J. Phys. Chem. C* **115** 15862–7
- [30] Comini E, Faglia G, Sberveglieri G, Pan Z and Wang Z L 2002 Stable and highly sensitive gas sensors based on semiconducting oxide nanobelts *Appl. Phys. Lett.* **81** 1869–71

- [31] Wang Z L 2004 Nanostructures of zinc oxide *Mater. Today* **7** 26–33
- [32] Nie B, Hu J G, Luo L B, Xie C, Zeng L H, Lv P and Yu Y Q 2013 Monolayer graphene film on ZnO nanorod array for high-performance schottky junction ultraviolet photo-detectors *Small* **9** 2872–9
- [33] Kong W Y, Wu G A, Wang K Y, Zhang T F, Zou Y F, Wang D D and Luo L B 2016 Graphene- $\beta$ -Ga<sub>2</sub>O<sub>3</sub> heterojunction for highly sensitive deep UV photodetector application *Adv. Mater.* **28** 10725–31
- [34] Wang M Z, Liang F X, Nie B, Zeng L H, Zheng L X, Lv P and Luo L B 2013 TiO<sub>2</sub> nanotube array/monolayer graphene film Schottky junction ultraviolet light photodetectors *Part. Part. Syst. Charact.* **30** 630–6
- [35] Luo L B, Xie C, Wang X H, Yu Y Q, Wu C Y, Hu H and Jie J S 2014 Surface plasmon resonance enhanced highly efficient planar silicon solar cell *Nano Energy* **9** 112–20
- [36] Kim Y J, Yoon A, Kim M, Yi G C and Liu C 2011 Hydrothermally grown ZnO nanostructures on few-layer graphene sheets *Nanotechnology* **22** 245603
- [37] Liu H, Sun Q, Xing J, Zheng Z, Zhang Z, Lü Z and Zhao K 2015 Fast and enhanced broadband photoresponse of a ZnO nanowire array/reduced graphene oxide film hybrid photodetector from the visible to the near-infrared range *ACS Appl. Mater. Interfaces* **7** 6645–51
- [38] Aziz N, Nishiyama T, Rusli N, Mahmood M, Yasui K and Hashim A 2014 Seedless growth of zinc oxide flower-shaped structures on multilayer graphene by electrochemical deposition *Nanoscale Res. Lett.* **9** 337
- [39] Xu C, Kim B S, Lee J H, Kim M, Hwang S W, Choi B L and Whang D 2012 Seed-free electrochemical growth of ZnO nanotube arrays on single-layer graphene *Mater. Lett.* **72** 25–8
- [40] Ali A, Ali K, Yang Y J, Jo J and Choi K H 2014 Rapid fabrication of graphene/ZnO composite thin film *Japan J. Appl. Phys.* **53** 05HA01
- [41] Zeng Y, Zhao Y and Jiang Y 2014 Investigate the interface structure and growth mechanism of high quality ZnO films grown on multilayer graphene layers *Appl. Surf. Sci.* **301** 391–5
- [42] Lin J, Penchev M, Wang G, Paul R K, Zhong J, Jing X and Ozkan C S 2010 Heterogeneous graphene nanostructures: ZnO nanostructures grown on large-area graphene layers *Small* **6** 2448–52
- [43] Cheng S H, Yeh Y C, Lu M L, Chen C W and Chen Y F 2012 Enhancement of laser action in ZnO nanorods assisted by surface plasmon resonance of reduced graphene oxide nanoflakes *Opt. Express* **20** A799–805
- [44] Luo L B, Yang X B, Liang F X, Jie J S, Li Q, Zhu Z F and Wang L 2012 Transparent and flexible selenium nanobelt-based visible light photodetector *CrystEngComm* **14** 1942–7
- [45] Noh Y Y, Kim D Y and Yase K 2005 Highly sensitive thin-film organic phototransistors: effect of wavelength of light source on device performance *J. Appl. Phys.* **98** 074505
- [46] Nam S, Seo J, Park S, Lee S, Jeong J, Lee H and Kim Y 2013 Hybrid phototransistors based on bulk heterojunction films of poly (3-hexylthiophene) and zinc oxide nanoparticle *ACS Appl. Mater. Interfaces* **5** 1385–92
- [47] Pattanasattayavong P, Rossbauer S, Thomas S, Labram J G, Snaith H J and Anthopoulos T D 2012 Solution-processed dye-sensitized ZnO phototransistors with extremely high photoresponsivity *J. Appl. Phys.* **112** 074507



- [48] Janotti A and Van de Walle C G 2008 Sources of unintentional conductivity in InN *Appl. Phys. Lett.* **92** 032104
- [49] Zeng H, Cai W and Liu P *et al* 2008 ZnO-based hollow nanoparticles by selective etching: elimination and reconstruction of metal-semiconductor interface, improvement of blue emission and photocatalysis *ACS Nano* **2** 1661
- [50] Schmidt-Mende L and MacManus-Driscoll J L 2007 ZnO-nanostructures, defects, and devices *Mater. Today* **10** 40–8
- [51] McCluskey M D and Jokela S J 2009 Defects in ZnO *J. Appl. Phys.* **106** 10
- [52] Konstantatos G, Badioli M, Gaudreau L, Osmond J, Bernechea M, De Arquer F P G and Koppens F H 2012 Hybrid graphene-quantum dot phototransistors with ultrahigh gain *Nat. Nanotechnol.* **7** 363–8
- [53] Kumar M, Noh Y, Polat K, Okyay A K and Lee D 2015 Metal-semiconductor-metal UV photodetector based on Ga doped ZnO/graphene interface *Solid State Commun.* **224** 37–40
- [54] Dang V Q, Trung T Q, Kim D I, Duy L T, Hwang B U, Lee D W and Lee N E 2015 Ultrahigh responsivity in graphene-ZnO nanorod hybrid UV photodetector *Small* **11** 3054–65
- [55] Dang V Q, Trung T Q, Duy L T, Kim B Y, Siddiqui S, Lee W and Lee N E 2015 High-performance flexible ultraviolet (UV) phototransistor using hybrid channel of vertical ZnO nanorods and graphene *ACS Appl. Mater. Interfaces* **7** 11032–40
- [56] Boruah B D, Mukherjee A, Sridhar S and Misra A 2015 Highly dense ZnO nanowires grown on graphene foam for ultraviolet photodetection *ACS Appl. Mater. Interfaces* **7** 10606–11
- [57] Biroju R K, Tilak N, Rajender G, Dhara S and Giri P K 2015 Catalyst free growth of ZnO nanowires on graphene and graphene oxide and its enhanced photoluminescence and photoresponse *Nanotechnology* **26** 145601
- [58] Yang H, Li J, Yu D and Li L 2016 Seed/catalyst free growth and self-powered photoresponse of vertically aligned ZnO nanorods on reduced graphene oxide nanosheets *Cryst. Growth Des.* **16** 4831–8
- [59] Zhan Z, Zheng L, Pan Y, Sun G and Li L 2012 Self-powered, visible-light photodetector based on thermally reduced graphene oxide-ZnO (rGO-ZnO) hybrid nanostructure *J. Mater. Chem.* **22** 2589–95
- [60] Ick Son D, Yeon Yang H, Whan Kim T and Il Park W 2013 Photoresponse mechanisms of ultraviolet photodetectors based on colloidal ZnO quantum dot-graphene nanocomposites *Appl. Phys. Lett.* **102** 021105
- [61] Son D I, Yang H Y, Kim T W and Park W I 2015 Transparent and flexible ultraviolet photodetectors based on colloidal ZnO quantum dot/graphene nanocomposites formed on poly (ethylene terephthalate) substrates *Composites B* **69** 154–8
- [62] Guo W, Xu S, Wu Z, Wang N, Loy M M T and Du S 2013 Oxygen-assisted charge transfer between ZnO quantum dots and graphene *Small* **9** 3031–6
- [63] Chen J H, Jang C, Adam S, Fuhrer M S, Williams E D and Ishigami M 2008 Charged-impurity scattering in graphene *Nat. Phys.* **4** 377–81
- [64] Gong M, Liu Q, Cook B, Kattel B, Wang T, Chan W L and Wu J Z 2017 All-printable ZnO quantum dots/graphene van der Waals heterostructures for ultrasensitive detection of ultraviolet light *ACS Nano* **11** 4114–23
- [65] Liu Q, Gong M, Cook B, Ewing D, Casper M, Stramel A and Wu J 2017 Transfer-free and printable graphene/ZnO-nanoparticle nanohybrid photodetectors with high performance *J. Mater. Chem. C* **5** 6427–32

- [66] Choi H, Seo S, Lee J H, Hong S H, Song J, Kim S and Lee S 2018 Solution-processed ZnO/SnO<sub>2</sub> bilayer ultraviolet phototransistor with high responsivity and fast photoresponse *J. Mater. Chem. C* **6** 6014–22
- [67] Liu H Y and Huang R C 2018 A study of anatase TiO<sub>2</sub>-based thin film phototransistors by non-vacuum thin film deposition method *IEEE Trans. Electron Dev.* **65** 2517–24
- [68] Manga K K, Wang S, Jaiswal M, Bao Q and Loh K P 2010 High-gain graphene-titanium oxide photoconductor made from inkjet printable ionic solution *Adv. Mater.* **22** 5265–70
- [69] Manga K K, Wang J, Lin M, Zhang J, Nesladek M, Nalla V and Loh K P 2012 High-performance broadband photodetector using solution-processible PbSe–TiO<sub>2</sub>–graphene hybrids *Adv. Mater.* **24** 1697–702
- [70] Zheng K, Meng F, Jiang L, Yan Q, Hng H H and Chen X 2013 Visible photoresponse of single-layer graphene decorated with TiO<sub>2</sub> nanoparticles *Small* **9** 2076–80
- [71] Zheng Z, Zhuge F, Wang Y, Zhang J, Gan L, Zhou X and Zhai T 2017 Decorating perovskite quantum dots in TiO<sub>2</sub> nanotubes array for broadband response photodetector *Adv. Funct. Mater.* **27** 1703115
- [72] Guan X, Wang Z, Hota M K, Alshareef H N and Wu T 2019 P-type SnO thin film phototransistor with perovskite-mediated photogating *Adv. Electron. Mater.* **5** 1800538
- [73] Han G, Cao S, Yang Q, Yang W, Guo T and Chen H 2018 High-performance all-solution-processed flexible photodetector arrays based on ultrashort channel amorphous oxide semiconductor transistors *ACS Appl. Mater. Interfaces* **10** 40631–40
- [74] Ge M, Cao C, Huang J, Li S, Chen Z, Zhang K Q and Lai Y 2016 A review of one-dimensional TiO<sub>2</sub> nanostructured materials for environmental and energy applications *J. Mater. Chem. A* **4** 6772–801
- [75] Roy P, Berger S and Schmuki P 2011 TiO<sub>2</sub> nanotubes: synthesis and applications *Angew. Chem. Int. Ed.* **50** 2904–39
- [76] Jin Z, Gao L, Zhou Q and Wang J 2014 High-performance flexible ultraviolet photoconductors based on solution-processed ultrathin ZnO/Au nanoparticle composite films *Sci. Rep.* **4** 1–8
- [77] Wang F X, Lin J, Liu Y Q, Wu H D and Pan G B 2014 Facile fabrication and enhanced photoresponse of hybrid heterojunction films of ZnO nanowire network/ZnO nanoparticles *Org. Electron.* **15** 844–9
- [78] Ogo Y, Nomura K, Yanagi H, Kamiya T, Hirano M and Hosono H 2008 Amorphous Sn–Ga–Zn–O channel thin-film transistors *Phys. Status Solidi a* **205** 1920–4
- [79] Song J I, Park J S, Kim H, Heo Y W, Lee J H, Kim J J and Choi B D 2007 Transparent amorphous indium zinc oxide thin-film transistors fabricated at room temperature *Appl. Phys. Lett.* **90** 022106
- [80] Han D, Chen Z, Cong Y, Yu W, Zhang X and Wang Y 2016 High-performance flexible tin-zinc-oxide thin-film transistors fabricated on plastic substrates *IEEE Trans. Electron Dev.* **63** 3360–3
- [81] Nomura K, Ohta H, Takagi A, Kamiya T, Hirano M and Hosono H 2004 Room-temperature fabrication of transparent flexible thin-film transistors using amorphous oxide semiconductors *Nature* **432** 488–92
- [82] Jeon S, Song I, Lee S, Ryu B, Ahn S E, Lee E, Kim Y, Nathan A, Robertson J and Chung U I 2014 Origin of high photoconductive gain in fully transparent heterojunction nanocrystalline oxide image sensors and interconnects *Adv. Mater.* **26** 7102–9

- [83] Li J Y, Chang S P, Hsu M H and Chang S J 2017 Photo-electrical properties of MgZnO thin-film transistors with high-k dielectrics *IEEE Photon. Techn. Lett.* **30** 59–62
- [84] Yang C P, Chang S P, Chang S J, Chen S X, Hsu M H, Tung W J and Weng W Y 2018 Bandgap engineered ultraviolet photodetectors with gallium-zinc-oxide via co-sputtering method *ECS J. Solid State Sci. Technol.* **7** Q3083–8
- [85] Hosono H 2006 Ionic amorphous oxide semiconductors: material design, carrier transport, and device application *J. Non-Cryst. Solids* **352** 851–8
- [86] Feng L, Yu G, Li X, Zhang J, Ye Z and Lu J 2016 Solution processed amorphous ZnSnO thin-film phototransistors *IEEE Trans. Electron Dev.* **64** 206–10
- [87] Lee H M, Jeong H J, Ok K C, Rim Y S and Park J S 2018 Near-infrared photoresponsivity of ZnON thin-film transistor with energy band-tunable semiconductor *ACS Appl. Mater. Interfaces* **10** 30541–7
- [88] Rim Y S, Ok K C, Yang Y M, Chen H, Bae S H, Wang C and Yang Y 2016 Boosting responsivity of organic–metal oxynitride hybrid heterointerface phototransistor *ACS Appl. Mater. Interfaces* **8** 14665–70
- [89] Cho S W, Kim Y B, Jung S H, Baek S K, Kim J S, Lee M and Kim Y H 2018 All-solution-processed metal oxide/chalcogenide hybrid full-color phototransistors with multistacked functional layers and composition-gradient heterointerface *Adv. Opt. Mater.* **6** 1800196
- [90] Sharma A, Chourasia N K, Sugathan A, Kumar Y, Jit S, Liu S W and Pal B N 2018 Solution processed  $\text{Li}_5\text{AlO}_4$  dielectric for low voltage transistor fabrication and its application in metal oxide/quantum dot heterojunction phototransistors *J. Mater. Chem. C* **6** 790–8
- [91] Seung Rim Y, Jeong W, Du Ahn B and Jae Kim H 2013 Defect reduction in photon-accelerated negative bias instability of InGaZnO thin-film transistors by high-pressure water vapor annealing *Appl. Phys. Lett.* **102** 143503
- [92] Jeon K, Kim C, Song I, Park J, Kim S, Kim S and Kim D H 2008 Modeling of amorphous InGaZnO thin-film transistors based on the density of states extracted from the optical response of capacitance-voltage characteristics *Appl. Phys. Lett.* **93** 182102
- [93] Lee E, Benayad A, Shin T, Lee H, Ko D S, Kim T S and Park G S 2014 Nanocrystalline ZnON; high mobility and low band gap semiconductor material for high performance switch transistor and image sensor application *Sci. Rep.* **4** 4948
- [94] Ok K C, Jeong H J, Kim H S and Park J S 2014 Highly stable ZnON thin-film transistors with high field-effect mobility exceeding  $50 \text{ cm}^2/\text{Vs}$  *IEEE Electron Dev. Lett.* **36** 38–40
- [95] Kim H, Wu Z, Eedugurala N, Azoulay J D and Ng T N 2019 Solution-processed phototransistors combining organic absorber and charge transporting oxide for visible to infrared light detection *ACS Appl. Mater. Interfaces* **11** 36880–5
- [96] Shin K Y, Tak Y J, Kim W G, Hong S and Kim H J 2017 Improvement of electrical characteristics and stability of amorphous indium gallium zinc oxide thin film transistors using nitrocellulose passivation layer *ACS Appl. Mater. Interfaces* **9** 13278–85
- [97] Lee H, Chang K S, Tak Y J, Jung T S, Park J W, Kim W G and Kim H J 2017 Low-temperature activation under  $150 \text{ }^\circ\text{C}$  for amorphous IGZO TFTs using voltage bias *J. Inf. Disp.* **18** 131–5
- [98] Lim Y, Hwang N, Lee J, Lee S and Yi M 2019 Improved electrical performance of  $\text{SiO}_2$ -doped indium zinc oxide thin-film transistor *J. Nanosci. Nanotechnol.* **19** 1470–3

- [99] Yoon J, Bae G Y, Yoo S, Yoo J I, You N H, Hong W K and Ko H C 2020 Deep-ultraviolet sensing characteristics of transparent and flexible IGZO thin film transistors *J. Alloys Compd.* **817** 152788
- [100] Tao Z, Liu X, Lei W and Chen J 2018 High sensitive solar blind phototransistor based on ZnO nanorods/IGZO heterostructure annealed by laser *Mater. Lett.* **228** 451–5
- [101] Wang J, Chen Y, Kong L A, Fu Y, Gao Y and Sun J 2018 Deep-ultraviolet-triggered neuromorphic functions in In-Zn-O phototransistors *Appl. Phys. Lett.* **113** 151101
- [102] Yang J, Kwak H, Lee Y, Kang Y S, Cho M H, Cho J H and Kim H 2016 MoS<sub>2</sub>-InGaZnO heterojunction phototransistors with broad spectral responsivity *ACS Appl. Mater. Interfaces* **8** 8576–82
- [103] Barbagioanni E G, Strano V, Franzò G and Mirabella S 2016 The role of Zn vacancies in UV sensing with ZnO nanorods *Appl. Phys. Lett.* **109** 143104
- [104] Wu C, He Z, Lu J, Dai J and Xu C 2016 Energy band modification for UV photoresponse improvement in a ZnO microrod-quantum dot structure *RSC Adv.* **6** 687–91
- [105] Ma M, Kang Z, Liao Q, Zhang Q, Gao F, Zhao X and Zhang Y 2018 Development, applications, and future directions of triboelectric nanogenerators *Nano Res.* **11** 2951–69
- [106] Yoo H, Kim W G, Kang B H, Kim H T, Park J W, Choi D H and Kim H J 2020 High photosensitive indium–gallium–zinc oxide thin-film phototransistor with a selenium capping layer for visible-light detection *ACS Appl. Mater. Interfaces* **12** 10673–80
- [107] Wei S, Wang F, Zou X, Wang L, Liu C, Liu X and Liao L 2019 Flexible quasi-2D perovskite/IGZO phototransistors for ultrasensitive and broadband photodetection *Adv. Mater.* 1907527
- [108] Hou Y, Wang L, Zou X, Wan D, Liu C, Li G and Liao L 2020 Substantially improving device performance of all-inorganic perovskite-based phototransistors via indium tin oxide nanowire incorporation *Small* **16** 1905609
- [109] Huang K *et al* 2019 Nanostructured high-performance thin-film transistors and phototransistors fabricated by a high-yield and versatile near-field nanolithography strategy *ACS Nano* **13** 6618–30
- [110] Dai M K, Liou Y R, Lian J T, Lin T Y and Chen Y F 2015 Multifunctionality of giant and long-lasting persistent photoconductivity: semiconductor–conductor transition in graphene nanosheets and amorphous InGaZnO hybrids *ACS Photon.* **2** 1057–64
- [111] Pei Z, Lai H C, Wang J Y, Chiang W H and Chen C H 2014 High-responsivity and high-sensitivity graphene dots/a-IGZO thin-film phototransistor *IEEE Electron Device Lett.* **36** 44–6
- [112] Hwang I, Kim J, Lee M, Lee M W, Kim H J, Kwon H I and Park S K 2017 Wide-spectral/dynamic-range skin-compatible phototransistors enabled by floated heterojunction structures with surface functionalized SWCNTs and amorphous oxide semiconductors *Nanoscale* **9** 16711–21
- [113] Du S, Li G, Cao X, Wang Y, Lu H, Zhang S and Zhou H 2017 Oxide semiconductor phototransistor with organolead trihalide perovskite light absorber *Adv. Electron. Mater.* **3** 1600325
- [114] Sun M, Fang Q, Zhang Z, Xie D, Sun Y, Xu J and Zhang Y 2018 All-inorganic perovskite nanowires–ingazno heterojunction for high-performance ultraviolet–visible photodetectors *ACS Appl. Mater. Interfaces* **10** 7231–8
- [115] Liu X, Kuang W, Ni H, Tao Z, Huang Q, Chen J, Liu Q, Chang J and Lei W 2018 A highly sensitive and fast graphene nanoribbon/CsPbBr<sub>3</sub> quantum dot phototransistor with enhanced vertical metal oxide heterostructures *Nanoscale* **10** 10182–9

- [116] Rim Y S, Yang Y, Bae S H, Chen H, Li C, Goorsky M S and Yang Y 2015 Ultrahigh and broad spectral photodetectivity of an organic–inorganic hybrid phototransistor for flexible electronics *Adv. Mater.* **27** 6885–91

## Chapter 10

- [1] Kahng D and Sze S M 1967 A floating gate and its application to memory devices *Bell Syst. Tech. J* **46** 1288–95
- [2] Masuoka F, Asano M, Iwahashi H, Komuro T and Tanaka S 1985 A 256K flash EEPROM using triple polysilicon technology *1985 IEEE Int. Solid-State Circuits Conf. Digest of Technical Papers(13–15 February 1985)* vol 28 pp 168–9
- [3] Bez R, Camerlenghi E, Modelli A and Visconti A 2003 Introduction to flash memory *Proc. IEEE* **91** 489–502
- [4] Lai S K 2008 Flash memories: successes and challenges *IBM J. Res. Dev.* **52** 529–35
- [5] Irom F and Nguyen D N 2007 Single event effect characterization of high density commercial NAND and NOR nonvolatile flash memories *IEEE Trans. Nucl. Sci.* **54** 2547–53
- [6] Pon H 2006 Technology scaling impact on NOR and NAND flash memories and their applications *2006 8th Int. Conf. Solid-State and Integrated Circuit Technology Proc. (23–26 October 2006)* pp 697–700
- [7] Kapetanakis E *et al* 2000 Charge storage and interface states effects in Si-nanocrystal memory obtained using low-energy Si<sup>+</sup> implantation and annealing *Appl. Phys. Lett.* **77** 3450–2
- [8] Keshavan B V and Lin H C 1968 MONOS memory element *1968 Int. Electron Devices Meeting (23–25 October 1968)* pp 140–2
- [9] Bostock D 1976 1024-bit fully decoded MNOS non-volatile memory *ESSCIRC 76: 2nd European Solid State Circuits Conf. (21–24 September 1976)* pp 42–3
- [10] Takahashi Y and Ohnishi K 1993 Estimation of insulation layer conductance in MNOS structure *IEEE Trans. Electron Devices* **40** 2006–10
- [11] White M H, Yang Y, Ansha P and French M L 1997 A low voltage SONOS nonvolatile semiconductor memory technology *IEEE Trans. Compon. Packag. Manuf. Technol. A* **20** 190–5
- [12] Chen T S, Wu K H, Chung H and Kao C H 2004 Performance improvement of SONOS memory by bandgap engineering of charge-trapping layer *IEEE Electron Device Lett.* **25** 205–7
- [13] Kinam K and Jungdal C 2006 Future outlook of NAND flash technology for 40 nm node and beyond *2006 21st IEEE Non-Volatile Semiconductor Memory Workshop (12–16 February 2006)* pp 9–11
- [14] Kinam K 2005 Technology for sub-50 nm DRAM and NAND flash manufacturing *IEEE Int. Electron Devices Meeting, 2005. IEDM Technical Digest (5–5 December 2005)* pp 323–6
- [15] Choi S-J *et al* 2011 Nonvolatile memory by all-around-gate junctionless transistor composed of silicon nanowire on bulk substrate *IEEE Electron Device Lett.* **32** 602–4
- [16] Colinge J-P *et al* 2010 Reduced electric field in junctionless transistors *Appl. Phys. Lett.* **96**
- [17] Colinge J P *et al* 2010 Nanowire transistors without junctions *Nat. Nanotechnol.* **5** 225–9
- [18] Yan Ny T, Chim W K, Wee Kiong C, Moon Sig J and Byung Jin C 2006 Hafnium aluminum oxide as charge storage and blocking-oxide layers in SONOS-type nonvolatile memory for high-speed operation *IEEE Trans. Electron Devices* **53** 654–62

- [19] Lan X *et al* 2013 The effect of thermal treatment induced inter-diffusion at the interfaces on the charge trapping performance of  $\text{HfO}_2/\text{Al}_2\text{O}_3$  nanolaminate-based memory devices *J. Appl. Phys.* **114** 044104
- [20] Specht M *et al* 2005 Charge trapping memory structures with  $\text{Al}_2\text{O}_3$  trapping dielectric for high-temperature applications *Solid-State Electronics* **49** 716–20
- [21] Park J *et al* 2010 Improvement of reliability characteristics using the  $\text{N}_2$  implantation in SOHOS flash memory 2010 *IEEE Nanotechnology Materials and Devices Conf. (12–15 October 2010)* pp 364–7
- [22] Tan Y N, Chim W K, Cho B J and Choi W K 2004 Over-erase phenomenon in SONOS-type flash memory and its minimization using a hafnium oxide charge storage layer *IEEE Trans. Electron Devices* **51** 1143–7
- [23] Huby N, Ferrari S, Guziewicz E, Godlewski M and Osinniy V 2008 Electrical behavior of zinc oxide layers grown by low temperature atomic layer deposition *Appl. Phys. Lett.* **92** 023502
- [24] Xu H, Ye Z, Liu N, Wang Y, Zhang N and Liu Y 2017 Low-power transparent RFID circuits using enhancement/depletion logic gates based on deuterium-treated ZnO TFTs *IEEE Electron Device Lett.* **38** 1383–6
- [25] Jung Y, Lee K, Kim W-J, Lee W-J, Choi H and Kim K H 2012 Properties of In–Ga–ZnO thin films for thin film transistor channel layer prepared by facing targets sputtering method *Ceram. Int.* **38** S601
- [26] Ye Z, Yuan Y, Xu H, Liu Y, Luo J and Wong M 2017 Mechanism and origin of hysteresis in oxide thin-film transistor and its application on 3-D nonvolatile memory *IEEE Trans. Electron Devices* **64** 438–46
- [27] Ye Z, Lu L and Wong M 2012 Zinc-oxide thin-film transistor with self-aligned source/drain regions doped with implanted boron for enhanced thermal stability *IEEE Trans. Electron Devices* **59** 393–9
- [28] Ye Z and Wong M 2012 Characteristics of plasma-fluorinated zinc oxide thin-film transistors *IEEE Electron Device Lett.* **33** 1147–9
- [29] Ye Z and Wong M 2012 Characteristics of thin-film transistors fabricated on fluorinated zinc oxide *IEEE Electron Device Lett.* **33** 549–51
- [30] Oruc F B, Cimen F, Rizk A, Ghaffari M, Nayfeh A and Okyay A K 2012 Thin-film ZnO charge-trapping memory cell grown in a single ALD step *IEEE Electron Device Lett.* **33** 1714–6
- [31] Yun D-J, Kang H-B and Yoon S-M 2016 Process optimization and device characterization of nonvolatile charge trap memory transistors using In–Ga–ZnO thin films as both charge trap and active channel layers *IEEE Trans. Electron Devices* **63** 3128–34
- [32] Kim H-R, Kang C-S, Kim S-K, Byun C-W and Yoon S-M 2019 Characterization on the operation stability of mechanically flexible memory thin-film transistors using engineered ZnO charge-trap layers *J. Phys. D: Appl. Phys.* **52** 325106
- [33] Bak J Y *et al* 2015 Effects of thickness and geometric variations in the oxide gate stack on the nonvolatile memory behaviors of charge-trap memory thin-film transistors *Solid-State Electronics* **111** 153–60
- [34] Chen S *et al* 2013 Novel Zn-doped  $\text{Al}_2\text{O}_3$  charge storage medium for light-erasable In–Ga–Zn–O TFT memory *IEEE Electron Device Lett.* **34** 1008–10
- [35] Chen S, Zhang W-P, Cui X-M, Ding S-J, Sun Q-Q and Zhang W 2014 Monochromatic light-assisted erasing effects of In-Ga-Zn-O thin film transistor memory with  $\text{Al}_2\text{O}_3/\text{Zn}$ -doped  $\text{Al}_2\text{O}_3/\text{Al}_2\text{O}_3$  stacks *Appl. Phys. Lett.* **104** 103504

- [36] Kim S-J, Lee W-H and Yoon S-M 2015 Nonvolatile memory performances of transparent and/or flexible memory thin-film transistors using IGZO channel and ZnO charge-trap layers *2015 22nd International Workshop on Active-Matrix Flatpanel Displays and Devices (AM-FPD) (1–4 July 2015)* pp 21–3
- [37] Kim S-J, Park M-J, Yun D-J, Lee W-H, Kim G-H and Yoon S-M 2016 High performance and stable flexible memory thin-film transistors using In–Ga–Zn–O channel and ZnO charge-trap layers on poly(ethylene naphthalate) substrate *IEEE Trans. Electron Devices* **63** 1557–64
- [38] Na S-Y and Yoon S-M 2019 Impacts of HfO<sub>2</sub>/ZnO stack-structured charge-trap layers controlled by atomic layer deposition on nonvolatile memory characteristics of In-Ga-Zn-O channel charge-trap memory thin-film transistors *IEEE J. Electron Devices Soc.* **7** 453–61
- [39] Zhang W-P, Qian S-B, Liu W-J, Ding S-J and Zhang D W 2015 Novel multi-level cell TFT memory with an In–Ga–Zn–O charge storage layer and channel *IEEE Electron Device Lett.* **36** 1021–3
- [40] Her J-L, Chen F-H, Chen C-H and Pan T-M 2015 Electrical characteristics of gallium–indium–zinc oxide thin-film transistor non-volatile memory with Sm<sub>2</sub>O<sub>3</sub> and SmTiO<sub>3</sub> charge trapping layers *RSC Adv.* **5** 8566–70
- [41] Zhang W *et al* 2018 Demonstration of  $\alpha$ -InGaZnO TFT nonvolatile memory using TiAlO charge trapping layer *IEEE Trans. Nanotechnol.* **17** 1089–93
- [42] Blauwe J D 2002 Nanocrystal nonvolatile memory devices *IEEE Trans. Nanotechnol.* **1** 72–7
- [43] Liu Y, Chen T P, Ding L, Zhang S, Fu Y Q and Fung S 2006 Charging mechanism in a SiO<sub>2</sub> matrix embedded with Si nanocrystals *J. Appl. Phys.* **100**
- [44] Tiwari S, Rana F, Hanafi H, Hartstein A, Crabbé E F and Chan K 1996 A silicon nanocrystals based memory *Appl. Phys. Lett.* **68** 1377–9
- [45] Liu Z, Lee C, Narayanan V, Pei G and Kan E C 2002 Metal nanocrystal memories-part II: electrical characteristics *IEEE Trans. Electron Devices* **49** 1614–22
- [46] Chang T-C, Jian F-Y, Chen S-C and Tsai Y-T 2011 Developments in nanocrystal memory *Mater. Today* **14** 608–15
- [47] Chiang T-Y, Ma W C-Y, Wu Y-H, Wang K-T and Chao T-S 2010 A novel p-n-diode structure of SONOS-type TFT NVM with embedded silicon nanocrystals *IEEE Electron Device Lett.* **31** 1239–41
- [48] Lin Y-H, Chien C-H, Chou T-H, Chao T-S and Lei T-F 2007 Low-temperature polycrystalline silicon thin-film flash memory with hafnium silicate *IEEE Trans. Electron Devices* **54** 531–6
- [49] Lo S, Buchanan D A and Taur Y 1999 Modeling and characterization of quantization, polysilicon depletion, and direct tunneling effects in MOSFETs with ultrathin oxides *IBM J. Res. Dev.* **43** 327–37
- [50] Lee C, Meteer J, Narayanan V and Kan E 08/01 2005 Self-assembly of metal nanocrystals on ultrathin oxide for nonvolatile memory applications *J. Electron. Mater.* **34** 1–11
- [51] Gupta D, Anand M, Ryu S-W, Choi Y-K and Yoo S 2008 Nonvolatile memory based on sol-gel ZnO thin-film transistors with Ag nanoparticles embedded in the ZnO/gate insulator interface *Appl. Phys. Lett.* **93** 224106
- [52] Qian S-B, Shao Y, Liu W-J, Zhang D W and Ding S-J 2017 Erasing-modes dependent performance of a-IGZO TFT memory with atomic-layer-deposited Ni nanocrystal charge storage layer *IEEE Trans. Electron Devices* **64** 3023–7

- [53] Jang J *et al* 2011 Endurance characteristics of amorphous-InGaZnO transparent flash memory with gold nanocrystal storage layer *IEEE Trans. Electron Devices* **58** 3940–7
- [54] Tehrani S, Slaughter J M, Chen E, Durlam M, Shi J and DeHerren M 1999 Progress and outlook for MRAM technology *IEEE Trans. Magn.* **35** 2814–9
- [55] Hu G *et al* 2019 Spin-transfer torque MRAM with reliable 2 ns writing for last level cache applications *2019 IEEE Int. Electron Devices Meeting (IEDM) (7–11 December 2019)* pp 2.6.1–4
- [56] Nagel N *et al* 2004 New highly scalable 3 dimensional chain FeRAM cell with vertical capacitor *Digest of Technical Papers. 2004 Symp. on VLSI Technology (15–17 June 2004)* 146–7
- [57] Mikolajick T *et al* 2019 Next generation ferroelectric memories enabled by hafnium oxide *2019 IEEE Int. Electron Devices Meeting (IEDM) (7–11 December 2019)* pp 15.5.1–4
- [58] Kim G, Lee S, Hong S, Baik S J, Hori H and Ahn D 2014 Adjustable voltage dependent switching characteristics of PRAM for low voltage programming of multi-level resistances *2014 14th Annual Non-Volatile Memory Technology Symp. (NVMTS) (27–29 October 2014)* pp 1–3
- [59] Wong H S P *et al* 2012 Metal–oxide RRAM *Proc. IEEE* **100** 1951–70
- [60] Prall K 2017 Benchmarking and metrics for emerging memory *2017 IEEE Int. Memory Workshop (IMW) (14–17 May 2017)* pp 1–5
- [61] Watanabe Y *et al* 2001 Current-driven insulator–conductor transition and nonvolatile memory in chromium-doped SrTiO<sub>3</sub> single crystals *Appl. Phys. Lett.* **78** 3738–40
- [62] Beck A J, Bednorz J, Gerber C, Rossel C and Widmer D 2000 Reproducible switching effect in thin oxide films for memory applications *Appl. Phys. Lett.* **77** 139–41
- [63] Seo S *et al* 2004 Reproducible resistance switching in polycrystalline NiO films *Appl. Phys. Lett.* **85** 5655–7
- [64] Rohde C, Choi B J, Jeong D S, Choi S, Zhao J-S and Hwang C 2005 Identification of a determining parameter for resistive switching of TiO<sub>2</sub> thin films *Appl. Phys. Lett.* **86** 262907
- [65] Yang J-B *et al* 2014 Dual operation characteristics of resistance random access memory in indium-gallium-zinc-oxide thin film transistors *Appl. Phys. Lett.* **104** 153501
- [66] Felfel A *et al* 2020 Quantifying the benefits of monolithic 3D computing systems enabled by TFT and RRAM *2020 Design, Automation & Test in Europe Conf. & Exhibition (DATE) (9–13 March 2020)* pp 43–8

## Chapter 11

- [1] Jiang J, Guo J, Wan X, Yang Y, Xie H and Wan Q 2017 2D MoS<sub>2</sub> neuromorphic devices for brain-like computational systems *Small* **13** 1700933
- [2] Wan Q, Sharbati M T, Erickson J R, Du Y and Xiong F 2019 Emerging artificial synaptic devices for neuromorphic computing *Adv. Mater.* **4** 1900037
- [3] Wan C, Zhu L, Zhou J, Shi Y and Wan Q 2013 Memory and learning behaviors mimicked in nanogranular SiO<sub>2</sub>-based proton conductor gated oxide-based synaptic transistors *Nanoscale* **5** 10194–9
- [4] Wan C, Zhu L, Zhou J, Shi Y and Wan Q 2014 Inorganic proton conducting electrolyte coupled oxide-based dendritic transistors for synaptic electronics *Nanoscale* **6** 4491–7
- [5] Zhao Y and Jiang J 2018 Recent progress on neuromorphic synapse electronics: from emerging materials, devices, to neural networks *J. Nanosci. Nanotechnol.* **18** 8003–15



- [6] Tian H, Mi W, Wang X, Zhao H, Xie Q, Li C, Li Y-X, Yang Y and Ren T-L 2015 Graphene dynamic synapse with modulatable plasticity *Nano Lett.* **15** 8013–9
- [7] Li E *et al* 2019 Synaptic transistor capable of accelerated learning induced by temperature-facilitated modulation of synaptic plasticity *ACS Appl. Mater. Interfaces* **11** 46008–16
- [8] Shen A M, Chen C-L, Kim K, Cho B, Tudor A and Chen Y 2013 Analog neuromorphic module based on carbon nanotube synapses *ACS Nano* **7** 6117–22
- [9] Salonikidou B, Yasunori T, Le Borgne B, England J, Shizuo T and Sporea R A 2019 Toward fully printed memristive elements: a-TiO<sub>2</sub> electronic synapse from functionalized nanoparticle ink *ACS Appl. Electron Mater.* **1** 2692–700
- [10] Park Y and Lee J-S 2017 Artificial synapses with short-and long-term memory for spiking neural networks based on renewable materials *ACS Nano* **11** 8962–69
- [11] Zhang H, Ju X, Yew K S and Ang D S 2019 Implementation of simple but powerful trilayer oxide-based artificial synapses with a tailored bio-synapse-like structure *ACS Appl. Mater. Interfaces* **12** 1036–45
- [12] Jiang S, Nie S, He Y, Liu R, Chen C and Wan Q 2019 Emerging synaptic devices: from two-terminal memristors to multiterminal neuromorphic transistors *Mater. Today Nano* **8** 100059
- [13] Ohno T, Hasegawa T, Tsuruoka T, Terabe K, Gimzewski J K and Aono M 2011 Short-term plasticity and long-term potentiation mimicked in single inorganic synapses *Nat. Mater.* **10** 591–5
- [14] Chen Y, Yu H, Gong J, Ma M, Han H, Wei H and Xu W 2018 Artificial synapses based on nanomaterials *Nanotechnology* **30** 012001
- [15] La Barbera S, Vuillaume D and Alibart F 2015 Filamentary switching: synaptic plasticity through device volatility *ACS Nano* **9** 941–9
- [16] Li D, Wu B, Zhu X, Wang J, Ryu B and Liang X 2018 MoS<sub>2</sub> memristors exhibiting variable switching characteristics toward biorealistic synaptic emulation *ACS Nano* **12** 9240–52
- [17] Kim S, Kim H, Hwang S, Kim M-H, Chang Y and Park B-G 2017 Analog synaptic behavior of a silicon nitride memristor *ACS Appl. Mater. Interfaces* **9** 40420–7
- [18] Lee T-H, Hwang H-G, Woo J-U, Kim D-H, Kim T-W and Nahm S 2018 Synaptic plasticity and metaplasticity of biological synapse realized in a KNbO<sub>3</sub> memristor for application to artificial synapse *ACS Appl. Mater. Interfaces* **10** 25673–82
- [19] Sun J *et al* 2018 Optoelectronic synapse based on IGZO-alkylated graphene oxide hybrid structure *Adv. Funct. Mater.* **28** 1804397
- [20] Nishitani Y, Kaneko Y, Ueda M, Morie T and Fujii E 2012 Three-terminal ferroelectric synapse device with concurrent learning function for artificial neural networks *J. Appl. Phys.* **111** 124108
- [21] Xiong W, Zhu L, Ye C, Yu F, Ren Z and Ge Z 2019 Bilayered oxide-based cognitive memristor with brain-inspired learning activities *Adv. Electron. Mater.* **5** 1900439
- [22] Barquinha P, Pereira L, Goncalves G, Martins R and Fortunato E 2008 The effect of deposition conditions and annealing on the performance of high-mobility GIZO TFTs *Solid State Lett.* **11** H248–51
- [23] Barquinha P, Pereira L, Goncalves G, Martins R and Fortunato E 2009 Toward high-performance amorphous GIZO TFTs *J. Electrochem. Soc.* **156** H161–8
- [24] Lin H-C, Shie B-S and Huang T-Y 2014 100-nm IGZO thin-film transistors with film profile engineering *IEEE Trans. Electron Devices* **61** 2224–7

- [25] Zhang C *et al* 2018 Ion migration studies in exfoliated 2D molybdenum oxide via ionic liquid gating for neuromorphic device applications *ACS Appl. Mater. Interfaces* **10** 22623–31
- [26] Koo J, Yang J, Cho B, Jo H, Lee K H and Kang M S 2018 Nonvolatile electric double-layer transistor memory devices embedded with Au nanoparticles *ACS Appl. Mater. Interfaces* **10** 9563–70
- [27] Ji H, Wei J and Natelson D 2012 Modulation of the electrical properties of VO<sub>2</sub> nanobeams using an ionic liquid as a gating medium *Nano Lett.* **12** 2988–92
- [28] Xu W, Li H, Xu J-B and Wang L 2018 Recent advances of solution-processed metal oxide thin-film transistors *ACS Appl. Mater. Interfaces* **10** 25878–901
- [29] Black J M *et al* 2017 Role of electrical double layer structure in ionic liquid gated devices *ACS Appl. Mater. Interfaces* **9** 40949–58
- [30] Yu X, Zhou N, Smith J, Lin H, Stallings K, Yu J, Marks T J and Facchetti A 2013 Synergistic approach to high-performance oxide thin film transistors using a bilayer channel architecture *ACS Appl. Mater. Interfaces* **5** 7983–8
- [31] Li Y, Lan L, Sun S, Lin Z, Gao P, Song W, Song E, Zhang P and Peng J 2017 All inkjet-printed metal-oxide thin-film transistor array with good stability and uniformity using surface-energy patterns *ACS Appl. Mater. Interfaces* **9** 8194–200
- [32] Hennek J W, Kim M G, Kanatzidis M G, Facchetti A and Marks T J 2012 Exploratory combustion synthesis: amorphous indium yttrium oxide for thin-film transistors *J. Am. Chem. Soc.* **134** 9593–6
- [33] Sharma A, Chourasia N K, Pal N, Biring S and Pal B N 2019 Role of electron donation of TiO<sub>2</sub> gate interface for developing solution-processed high-performance one-volt metal-oxide thin-film transistor using ion-conducting gate dielectric *J. Phys. Chem. C* **123** 20278–86
- [34] Dou W, Jiang J, Sun J, Zhou B and Wan Q 2011 Low-voltage electric-double-layer TFTs on SiO<sub>2</sub>-covered paper substrates *IEEE Electron Device Lett.* **32** 1543–5
- [35] Fortunato E, Barquinha P and Martins R 2012 Oxide semiconductor thin-film transistors: a review of recent advances *Adv. Mater.* **24** 2945–86
- [36] Sato A, Abe K, Hayashi R, Kumomi H, Nomura K, Kamiya T, Hirano M and Hosono H 2009 Amorphous In–Ga–Zn–O coplanar homojunction thin-film transistor *Appl. Phys. Lett.* **94** 133502
- [37] Jiang J, Wan Q, Sun J, Dou W and Zhou B 2011 Junctionless in-plane-gate transparent thin-film transistors *Appl. Phys. Lett.* **99** 193502
- [38] Jiang J, Wan Q, Sun J and Lu A 2009 Ultralow-voltage transparent electric-double-layer thin-film transistors processed at room temperature *Appl. Phys. Lett.* **95** 152114
- [39] Zucker R S and Regehr W G 2002 Short-term synaptic plasticity *Annu. Rev. Physiol.* **64** 355–405
- [40] Zhu L, Wan C, Gao P, Liu Y, Xiao H, Yie J C and Wan Q 2016 Flexible proton-gated oxide synaptic transistors on Si membrane *ACS Appl. Mater. Interfaces* **8** 21770–5
- [41] Wan C, Liu Y, Feng P, Wang W, Zhu L, Liu Z P, Shi Y and Wan Q 2016 Flexible metal oxide/graphene oxide hybrid neuromorphic transistors on flexible conducting graphene substrates *Adv. Mater.* **28** 5878–85
- [42] Ho V M, Lee J-A and Martin K C 2011 The cell biology of synaptic plasticity *Science* **334** 623–8
- [43] Pereda A E 2014 Electrical synapses and their functional interactions with chemical synapses *Nat. Rev. Neurosci.* **15** 250–63

- [44] Abbott L and Regehr W G 2004 Synaptic computation *Nature* **431** 796–803
- [45] Wen J, Zhu L, Fu Y, Xiao H, Guo L and Wan Q 2017 Activity dependent synaptic plasticity mimicked on indium-tin-oxide electric-double-layer transistor *ACS Appl. Mater. Interfaces* **9** 37064–9
- [46] Voglis G and Tavernarakis N 2006 The role of synaptic ion channels in synaptic plasticity *EMBO Rep.* **7** 1104–10
- [47] Bi G-Q and Poo M-M 1998 Synaptic modifications in cultured hippocampal neurons: dependence on spike timing, synaptic strength, and postsynaptic cell type *J. Neurosci.* **18** 10464–72
- [48] Shen J, Shang D, Chai Y, Wang S, Shen B and Sun Y 2018 Mimicking synaptic plasticity and neural network using memtransistors *Adv. Mater.* **30** 1706717
- [49] Wan C, Liu Y, Zhu L, Feng P, Shi Y and Wan Q 2016 Short-term synaptic plasticity regulation in solution-gated indium-gallium-zinc-oxide electric-double-layer transistors *ACS Appl. Mater. Interfaces* **8** 9762–8
- [50] Li B *et al* 2018 Mediating short-term plasticity in an artificial memristive synapse by the orientation of silica mesopores *Adv. Mater.* **30** 1706395
- [51] Kim M-K and Lee J-S 2018 Short-term plasticity and long-term potentiation in artificial biosynapses with diffusive dynamics *ACS Nano* **12** 1680–7
- [52] Pilar-Cuellar F *et al* 2017 Enhanced stress response in 5-HT<sub>1A</sub>R overexpressing mice: altered HPA function and hippocampal long-term potentiation *ACS Chem. Neurosci.* **8** 2393–401
- [53] Markram H, Gerstner W and Sjöström P J 2011 A history of spike-timing-dependent plasticity *Front. Synaptic Neurosci.* **3** 4
- [54] Neuhofer D, Lassalle O and Manzoni O J 2018 Muscarinic M1 receptor modulation of synaptic plasticity in nucleus accumbens of wild-type and fragile X mice *ACS Chem. Neurosci.* **9** 2233–40
- [55] Li J, Ge C, Lu H, Guo H, Guo E, He M, Wang C, Yang G and Jin K 2019 Energy-efficient artificial synapses based on oxide tunnel junctions *ACS Appl. Mater. Interfaces* **11** 43473–9
- [56] Augustin S M and Lovinger D M 2018 Functional relevance of endocannabinoid-dependent synaptic plasticity in the central nervous system *ACS Chem. Neurosci.* **9** 2146–61
- [57] Ahmed T, Kuriakose S, Mayes E L H, Ramanathan R, Bansal V, Bhaskaran M, Sriram S and Walia S 2019 Optically stimulated artificial synapse based on layered black phosphorus *Small* **15** 1900966
- [58] Chen Y, Qiu W, Wang X, Liu W, Wang J, Dai J, Yuan Y, Gao Y and Sun J 2019 Solar-blind SnO<sub>2</sub> nanowire photo-synapses for associative learning and coincidence detection *Nano Energy* **62** 393–400
- [59] He Y, Yang Y, Nie S, Liu R and Wan Q 2018 Electric-double-layer transistors for synaptic devices and neuromorphic systems *J. Mater. Chem. C* **6** 5336–52
- [60] Bao L *et al* 2019 Dual-gated MoS<sub>2</sub> neuristor for neuromorphic computing *ACS Appl. Mater. Interfaces* **11** 41482–9
- [61] Jiang J, Hu W, Xie D, Yang J, He J, Gao Y and Wan Q 2019 2D electric-double-layer phototransistor for photoelectronic and spatiotemporal hybrid neuromorphic integration *Nanoscale* **11** 1360–9
- [62] Arnold A J, Razavieh A, Nasr J R, Schulman D S, Eichfeld C M and Das S 2017 Mimicking neurotransmitter release in chemical synapses via hysteresis engineering in MoS<sub>2</sub> transistors *ACS Nano* **11** 3110–8

- [63] Gou G, Sun J, Qian C, He Y, Kong L, Fu Y, Dai G, Yang J and Gao Y 2016 Artificial synapses based on biopolymer electrolyte-coupled SnO<sub>2</sub> nanowire transistors *J. Mater. Chem. C* **4** 11110–7
- [64] Fuller E J *et al* 2017 Li-ion synaptic transistor for low power analog computing *Adv. Mater.* **29** 1604310
- [65] Qian C, Kong L, Yang J, Gao Y and Sun J 2017 Multi-gate organic neuron transistors for spatiotemporal information processing *Appl. Phys. Lett.* **110** 083302
- [66] Wan C *et al* 2018 An artificial sensory neuron with tactile perceptual learning *Adv. Mater.* **30** 1801291
- [67] Sanchez Esqueda I *et al* 2018 Aligned carbon nanotube synaptic transistors for large-scale neuromorphic computing *ACS Nano* **12** 7352–61
- [68] Dai S, Wang Y, Zhang J, Zhao Y, Xiao F, Liu D, Wang T and Huang J 2018 Wood-derived nanopaper dielectrics for organic synaptic transistors *ACS Appl. Mater. Interfaces* **10** 39983–91
- [69] Kim S, Yoon J, Kim H-D and Choi S-J 2015 Carbon nanotube synaptic transistor network for pattern recognition *ACS Appl. Mater. Interfaces* **7** 25479–86
- [70] Yu R, Li E, Wu X, Yan Y, He W, He L, Chen J, Chen H and Guo T 2020 Electret-based organic synaptic transistor for neuromorphic computing *ACS Appl. Mater. Interfaces* **12** 15446–55
- [71] Li Z, Wan C, Guo L, Shi Y and Wan Q 2014 Artificial synapse network on inorganic proton conductor for neuromorphic systems *Nat. Commun.* **5** 3158
- [72] Hu D, Yang R, Jiang L and Guo X 2018 Memristive synapses with photoelectric plasticity realized in ZnO<sub>1-x</sub>/AlO<sub>y</sub> heterojunction *ACS Appl. Mater. Interfaces* **10** 6463–70
- [73] Li G *et al* 2020 Silicon nanomembrane phototransistor flipped with multifunctional sensors toward smart digital dust *Sci. Adv.* **6** eaaz6511
- [74] Li J, Jiang D, Yang Y, Zhou Y, Chen Q and Zhang J 2020 Li-ion doping as a strategy to modulate the electrical-double-layer for improved memory and learning behavior of synapse transistor based on fully aqueous solution-processed In<sub>2</sub>O<sub>3</sub>/AlLiO film *Adv. Electron. Mater.* **6** 1901363.
- [75] Halter M, Begon-Lours L, Bragaglia V, Sousa M, Offrein B J, Abel S, Luisier M and Fompeyrine J 2020 Back-end, CMOS-compatible ferroelectric field-effect transistor for synaptic weights *ACS Appl. Mater. Interfaces* **12** 17725–32
- [76] Li Y, Fuller E J, Asapu S, Agarwal S, Kurita T, Yang J J and Talin A A 2019 Low-voltage, CMOS-free synaptic memory based on Li<sub>x</sub>TiO<sub>2</sub> redox transistors *ACS Appl. Mater. Interfaces* **11** 38982–92
- [77] Jiang J, Dai M, Sun J, Zhou B, Lu A and Wan Q 2011 Electrostatic modification of oxide semiconductors by electric double layers of microporous SiO<sub>2</sub>-based solid electrolyte *J. Appl. Phys.* **109** 054501
- [78] Guo J, Jiang J and Yang B 2018 Low-voltage electric-double-layer MoS<sub>2</sub> transistor gated via water solution *Solid-State Electron.* **150** 8–15
- [79] Yuan H, Shimotani H, Ye J, Yoon S, Aliah H, Tzukazaki A, Kawasaki M and Iwasa Y 2010 Electrostatic and electrochemical nature of liquid-gated electric-double-layer transistors based on oxide semiconductors *J. Chem. Soc.* **132** 18402–7
- [80] Liu Y, Li B, Zhu L, Feng P, Shi Y and Wan Q 2016 Dopamine detection based on low-voltage oxide homojunction electric-double-layer thin-film transistors *IEEE Electron Device Lett.* **37** 1

- [81] Jiang J, Wan Q and Zhang Q 2013 Transparent junctionless electric-double-layer transistors gated by a reinforced chitosan-based biopolymer electrolyte *IEEE Trans. Electron Devices* **60** 1951
- [82] Xie D, Jiang J, Hu W, He Y, Yang J, He J, Gao Y and Wan Q 2018 Coplanar multigate MoS<sub>2</sub> electric-double-layer transistors for neuromorphic visual recognition *ACS Appl. Mater. Interfaces* **10** 25943–8
- [83] Du H, Lin X, Xu Z and Chu D 2015 Electric double-layer transistors: a review of recent progress *J. Mater. Sci.* **50** 5641–73
- [84] Fujimoto T and Awaga K 2013 Electric-double-layer field-effect transistors with ionic liquids *Phys. Chem. Chem. Phys.* **15** 8983–9006
- [85] Guo L, Wen J, Zhu L, Fu Y and Xiao H 2017 Humidity-dependent synaptic plasticity for proton gated oxide synaptic transistor *IEEE Electron Device Lett.* **38** 1248–51
- [86] Zheng Z, Jiang J, Guo J, Yang J and Gao Y 2016 Bio-inspired coplanar-gate-coupled ITO-free oxide-based transistors employing natural nontoxic bio-polymer electrolyte *Org. Electron.* **37** 474–8
- [87] Zheng Z, Jiang J, Guo J, Sun J and Yang J 2016 Chitosan-gated low-voltage transparent indium-free aluminum-doped zinc oxide thin-film transistors *Org. Electron.* **33** 311–5
- [88] Zhou J, Liu N, Zhu L, Shi Y and Wan Q 2014 Energy-efficient artificial synapses based on flexible IGZO electric-double-layer transistors *IEEE Electron Device Lett.* **36** 198–200
- [89] Hu W, Jiang J, Xie D, Wang S, Bi K and He J 2018 Transient security transistors self-supported on biodegradable natural-polymer membranes for brain-inspired neuromorphic applications *Nanoscale* **10** 14893–901
- [90] Zhou Y, Li J, Yang Y, Chen Q and Zhang J 2020 Artificial synapse emulated through fully aqueous solution-processed low-voltage In<sub>2</sub>O<sub>3</sub> thin-film transistor with Gd<sub>2</sub>O<sub>3</sub> solid electrolyte *ACS Appl. Mater. Interfaces* **12** 980–8
- [91] Shao F, Yang Y, Zhu L, Feng P and Wan Q 2016 Oxide-based synaptic transistors gated by sol-gel silica electrolytes *ACS Appl. Mater. Interfaces* **8** 3050–5
- [92] Yu F, Zhu L, Gao W, Fu Y, Xiao H, Tao J and Zhou J M 2018 Chitosan-based polysaccharide-gated flexible indium tin oxide synaptic transistor with learning abilities *ACS Appl. Mater. Interfaces* **10** 16881–6
- [93] Yang Y, Wen J, Guo L, Wan X, Du P, Feng P, Shi Y and Wang Q 2016 Long-term synaptic plasticity emulated in modified graphene oxide electrolyte gated IZO-based thin-film transistors *ACS Appl. Mater. Interfaces* **8** 30281–6
- [94] Rachmuth G, Shouval H Z, Bear M F and Poon C-S 2011 A biophysically-based neuromorphic model of spike rate-and timing-dependent plasticity *Proc. Natl Acad. Sci.* **108** E1266–74
- [95] Feng G, Zhao Y and Jiang J 2019 Lightweight flexible indium-free oxide TFTs with AND logic function employing chitosan biopolymer as self-supporting layer *Solid-State Electron.* **153** 16–22
- [96] Xie D, Hu W and Jiang J 2018 Bidirectionally-triggered 2D MoS<sub>2</sub> synapse through coplanar-gate electric-double-layer polymer coupling for neuromorphic complementary spatiotemporal learning *Org. Electron.* **63** 120–8
- [97] Huang H *et al* 2019 Electrolyte-gated synaptic transistor with oxygen ions *Adv. Funct. Mater.* **29** 1902702
- [98] Caporale N and Dan Y 2008 Spike timing-dependent plasticity: a Hebbian learning rule *Annu. Rev. Neurosci.* **31** 25–46

- [99] Park H L, Lee Y, Kim N, Seo D G, Go G T and Lee T W 2020 Flexible neuromorphic electronics for computing, soft robotics, and neuroprosthetics *Adv. Mater.* **32** 1903558
- [100] Yu F, Zhu L, Xiao H, Gao W and Guo Y 2018 Restickable oxide neuromorphic transistors with spike-timing-dependent plasticity and Pavlovian associative learning activities *Adv. Funct. Mater.* **28** 1804025
- [101] Zhu Y, Liu G, Xin Z, Fu C, Wan Q and Shan F 2020 Solution-processed, electrolyte-gated In<sub>2</sub>O<sub>3</sub> flexible synaptic transistors for brain-inspired neuromorphic applications *ACS Appl. Mater. Interfaces* **12** 1061–8
- [102] Kim M K and Lee J S 2019 Ferroelectric analog synaptic transistors *Nano Lett.* **19** 2044–50
- [103] Nishitani Y, Kaneko Y, Ueda M, Fujii E and Tsujimura A 2013 Dynamic observation of brain-like learning in a ferroelectric synapse device *Japan J. Appl. Phys.* **52** 04CE6
- [104] Yoo H *et al* 2020 High photosensitive indium-gallium-zinc oxide thin-film phototransistor with a selenium capping layer for visible-light detection *ACS Appl. Mater. Interfaces* **12** 10673–80
- [105] Li H, Chen T, Liu P, Hu S, Liu Y, Zhang Q and Lee P S 2016 A light-stimulated synaptic transistor with synaptic plasticity and memory functions based on InGaZnO<sub>x</sub>-Al<sub>2</sub>O<sub>3</sub> thin film structure *J. Appl. Phys.* **119** 244505
- [106] Kwon S M, Cho S W, Kim M, Heo J S, Kim Y H and Park S K 2019 Environment-adaptable artificial visual perception behaviors using a light-adjustable optoelectronic neuromorphic device array *Adv. Mater.* **31** 1906433
- [107] Peng C, Jiang W, Li Y, Li X and Zhang J 2019 Photoelectric IGZO electric-double-layer transparent artificial synapses for emotional state simulation *ACS Appl. Electron. Mater.* **1** 2406–14
- [108] Kim M K and Lee J S 2020 Synergistic improvement of long-term plasticity in photonic synapses using ferroelectric polarization in hafnia-based oxide-semiconductor transistors *Adv. Mater.* **32** 1907826
- [109] Duan N *et al* 2019 An electro-photo-sensitive synaptic transistor for edge neuromorphic visual systems *Nanoscale* **11** 17590–9
- [110] Huang W *et al* 2020 Zero-power optoelectronic synaptic devices *Nano Energy* **73** 104790
- [111] Sangwan V K and Hersam M C 2020 Neuromorphic nanoelectronic materials *Nat. Nanotechnol.*
- [112] Dai S, Zhao Y, Wang Y, Zhang J, Fang L, Jin S, Shao Y and Huang J 2019 Recent advances in transistor-based artificial synapses *Adv. Funct. Mater.* **29** 1903700

## Chapter 12

- [1] Klasens H A and Koelmans H 1964 A tin oxide field-effect transistor *Solid-State Electron.* **7** 701–2
- [2] Seager C H, McIntyre D C, Warren W L and Tuttle B A 1996 Charge trapping and device behavior in ferroelectric memories *Appl. Phys. Lett.* **68** 2660–2
- [3] Nomura K, Ohta H, Ueda K, Kamiya T, Hirano M and Hosono H 2003 Thin-film transistor fabricated in single-crystalline transparent oxide semiconductor *Science* **300** 1269–72
- [4] Nomura K, Ohta H, Takagi A, Kamiya T, Hirano M and Hosono H 2004 Room-temperature fabrication of transparent flexible thin-film transistors using amorphous oxide semiconductors *Nature* **432** 488–92

- [5] Sharp Begins Production of World's First LCD Panels Incorporating IGZO Oxide Semiconductors 2012 (<http://www.sharp-worldcom/corporate/news/120413.html>)
- [6] Petti L, Münzenrieder N, Vogt C, Faber H, Büthe L, Cantarella G, Bottacchi F, Anthopoulos T D and Tröster G 2016 Metal oxide semiconductor thin-film transistors for flexible electronics *Appl. Phys. Rev.* **3** 021303
- [7] Troughton J and Atkinson D 2019 Amorphous InGaZnO and metal oxide semiconductor devices: an overview and current status *J. Mater. Chem. C* **7** 12388–414
- [8] Park J W, Kang B H and Kim H J 2020 A review of low-temperature solution-processed metal oxide thin-film transistors for flexible electronics *Adv. Funct. Mater.* **30** 1904632
- [9] Park J S, Maeng W J, Kim H S and Park J S 2012 Review of recent developments in amorphous oxide semiconductor thin-film transistor devices *Thin Solid Films* **520** 1679–93
- [10] Fortunato E, Barquinha P and Martins R 2012 Oxide semiconductor thin-film transistors: a review of recent advances *Adv. Mater.* **24** 2945–86
- [11] Kimura M 2019 Emerging applications using metal-oxide semiconductor thin-film devices *Jpn. J. Appl. Phys.* **58** 090503
- [12] Xu W Y, Li H, Xu J B and Wang L 2018 Recent advances of solution-processed metal oxide thin-film transistors *ACS Appl. Mater. Interfaces* **10** 25878–901
- [13] Pearton S J, Yang J C, Cary P H, Ren F, Kim J, Tadjer M J and Mastro M A 2018 A review of Ga<sub>2</sub>O<sub>3</sub> materials, processing, and devices *Appl. Phys. Rev.* **5** 011301
- [14] Myny K 2018 The development of flexible integrated circuits based on thin-film transistors *Nat. Electron.* **1** 30–9
- [15] Hosono H 2006 Ionic amorphous oxide semiconductors: material design, carrier transport, and device application *J. Non-Cryst. Solids* **352** 851–8
- [16] Barquinha P, Pereira L, Gonçalves G, Martins R and Fortunato E 2009 Toward high-performance amorphous GIZO TFTs *J. Electrochem. Soc.* **156** H161
- [17] Iwasaki T, Itagaki N, Den T, Kumomi H, Nomura K, Kamiya T and Hosono H 2007 Combinatorial approach to thin-film transistors using multicomponent semiconductor channels: an application to amorphous oxide semiconductors in In-Ga-Zn-O system *Appl. Phys. Lett.* **90** 242114
- [18] Suresh A, Wellenius P, Dhawan A and Muth J 2007 Room temperature pulsed laser deposited indium gallium zinc oxide channel based transparent thin film transistors *Appl. Phys. Lett.* **90** 123512
- [19] Park M J *et al* 2015 Improvements in the bending performance and bias stability of flexible InGaZnO thin film transistors and optimum barrier structures for plastic poly(ethylene naphthalate) substrates *J. Mater. Chem. C* **3** 4779–86
- [20] Choi C H, Lin L Y, Cheng C C and Chang C H 2015 Printed oxide thin film transistors: a mini review *ECS J. Solid State Sci. Technol.* **4** P3044–51
- [21] Kim G H, Kim H S, Shin H S, Du Ahn B, Kim K H and Kim H J 2009 Inkjet-printed InGaZnO thin film transistor *Thin Solid Films* **517** 4007–10
- [22] Fukuda N, Watanabe Y, Uemura S, Yoshida Y, Nakamura T and Ushijima H 2014 In-Ga-Zn oxide nanoparticles acting as an oxide semiconductor material synthesized via a coprecipitation-based method *J. Mater. Chem. C* **2** 2448
- [23] Liu H Y, Hung C C and Hsu W C 2018 Deposition of oxide thin films by ultrasonic spray pyrolysis deposition for InGaZnO thin-film transistor applications *IEEE Electron Device Lett.* **39** 1520–3

- [24] Yabuta H, Sano M, Abe K, Aiba T, Den T, Kumomi H, Nomura K, Kamiya T and Hosono H 2006 High-mobility thin-film transistor with amorphous InGaZnO<sub>4</sub> channel fabricated by room temperature rf-magnetron sputtering *Appl. Phys. Lett.* **89** 112123
- [25] Olziersky A, Barquinha P, Vilà A, Pereira L, Gonçalves G, Fortunato E, Martins R and Morante J R 2010 Insight on the SU-8 resist as passivation layer for transparent Ga<sub>2</sub>O<sub>3</sub>-In<sub>2</sub>O<sub>3</sub>-ZnO thin-film transistors *J. Appl. Phys.* **108** 064505
- [26] Park J S *et al* 2010 High-performance and stable transparent Hf-In-Zn-O thin-film transistors with a double-etch-stopper layer *IEEE Electron Device Lett.* **31** 1248–50
- [27] Ram M S, Kort L, Riet J, Verbeek R, Bel T, Gelinck G and Kronemeijer A J 2019 Submicrometer top-gate self-aligned a-IGZO TFTs by substrate conformal imprint lithography *IEEE Trans. Electron Devices* **66** 1778–82
- [28] Zhang Y, Yang H, Peng H, Cao Y, Qin L and Zhang S 2019 Self-aligned top-gate amorphous InGaZnO TFTs with plasma enhanced chemical vapor deposited sub-10 nm SiO<sub>2</sub> gate dielectric for low-voltage applications *IEEE Electron Device Lett.* **40** 1459–62
- [29] Park J C *et al* 2009 High performance amorphous oxide thin film transistors with self-aligned top-gate structure 2009 *IEEE Int. Electron Devices Meeting (IEDM) (7–9 December 2009)* (<https://doi.org/10.1109/IEDM.2009.5424391>)
- [30] Kamiya T, Nomura K and Hosono H 2010 Present status of amorphous In-Ga-Zn-O thin-film transistors *Sci. Technol. Adv. Mater.* **11** 044305
- [31] Nomura K, Takagi A, Kamiya T, Ohta H, Hirano M and Hosono H 2006 Amorphous oxide semiconductors for high-performance flexible thin-film transistors *Japan J. Appl. Phys.* **45** 4303–8
- [32] Yao J *et al* 2011 Electrical and photosensitive characteristics of a-IGZO TFTs related to oxygen vacancy *IEEE Trans. Electron Devices* **58** 1121–6
- [33] Kikuchi Y, Nomura K, Yanagi H, Kamiya T, Hirano M and Hosono H 2010 Device characteristics improvement of a-In-Ga-Zn-O TFTs by low-temperature annealing *Thin Solid Films* **518** 3017–21
- [34] Noh H K, Chang K J, Ryu B and Lee W J 2011 Electronic structure of oxygen-vacancy defects in amorphous In-Ga-Zn-O semiconductors *Phys. Rev. B* **84** 115205
- [35] Nomura K, Kamiya T and Hosono H 2013 Effects of diffusion of hydrogen and oxygen on electrical properties of amorphous oxide semiconductor, In-Ga-Zn-O *ECS J. Solid State Sci. Technol.* **2** P5–8
- [36] Han K L, Ok K C, Cho H S, Oh S and Park J S 2017 Effect of hydrogen on the device performance and stability characteristics of amorphous InGaZnO thin-film transistors with a SiO<sub>2</sub>/SiN<sub>x</sub>/SiO<sub>2</sub> buffer *Appl. Phys. Lett.* **111** 063502
- [37] Nam Y, Kim H O, Cho S H and Ko Park S H 2018 Effect of hydrogen diffusion in an In-Ga-Zn-O thin film transistor with an aluminum oxide gate insulator on its electrical properties *RSC Adv.* **8** 5622–8
- [38] Lee J M, Cho I T, Lee J H and Kwon H I 2008 Bias-stress-induced stretched-exponential time dependence of threshold voltage shift in InGaZnO thin film transistors *Appl. Phys. Lett.* **93** 093504
- [39] Nomura K, Kamiya T, Hirano M and Hosono H 2009 Origins of threshold voltage shifts in room-temperature deposited and annealed a-In-Ga-Zn-O thin-film transistors *Appl. Phys. Lett.* **95** 013502
- [40] Suresh A and Muth J F 2008 Bias stress stability of indium gallium zinc oxide channel based transparent thin film transistors *Appl. Phys. Lett.* **92** 033502



- [41] Nomura K, Kamiya T and Hosono H 2010 Interface and bulk effects for bias-light-illumination instability in amorphous-In-Ga-Zn-O thin-film transistors *J. Soc. Inf. Disp.* **18** 789
- [42] Tu Y *et al* 2020 Improving a-InGaZnO TFTs reliability by optimizing electrode capping structure under negative bias illumination stress *IEEE Electron Device Lett.* **41** 1221–4
- [43] Kim S J, Yoon S and Kim H J 2014 Review of solution-processed oxide thin-film transistors *Jpn. J. Appl. Phys.* **53** 02BA
- [44] Thomas S R, Pattanasattayavong P and Anthopoulos T D 2013 Solution-processable metal oxide semiconductors for thin-film transistor applications *Chem. Soc. Rev.* **42** 6910–23
- [45] Kwon J Y, Lee D J and Kim K B 2011 Transparent amorphous oxide semiconductor thin film transistor *Electron. Mater. Lett.* **7** 1–11
- [46] Lee H N, Kyung J W, Kang S K, Kim D Y, Sung M C, Kim S J, Kim C N, Kim H G and Kim S T 2006 *Proc. Int. Display Workshop 2006 (Otsu, Japan, 6–8 December 2006)* p 663
- [47] Jeong J K *et al* 2007 *47th Int. Meeting on Information Display (Daegu, Korea, 27–31 August 2007)* pp 9–4
- [48] Hara Y, Kikuchi T, Kitagawa H, Morinaga J, Ohgami H, Imai H, Daitoh T and Matsuo T 2018 IGZO-TFT technology for large-screen 8K display *J. Soc. Inf. Disp.* **26** 169–77
- [49] Münzenrieder N, Cherenack K H and Tröster G 2011 The effects of mechanical bending and illumination on the performance of flexible IGZO TFTs *IEEE Trans. Electron Devices* **58** 2041–8
- [50] Münzenrieder N *et al* 2015 Stretchable and conformable oxide thin-film electronics *Adv. Electron. Mater.* **1** 1400038
- [51] Salvatore G A, Münzenrieder N, Kinkeldei T, Petti L, Zysset C, Strelbel I, Bütthe L and Tröster G 2014 Wafer-scale design of lightweight and transparent electronics that wraps around hairs *Nat. Commun.* **5** 2982
- [52] Wu H C and Chien C H 2014 Highly transparent, high-performance IGZO-TFTs using the selective formation of IGZO source and drain electrodes *IEEE Electron Device Lett.* **35** 645–7
- [53] Ito M, Kon M, Okubo T, Ishizaki M and Sekine N 2005 *Proc. Int. Display Workshop/Asia Display (Takamatsu, Japan, 6–9 December 2005)* 845
- [54] Sung M C, Lee H N, Kim C N, Kang S K, Kim D Y, Kim S J, Kim S K, Kim S K, Kim H G and Kim S T 2007 *7th Int. Meeting Information Display (Daegu, Korea, 27–31 August 2007)* 9–1
- [55] Nagata T *et al* 2016 A 2.78-in 1058-ppi ultra-high-resolution flexible OLED display using CAAC-IGZO FETs *Dig. Tech. Pap. SID Int. Symp.* **47** 1052–5
- [56] Lee C T *et al* 2015 A novel highly transparent 6-in. AMOLED display consisting of IGZO TFTs *Dig. Tech. Pap. SID Int. Symp.* **46** 872–5
- [57] Guo D, Guo Q, Chen Z, Wu Z, Li P and Tang W 2019 Review of Ga<sub>2</sub>O<sub>3</sub>-based optoelectronic devices *Mater. Today Phys.* **11** 100157
- [58] Higashiwaki M, Kuramata A, Murakami H and Kumagai Y 2017 State-of-the-art technologies of gallium oxide power devices *J. Phys. D: Appl. Phys.* **50** 333002
- [59] Huan Y W, Sun S M, Gu C J, Liu W J, Ding S J, Yu H Y, Xia C T and Zhang D W 2018 Recent advances in β-Ga<sub>2</sub>O<sub>3</sub>-metal contacts *Nanoscale Res. Lett.* **13** 246
- [60] Xue H, He Q, Jian G, Long S, Pang T and Liu M 2018 An overview of the ultrawide bandgap Ga<sub>2</sub>O<sub>3</sub> semiconductor-based Schottky barrier diode for power electronics application *Nanoscale Res. Lett.* **13** 290

- [61] Fu B, Jia Z, Mu W, Yin Y, Zhang J and Tao X 2019 A review of  $\beta$ -Ga<sub>2</sub>O<sub>3</sub> single crystal defects, their effects on device performance and their formation mechanism *J. Semicond.* **40** 011804
- [62] Galazka Z 2018  $\beta$ -Ga<sub>2</sub>O<sub>3</sub> for wide-bandgap electronics and optoelectronics *Semicond. Sci. Technol.* **33** 113001
- [63] Higashiwaki M, Murakami H, Kumagai Y and Kuramata A 2016 Current status of Ga<sub>2</sub>O<sub>3</sub> power devices *Japan J. Appl. Phys.* **55** 1202A1
- [64] Dong H, Xue H, He Q, Qin Y, Jian G, Long S and Liu M 2019 Progress of power field effect transistor based on ultra-wide bandgap Ga<sub>2</sub>O<sub>3</sub> semiconductor material *J. Semicond.* **40** 011802
- [65] Higashiwaki M, Sasaki K, Murakami H, Kumagai Y, Koukitu A, Kuramata A, Masui T and Yamakoshi S 2016 Recent progress in Ga<sub>2</sub>O<sub>3</sub> power devices *Semicond. Sci. Technol.* **31** 034001
- [66] He H, Blanco M A and Pandey R 2006 Electronic and thermodynamic properties of  $\beta$ -Ga<sub>2</sub>O<sub>3</sub> *Appl. Phys. Lett.* **88** 261904
- [67] Higashiwaki M, Sasaki K, Kuramata A, Masui T and Yamakoshi S 2012 Gallium oxide (Ga<sub>2</sub>O<sub>3</sub>) metal-semiconductor field-effect transistors on single-crystal  $\beta$ -Ga<sub>2</sub>O<sub>3</sub> (010) substrates *Appl. Phys. Lett.* **100** 013504
- [68] Villora E G, Shimamura K, Yoshikawa Y, Aoki K and Ichinose N 2004 Large-size  $\beta$ -Ga<sub>2</sub>O<sub>3</sub> single crystals and wafers *J. Cryst. Growth* **270** 420–6
- [69] Galazka Z *et al* 2016 Scaling-up of bulk  $\beta$ -Ga<sub>2</sub>O<sub>3</sub> single crystals by the Czochralski method *ECS J. Solid State Sci. Technol.* **6** Q3007–11
- [70] Hoshikawa K, Ohba E, Kobayashi T, Yanagisawa J, Miyagawa C and Nakamura Y 2016 Growth of  $\beta$ -Ga<sub>2</sub>O<sub>3</sub> single crystals using vertical Bridgman method in ambient air *J. Cryst. Growth* **447** 36–41
- [71] Kuramata A, Koshi K, Watanabe S, Yamaoka Y, Masui T and Yamakoshi S 2016 High-quality  $\beta$ -Ga<sub>2</sub>O<sub>3</sub> single crystals grown by edge-defined film-fed growth *Japan J. Appl. Phys.* **55** 1202A2
- [72] Alema F, Hertog B, Osinsky A, Mukhopadhyay P, Toporkov M and Schoenfeld W V 2017 Fast growth rate of epitaxial  $\beta$ -Ga<sub>2</sub>O<sub>3</sub> by close coupled showerhead MOCVD *J. Cryst. Growth* **475** 77–82
- [73] Baldini M, Albrecht M, Fiedler A, Irmscher K, Klimm D, Schewski R and Wagner G 2016 Semiconducting Sn-doped  $\beta$ -Ga<sub>2</sub>O<sub>3</sub> homoepitaxial layers grown by metal organic vapour-phase epitaxy *J. Mater. Sci.* **51** 3650–6
- [74] Okumura H, Kita M, Sasaki K, Kuramata A, Higashiwaki M and Speck J S 2014 Systematic investigation of the growth rate of  $\beta$ -Ga<sub>2</sub>O<sub>3</sub> (010) by plasma-assisted molecular beam epitaxy *Appl. Phys. Express* **7** 095501
- [75] Sasaki K, Higashiwaki M, Kuramata A, Masui T and Yamakoshi S 2014 Growth temperature dependences of structural and electrical properties of Ga<sub>2</sub>O<sub>3</sub> epitaxial films grown on  $\beta$ -Ga<sub>2</sub>O<sub>3</sub> (010) substrates by molecular beam epitaxy *J. Cryst. Growth* **392** 30–3
- [76] Nomura K, Goto K, Togashi R, Murakami H, Kumagai Y, Kuramata A, Yamakoshi S and Koukitu A 2014 Thermodynamic study of  $\beta$ -Ga<sub>2</sub>O<sub>3</sub> growth by halide vapor phase epitaxy *J. Cryst. Growth* **405** 19–22
- [77] Murakami H *et al* 2014 Homoepitaxial growth of  $\beta$ -Ga<sub>2</sub>O<sub>3</sub> layers by halide vapor phase epitaxy *Appl. Phys. Express* **8** 015503

- [78] Leedy K D *et al* 2017 Highly conductive homoepitaxial Si-doped Ga<sub>2</sub>O<sub>3</sub> films on (010) β-Ga<sub>2</sub>O<sub>3</sub> by pulsed laser deposition *Appl. Phys. Lett.* **111** 012103
- [79] Oshima T, Nakazono T, Mukai A and Ohtomo A 2012 Epitaxial growth of γ-Ga<sub>2</sub>O<sub>3</sub> films by mist chemical vapor deposition *J. Cryst. Growth* **359** 60–3
- [80] Altuntas H, Donmez I, Ozgit-Akgun C and Biyikli N 2014 Electrical characteristics of β-Ga<sub>2</sub>O<sub>3</sub> thin films grown by PEALD *J. Alloys Compd.* **593** 190–5
- [81] Krishnamoorthy S, Xia Z, Bajaj S, Brenner M and Rajan S 2017 Delta-doped β-gallium oxide field-effect transistor *Appl. Phys. Express* **10** 051102
- [82] Xia Z *et al* 2018 Delta doped β-Ga<sub>2</sub>O<sub>3</sub> field effect transistors with regrown ohmic contacts *IEEE Electron Device Lett.* **39** 568–71
- [83] Wong M H, Nakata Y, Kuramata A, Yamakoshi S and Higashiwaki M 2017 Enhancement-mode Ga<sub>2</sub>O<sub>3</sub> MOSFETs with Si-ion-implanted source and drain *Appl. Phys. Express* **10** 041101
- [84] Higashiwaki M, Sasaki K, Kamimura T, Hoi Wong M, Krishnamurthy D, Kuramata A, Masui T and Yamakoshi S 2013 Depletion-mode Ga<sub>2</sub>O<sub>3</sub> metal-oxide-semiconductor field-effect transistors on β-Ga<sub>2</sub>O<sub>3</sub> (010) substrates and temperature dependence of their device characteristics *Appl. Phys. Lett.* **103** 123511
- [85] Green A J *et al* 2016 3.8-MV/cm breakdown strength of MOVPE-grown Sn-doped β-Ga<sub>2</sub>O<sub>3</sub> MOSFETs *IEEE Electron Device Lett.* **37** 902–5
- [86] Zeng K *et al* 2017 Ga<sub>2</sub>O<sub>3</sub> MOSFETs using spin-on-glass source/drain doping technology *IEEE Electron Device Lett.* **38** 513–6
- [87] Chabak K D *et al* 2016 Enhancement-mode Ga<sub>2</sub>O<sub>3</sub> wrap-gate fin field-effect transistors on native (100) β-Ga<sub>2</sub>O<sub>3</sub> substrate with high breakdown voltage *Appl. Phys. Lett.* **109** 213501
- [88] Chabak K D *et al* 2018 Recessed-gate enhancement-mode β-Ga<sub>2</sub>O<sub>3</sub> MOSFETs *IEEE Electron Device Lett.* **39** 67–70
- [89] Moser N *et al* 2017 Ge-doped β-Ga<sub>2</sub>O<sub>3</sub> MOSFETs *IEEE Electron Device Lett.* **38** 775–8
- [90] Hwang W S *et al* 2014 High-voltage field effect transistors with wide-bandgap β-Ga<sub>2</sub>O<sub>3</sub> nanomembranes *Appl. Phys. Lett.* **104** 203111
- [91] Ahn S, Ren F, Kim J, Oh S, Kim J, Mastro M A and Pearton S J 2016 Effect of front and back gates on β-Ga<sub>2</sub>O<sub>3</sub> nano-belt field-effect transistors *Appl. Phys. Lett.* **109** 062102
- [92] Kim J, Oh S, Mastro M A and Kim J 2016 Exfoliated β-Ga<sub>2</sub>O<sub>3</sub> nano-belt field-effect transistors for air-stable high power and high temperature electronics *Phys. Chem. Chem. Phys.* **18** 15760–4
- [93] Zhou H, Si M, Alghamdi S, Qiu G, Yang L and Ye P D 2017 High-performance depletion/enhancement-mode β-Ga<sub>2</sub>O<sub>3</sub> on insulator (GOOI) field-effect transistors with record drain currents of 600/450 mA/mm *IEEE Electron Device Lett.* **38** 103–6
- [94] Zhou H, Maize K, Qiu G, Shakouri A and Ye P D 2017 β-Ga<sub>2</sub>O<sub>3</sub> on insulator field-effect transistors with drain currents exceeding 1.5 A/mm and their self-heating effect *Appl. Phys. Lett.* **111** 092102
- [95] Zhou H, Maize K, Noh J, Shakouri A and Ye P D 2017 Thermodynamic studies of β-Ga<sub>2</sub>O<sub>3</sub> nanomembrane field-effect transistors on a sapphire substrate *ACS Omega* **2** 7723–9
- [96] Lu A, Sun J, Jiang J and Wan Q 2010 One-shadow-mask self-assembled ultralow-voltage coplanar homojunction thin-film transistors *IEEE Electron Device Lett.* **31** 1137–9
- [97] Jiang J, Sun J, Dou W and Wan Q 2012 Junctionless flexible oxide-based thin-film transistors on paper substrates *IEEE Electron Device Lett.* **33** 65–7

- [98] Shao Y, Xiao X, Wang L Y, Liu Y and Zhang S D 2014 Anodized ITO thin-film transistors *Adv. Funct. Mater.* **24** 4170–5
- [99] Li S, Tian M, Gao Q, Wang M, Li T, Hu Q, Li X and Wu Y 2019 Nanometre-thin indium tin oxide for advanced high-performance electronics *Nat. Mater.* **18** 1091–7
- [100] Wang M *et al* 2019 High performance gigahertz flexible radio frequency transistors with extreme bending conditions *2019 IEEE Int. Electron Devices Meeting (IEDM) (7–11 December 2019)*
- [101] Li S *et al* 2019 BEOL compatible 15-nm channel length ultrathin indium-tin-oxide transistors with  $\mu_n = 970 \mu\text{A}/\mu\text{m}$  and on/off ratio near  $10^{11}$  at  $V_{\text{ds}} = 0.5 \text{ V}$  *2019 IEEE Int. Electron Devices Meeting (IEDM) (7–11 December 2019)*
- [102] Anthopoulos T D 2019 Ultrathin channels make transistors go faster *Nat. Mater.* **18** 1033–4
- [103] Wang Y F, Wang Z G, Huang K R, Liang X C, Liu C N, Chen C D and Liu C 2020 Solution-processed ITO thin-film transistors with doping of gallium oxide show high on-off ratios and work at 1 mV drain voltage *Appl. Phys. Lett.* **116** 219901
- [104] Lu A X and Huang H M 2015 Low-voltage transparent thin-film transistors with ZnO/ITO double-channel layers *Jpn. J. Appl. Phys.* **54** 106502
- [105] Zhong W, Li G Y, Chen R S, Lan L F, Zhang X, Pei W H, Chen H and Deng S 2017 A study on the bottom-gate ITO-stabilized ZnO thin-film transistors *Int. Conf. Electron Devices and Solid-State Circuits (EDSSC) (Hsinchu, Taiwan, 18–20 October 2017)*
- [106] Deng S B, Chen R S, Li G J, Xia Z H, Zhang M, Zhou W, Wong M and Kwok H-S 2016 High-performance staggered top-gate thin-film transistors with hybrid-phase microstructural ITO-stabilized ZnO channels *Appl. Phys. Lett.* **109** 182105
- [107] Liu Y, Deng S B, Chen R S, Li B, En Y F and Chen Y Q 2018 Low-frequency noise in hybrid-phase-microstructure ITO-stabilized ZnO thin-film transistors *IEEE Electron Device Lett.* **39** 200–3
- [108] Yu W *et al* 2019 Performance enhancement of TiZO thin film transistors by introducing a thin ITO interlayer *IEEE J. Electron Devices Soc.* **7** 1302–5